

Company: Samsung Electronics Co., Ltd.

Test of: 802.11 a/n/ac WLAN Access Point

To: FCC CFR 47 Part 15 Subpart E 15.407

Report No.: CTKL01-U2_DFS Rev A

DFS TEST REPORT



DFS TEST REPORT



Test of: Samsung Electronics Co., Ltd. WEA412h

to

To: FCC CFR 47 Part 15 Subpart E 15.407

Test Report Serial No.: CTKL01-U2_DFS Rev A

This report supersedes: NONE

Applicant: Samsung Electronics Co., Ltd.
129, Samsung-ro Yeongtong-gu
Suwon-si, Gyeonggi-do, 16677
Korea

Product Function: 802.11 a/n/ac WLAN Access Point

Issue Date: 21st October 2016

This Test Report is Issued Under the Authority of:

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MiCOM Labs is an ISO 17025 Accredited Testing Laboratory



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1. ACCREDITATION, LISTINGS & RECOGNITION

1.1. TESTING ACCREDITATION

MiCOM Labs, Inc. is an accredited Electrical testing laboratory per the international standard ISO/IEC 17025:2005. The company is accredited by the American Association for Laboratory Accreditation (A2LA) www.a2la.org test laboratory number 2381.01. MiCOM Labs test schedule is available at the following URL; <http://www.a2la.org/scopepdf/2381-01.pdf>



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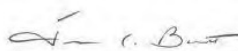
for technical competence in the field of

Electrical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 General requirements for the competence of testing and calibration laboratories. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated 8 January 2009).



Presented this 4th day of February 2016.



Senior Director of Quality & Communications
For the Accreditation Council
Certificate Number 2381.01
Valid to November 30, 2017

For the tests or types of tests to which this accreditation applies, please refer to the laboratory's Electrical Scope of Accreditation.





1.2. RECOGNITION

MiCOM Labs, Inc. has widely recognized wireless testing capabilities. Our international recognition includes Conformity Assessment Body designation by APEC MRA countries. MiCOM Labs test reports are accepted globally.

Country	Recognition Body	Status	Phase	Identification No.
USA	Federal Communications Commission (FCC)	TCB	-	US0159 Listing #: 102167
Canada	Industry Canada (IC)	FCB	APEC MRA 2	US0159 Listing #: 4143A-2 4143A-3
Japan	MIC (Ministry of Internal Affairs and Communication)	CAB	APEC MRA 2	RCB 210
	VCCI	--	--	A-0012
Europe	European Commission	NB	EU MRA	NB 2280
Australia	Australian Communications and Media Authority (ACMA)	CAB	APEC MRA 1	US0159
Hong Kong	Office of the Telecommunication Authority (OFTA)	CAB	APEC MRA 1	
Korea	Ministry of Information and Communication Radio Research Laboratory (RRL)	CAB	APEC MRA 1	
Singapore	Infocomm Development Authority (IDA)	CAB	APEC MRA 1	
Taiwan	National Communications Commission (NCC) Bureau of Standards, Metrology and Inspection (BSMI)	CAB	APEC MRA 1	
Vietnam	Ministry of Communication (MIC)	CAB	APEC MRA 1	

EU MRA – European Union Mutual Recognition Agreement.

NB – Notified Body

APEC MRA – Asia Pacific Economic Community Mutual Recognition Agreement. Recognition agreement under which test lab is accredited to regulatory standards of the APEC member countries.

Phase I - recognition for product testing

Phase II – recognition for both product testing and certification

1.3. PRODUCT CERTIFICATION

MiCOM Labs, Inc. is an accredited Product Certification Body per the international standard ISO/IEC 17065:2012. The company is accredited by the American Association for Laboratory Accreditation (A2LA) www.a2la.org test laboratory number 2381.02. MiCOM Labs test schedule is available at the following URL; <http://www.a2la.org/scopepdf/2381-02.pdf>



United States of America – Telecommunication Certification Body (TCB)
Industry Canada – Certification Body, CAB Identifier – US0159
Europe – Notified Body (NB), NB Identifier - 2280
Japan – Recognized Certification Body (RCB), RCB Identifier - 210



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2. DOCUMENT HISTORY

Document History		
Revision	Date	Comments
Draft	10 th October 2016	
Rev A	21 st October 2016	Initial Release

In the above table the latest report revision will replace all earlier versions.

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3. TEST RESULT CERTIFICATE

Manufacturer: Samsung Electronics Co., Ltd. 129, Samsung-ro Yeongtong-gu Suwon-si Gyeonggi-do 16677 Korea	Tested By: MiCOM Labs, Inc. 575 Boulder Court Pleasanton California 94566 USA
Model: WEA412h	Telephone: +1 925 462 0304
Type Of Equipment: 802.11 a/n/ac WLAN Access Point	Fax: +1 925 462 0306
S/N's: S632802752	
Test Date(s): 4 th – 5 th October 2016	Website: www.micomlabs.com

STANDARD(S)	TEST RESULTS
FCC CFR 47 Part 15 Subpart E 15.407 (Limited to DFS Testing)	EQUIPMENT COMPLIES

MiCOM Labs, Inc. tested the equipment mentioned in accordance with the requirements set forth in the above standards. Test results indicate that the equipment tested is capable of demonstrating compliance with the requirements as documented within this report.

Notes:

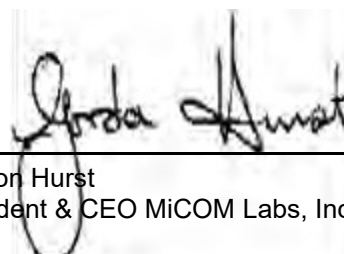
1. This document reports conditions under which testing was conducted and the results of testing performed.
2. Details of test methods used have been recorded and kept on file by the laboratory.
3. Test results apply only to the item(s) tested.

Approved & Released for MiCOM Labs, Inc. by:





Graeme Grieve
Quality Manager MiCOM Labs, Inc.



Gordon Hurst
President & CEO MiCOM Labs, Inc.

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4. REFERENCES AND MEASUREMENT UNCERTAINTY

4.1. Normative References

REF.	PUBLICATION	YEAR	TITLE
I	KDB 662911 D01 & D02	Oct 31 2013	Guidance for measurement of output emission of devices that employ single transmitter with multiple outputs or systems with multiple transmitters operating simultaneously in the same frequency band
II	KDB 905462 D07 v01r01	8th April 2016	Test guidance to demonstrate compliance for U-NII devices subject to DFS requirements.
III	KDB 926956 D01 v01r06	8th April 2016	U-NII Device Transition Plan
IV	KDB 789033 D02 v01r02	8th April 2016	General UNII Test Procedures New Rules
V	A2LA	June 2015	R105 - Requirement's When Making Reference to A2LA Accreditation Status
VI	ANSI C63.10	2013	American National Standard for Testing Unlicensed Wireless Devices
VII	ANSI C63.4	2014	American National Standards for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz
VIII	CISPR 22	2008	Information technology equipment - Radio disturbance characteristics - Limits and methods of measurement
IX	ETSI TR 100 028	2001-12	Parts 1 and 2 Electromagnetic compatibility and Radio Spectrum Matters (ERM); Uncertainties in the measurement of mobile radio equipment characteristics
X	FCC 06-96	Jun 30 2006	Memorandum Opinion and Order
XI	FCC 47 CFR Part 15.407	2014	Radio Frequency Devices; Subpart E –Unlicensed National Information Infrastructure Devices
XII	ICES-003	Issue 6 Jan 2016	Spectrum Management and Telecommunications; Interference-Causing Equipment Standard. Information Technology Equipment (Including Digital Apparatus) – Limits and methods of measurement.
XIII	M 3003	Edition 3 Nov.2012	Expression of Uncertainty and Confidence in Measurements
XIV	RSS-247 Issue 1	May 2015	Digital Transmission Systems (DTSs), Frequency Hopping System (FHSs) and License-Exempt Local Area Network (LE-LAN) Devices
XV	RSS-Gen Issue 4	November 2014	General Requirements and Information for the Certification of Radiocommunication Equipment
XVI	KDB 644545 D03 v01	August 14th 2014	Guidance for IEEE 802.11ac New Rules
XVII	FCC 47 CFR Part 2.1033	2014	FCC requirements and rules regarding photographs and test setup diagrams.
XVIII	EN 55022	2010 + AC:2011	Information technology equipment - Radio disturbance characteristics - Limits and methods of measurement

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4.2. Test and Uncertainty Procedure

Conducted and radiated emission measurements were conducted in accordance with American National Standards Institute ANSI C63.4, listed in the Normative References section of this report.

Measurement uncertainty figures are calculated in accordance with ETSI TR 100 028 Parts 1 and 2.

Measurement uncertainties stated are based on a standard uncertainty multiplied by a coverage factor $k = 2$, providing a level of confidence of approximately 95 % in accordance with UKAS document M 3003 listed in the Normative References section of this report.



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5. PRODUCT DETAILS AND TEST CONFIGURATIONS

5.1. Technical Details

Details	Description
Purpose:	Test of the Samsung Electronics Co., Ltd. WEA412h to FCC CFR 47 Part 15 Subpart E 15.407. Radio Frequency Devices; Subpart E –Unlicensed National Information Infrastructure Devices
Applicant:	Samsung Electronics Co., Ltd. 129, Samsung-ro Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677 Korea
Manufacturer:	As Applicant
Laboratory performing the tests:	MiCOM Labs, Inc. 575 Boulder Court Pleasanton California 94566 USA
Test report reference number:	CTKL01
Date EUT received:	4 th October 2016
Standard(s) applied:	FCC CFR 47 Part 15 Subpart E 15.407
Dates of test (from - to):	4 th – 5 th October 2016
No of Units Tested:	1
Type of Equipment:	802.11 a/n/ac WLAN Access Point
Product Family Name:	WEA412h
Model(s):	WEA412h
Location for use:	Indoor
Declared Frequency Range(s):	5250 - 5350 MHz; 5470 - 5725 MHz;
Primary function of equipment:	802.11 a/n/ac WLAN Access Point
Secondary function of equipment:	None provided
Type of Modulation:	OFDM
EUT Modes of Operation:	5470 - 5725 MHz: 802.11a; 802.11ac-80; 802.11n HT-40;
Declared Nominal Output Power (Ave):	5470 - 5725 MHz: 802.11a; 802.11ac-80; 802.11n HT-40;
Transmit/Receive Operation:	Transceiver - Half Duplex
Rated Input Voltage and Current:	48Vdc – 750mA
Operating Temperature Range:	Declared Range 0°C to 45°C
ITU Emission Designator:	20MD2D, 40MD2D, 80MD2D
Equipment Dimensions:	152 mm (L) x 96 mm (W) x 33 mm (H)
Weight:	0.2 kg
Software Rev:	V.4.4.6.R

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5.2. Scope Of Test Program

Samsung Electronics Co., Ltd. WEA412h

The scope of the test program was to test the Samsung Electronics Co., Ltd. WEA412h, 802.11 a/n/ac WLAN Access Point configurations in the frequency ranges 5250 - 5350 MHz; 5470 - 5725 MHz; for compliance against the following specification:

FCC CFR 47 Part 15 Subpart E 15.407

Radio Frequency Devices; Subpart E – Unlicensed National Information Infrastructure Devices

Samsung Electronics Co., Lt. WEA412h



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5.3. Equipment Model(s) and Serial Number(s)

Type	Description	Manufacturer	Model	Serial No.	Delivery Date
EUT	Access Point	Samsung Electronics	WEA412h	S632802752	4 th October 2016

5.4. Antenna Details

Type	Manufacturer	Model	Family	Gain (dBi)	BF Gain	Dir BW	X-Pol	Frequency Band (MHz)
integral	Samsung Electronics Co., Ltd.	ANT_C	PCB	5.7	-	360	-	5250 – 5350 5470 - 5725
integral	Samsung Electronics Co., Ltd.	ANT_D	PCB	4.9	-	360	-	5250 – 5350 5470 - 5725

BF Gain - Beamforming Gain
Dir BW - Directional BeamWidth
X-Pol - Cross Polarization

5.5. Cabling and I/O Ports

Port Type	Max Cable Length	# Of Ports	Screened	Conn Type	Data Type
Lan	10m	1	N	RJ-45	Serial
PoE	100m	1	N	RJ-45	Data
DC	10m	1	N	Barrel	Power
USB	5m	1	Y	USB	Digital

5.6. Test Configurations

Results for the following configurations are provided in this report:

Operational Mode(s) (802.11a/b/g/n/ac)	Data Rate with Highest Power MBit/s	Channel Frequency (MHz)		
		Low	Mid	High
5470 - 5725 MHz				
802.11a	6	5,500.00	--	--
802.11ac-80	29.3	5,530.00	--	--
802.11n HT-40	13.5	5,510.00	--	--

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5.7. Equipment Modifications

The following modifications were required to bring the equipment into compliance:

1. NONE

5.8. Deviations from the Test Standard

The following deviations from the test standard were required in order to complete the test program:

1. NONE

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6. TEST SUMMARY

List of Measurements

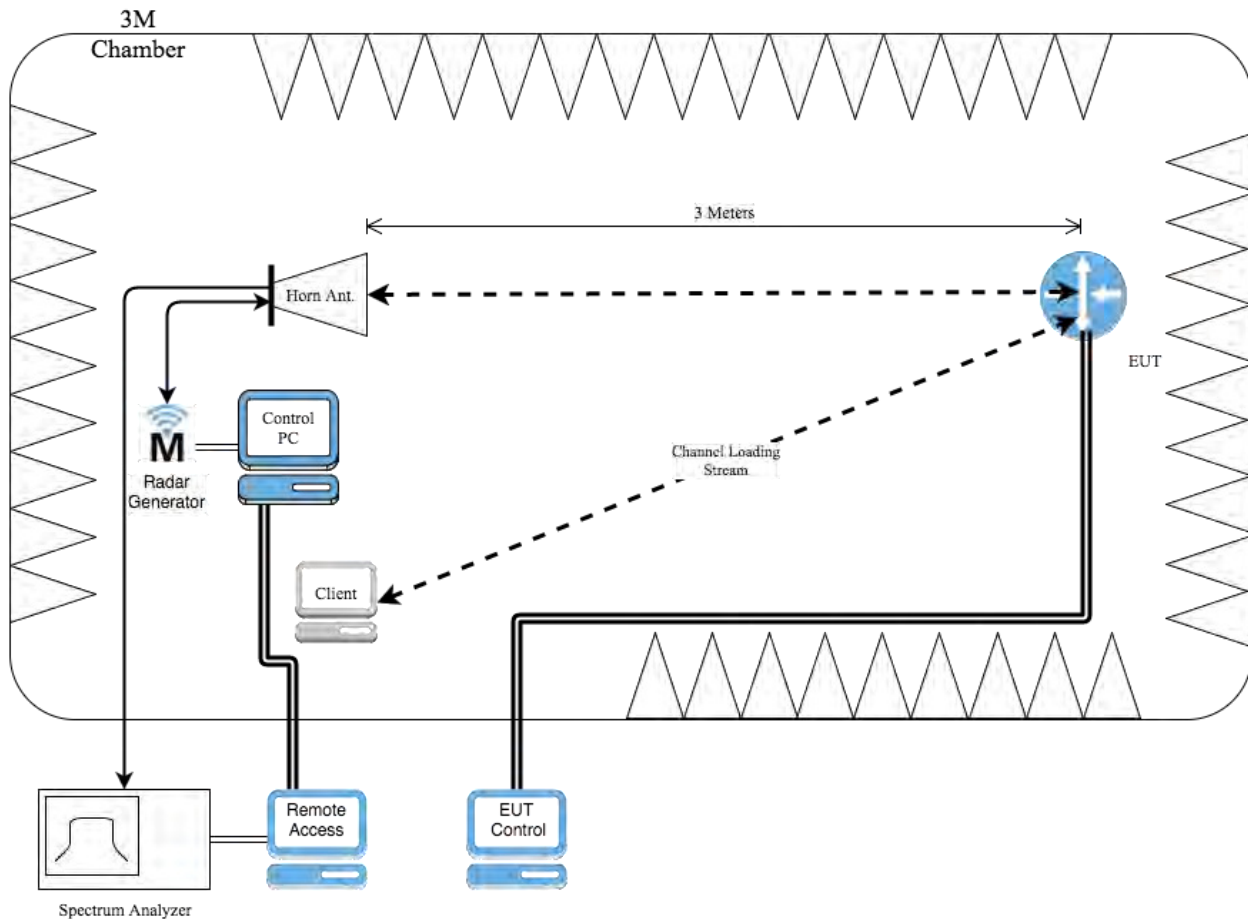
Test Header	Result	Data Link
Dynamic Frequency Selection (DFS)	Complies	
Channel Availability Check	Complies	
Initial CAC	Complies	View Result
Beginning CAC	Complies	View Result
End CAC	Complies	View Result
Channel Close / Transmission Time	Complies	View Result
Non-Occupancy Period	Complies	View Result
Probability of Detection	Complies	View Result
Detection Bandwidth	Complies	View Result

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7. TEST EQUIPMENT CONFIGURATION(S)

7.1. Radiated DFS Testing

Setup for Radiated DFS testing in 3 m chamber where the EUT is the Master device communicating with client device over the air. Radar Test Waveforms are injected from the DFS generator and detected by the Master.



A full system calibration was performed on the test station and any resulting system losses (or gains) were taken into account in the production of all final measurement data.



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Asset#	Description	Manufacturer	Model#	Serial#	Calibration Due Date
104	Antenna Horn 1-18GHz	Electro-Mechanics	3115	9205-3882	17 Feb 2017
117	Low Power Sensor - 70dBm to -20dBm 50 MHz - 50GHz	HP	8487D	3318A00371	17 Oct 2016
158	Barometer/Thermometer	Control Company	4196	E2846	01 Dec 2016
207	Semi-Anechoic Chamber, Radiated Immunity & DFS testing.	ETS Lingren	ETS/Lingren 25	SL12462	17 Feb 2017
223	Power Meter	HP	EPM-442A	US37480256	19 Oct 2016
299	Test Software DFS Test System	Aeroflex	DFS test Software	V2.7.0	Not Required
359	DFS System	Aeroflex	PXI-1042	300001/004	13 Dec 2016
417	Laptop for DFS with DFS software	Lenova	W520	DFS	Not Required
418	PCI-e interface card	National Instruments	Express 8360	174AAC5	Not Required
444	SMA Cable Assembly	ETS-Lindgren	RFC-NMS-100-SMS-256 IN	001	Cal when used
71	Spectrum Analyzer 9KHz-50GHz	HP	8565E	3425A00181	06 Aug 2017
DFS PCIe#1	PCIe cable for Aeroflex	National Instruments	PCIe cable	None	Not Required

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8. TEST METHODOLOGY

8.1. Dynamic Frequency Selection (DFS) Overview

A U-NII network will employ a DFS function to detect signals from radar systems and to avoid co-channel operation with these systems. This applies to the 5250-5350 MHz and/or 5470-5725 MHz bands. Within the context of the operation of the DFS function, a U-NII device will operate in either Master Mode or Client Mode. U-NII devices operating in Client Mode can only operate in a network controlled by a U-NII device operating in Master Mode. The following tables summarize the requirements.

Requirement	Master Device or Client with Radar Detection	Client without Radar Detection
	Operational Mode	
DFS Detection Threshold	Yes	Not Required
Channel Closing Transmission Time	Yes	Yes
Channel Move Time	Yes	Yes
U-NII Detection Bandwidth	Yes	Not Required

Additional requirements for devices with multiple bandwidth modes	Master Device or Client with Radar Detection	Client without Radar Detection
U-NII Detection Bandwidth and Statistical Performance Check	All BW modes must be tested	Not required
Channel Move Time and Channel Closing Transmission Time	Test using widest BW mode available	Test using the widest BW mode available for the link
All other tests	Any single BW mode	Not required

NOTE: Frequencies selected for statistical performance check should include several frequencies within the radar detection bandwidth and frequencies near the edge of the radar detection bandwidth. For 802.11 devices it is suggested to select frequencies in each of the bonded 20 MHz channels and the channel center frequency.

The operational behavior and individual DFS requirements associated with these modes are as follows:

8.1.1. Master Devices

- a) The Master Device will use DFS in order to detect Radar Waveforms with received signal strength above the DFS Detection Threshold in the 5250 – 5350 MHz and 5470 – 5725 MHz bands. DFS is not required in the 5150 – 5250 MHz or 5725 – 5850 MHz bands.
- b) Before initiating a network on a Channel, the Master Device will perform a Channel Availability Check for a specified time duration (Channel Availability Check Time) to ensure that there is no radar system operating on the Channel, using DFS described under subsection a) above.
- c) The Master Device initiates a U-NII network by transmitting control signals that will enable other U-NII devices to Associate with the Master Device.
- d) During normal operation, the Master Device will monitor the Channel (In-Service Monitoring) to ensure that there is no radar system operating on the Channel, using DFS described under a).
- e) If the Master Device has detected a Radar Waveform during In-Service Monitoring as described under d), the Operating Channel of the U-NII network is no longer an Available Channel. The Master Device will instruct all associated Client Device(s) to stop transmitting on this Channel within the Channel Move Time. The transmissions during the Channel Move Time will be limited to the Channel Closing Transmission Time.
- f) Once the Master Device has detected a Radar Waveform it will not utilize the Channel for the duration of the Non-Occupancy Period.
- g) If the Master Device delegates the In-Service Monitoring to a Client Device, then the combination will be tested to the requirements described under d) through f) above.



8.1.2. Client Devices

- a) A Client Device will not transmit before having received appropriate control signals from a Master Device.
- b) A Client Device will stop all its transmissions whenever instructed by a Master Device to which it is associated and will meet the Channel Move Time and Channel Closing Transmission Time requirements. The Client Device will not resume any transmissions until it has again received control signals from a Master Device.
- c) If a Client Device is performing In-Service Monitoring and detects a Radar Waveform above the DFS Detection Threshold, it will inform the Master Device. This is equivalent to the Master Device detecting the Radar Waveform and d) through f) of section 5.1.1 apply.
- d) Irrespective of Client Device or Master Device detection the Channel Move Time and Channel Closing Transmission Time requirements remain the same.
- e) The client test frequency must be monitored to ensure no transmission of any type has occurred for 30 minutes. Note: If the client moves with the master, the device is considered compliant if nothing appears in the client non-occupancy period test. For devices that shutdown (rather than moving channels), no beacons should appear.

8.2. DFS Detection Thresholds

The table below provides the DFS Detection Thresholds for Master Devices as well as Client Devices incorporating In-Service Monitoring.

DFS Detection Thresholds for Master Devices and Client Devices with Radar Detection

Maximum Transmit Power	Value (see Notes 1, 2 and 3)
EIRP $\geq$ 200 milliwatt	-64 dBm
EIRP $<$ 200 milliwatt and power density $\leq$ 10 dBm/MHz	-62 dBm
EIRP $<$ 200 milliwatt that do not meet the power spectral density requirement	-64 dBm

NOTE 1: This is the level at the input of the receiver assuming a 0 dBi receive antenna

NOTE 2: Throughout these test procedures an additional 1 dB has been added to the amplitude of the test transmission waveforms to account for variations in measurement equipment. This will ensure that the test signal is at or above the detection threshold level to trigger a DFS response.

NOTE 3: EIRP is based on the highest antenna gain. For MIMO devices refer to KDB Publication 662911 D01.



8.3. Response Requirements

The following table provides the response requirements for Master and Client Devices incorporating DFS.

DFS Response Requirement Values

Parameter	Value
Non-Occupancy Period	Minimum 30 minutes
Channel Availability Check Time	60 seconds
Channel Move Time	10 seconds, see NOTE 1
Channel Closing Transmission Time	200 milliseconds + an aggregate of 60 milliseconds over remaining 10 second period, see NOTES 1 and 2
U-NII Detection Bandwidth	Minimum 100% of the U-NII 99% transmission power bandwidth, see NOTE 3

NOTE 1: Channel Move Time and the Channel Closing Transmission Time should be performed with Radar Type 0. The measurement timing begins at the end of the Radar Type 0 burst.

NOTE 2: The Channel Closing Transmission Time is comprised of 200 milliseconds starting at the beginning of the Channel Move Time plus any additional intermittent control signals required to facilitate a Channel move (an aggregate of 60 milliseconds) during the remainder of the 10 second period. The aggregate duration of control signals will not count quiet periods in between transmissions.

NOTE 3: During the U-NII Detection Bandwidth detection test, radar type 0 should be used. For each frequency step the minimum percentage of detection is 90 percent. Measurements are performed with no data traffic.



8.4. Radar Test Waveforms

This section provides the parameters for required test waveforms, minimum percentage of successful detections, and the minimum number of trials that must be used for determining DFS conformance. Step intervals of 0.1 microsecond for Pulse Width, 1 microsecond for PRI, 1 MHz for chirp width and 1 for the number of pulses will be utilized for the random determination of specific test waveforms.

8.4.1. Short Radar Pulses

Short Pulse Radar Test Waveforms

Radar Type	Pulse Width (μS)	PRI (μS)	Number of Pulses	Minimum Percentage of Successful Detection	Minimum Number of Trials
0	1	1428	18	See Note 1	See Note 1
1	1	Test A: 15 unique PRI values randomly selected from the list of 23 PRI values in Table 5a	$\text{Roundup} \left\{ \begin{array}{l} \left(\frac{1}{360} \right) \cdot \\ \left(\frac{19 \cdot 10^6}{\text{PRI}_{\mu\text{sec}}} \right) \end{array} \right\}$	60%	30
		Test B: 15 unique PRI values randomly selected in the range 518-3066 μS, with a minimum increment of 1 μS, excluding PRI values selected in Test A			
2	1-5	150-230	23-29	60%	30
3	6-10	200-500	16-18	60%	30
4	11-20	200-500	12-16	60%	30
Aggregate (Radar Types 1-4)				80%	120
Note 1: Short Radar Pulse Type 0 should be used for the Detection Bandwidth test, Channel Move Time and Channel Closing Time tests					

A minimum of 30 unique waveforms are required for each of the Short Pulse Radar Types 2 through 4. If more than 30 waveforms are used for Short Pulse Radar Types 2 through 4, then each additional waveform must also be unique and not repeated from the previous waveforms. If more than 30 waveforms are used for Short Pulse Radar Type 1, then each additional waveform is generated with Test B and must also be unique and not repeated from the previous waveforms in Tests A or B.



8.4.2. Long Radar Pulse Test

Long Pulse Radar Test Waveforms

Radar Type	Pulse Width (µsec)	Chirp Width (MHz)	PRI (µsec)	Number of Pulses per Burst	Number of Bursts	Minimum Percentage of Successful Detection	Minimum Trials
5	50-100	5-20	1000-2000	1-3	8-20	80%	30

The parameters for this waveform are randomly chosen. Thirty unique waveforms are required for the Long Pulse radar test signal. If more than 30 waveforms are used for the Long Pulse radar test signal, then each additional waveform must also be unique and not repeated from the previous waveforms.

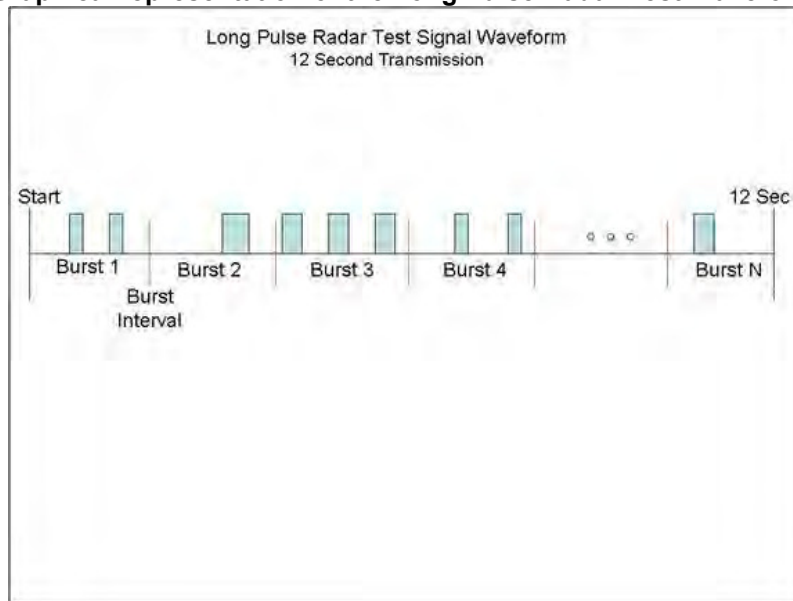
Each waveform is defined as follows:

1. The transmission period for the Long Pulse Radar test signal is 12 seconds.
2. There are a total of 8 to 20 Bursts in the 12 second period, with the number of Bursts being randomly chosen. This number is Burst Count.
3. Each Burst consists of 1 to 3 pulses, with the number of pulses being randomly chosen. Each Burst within the 12 second sequence may have a different number of pulses.
4. The pulse width is between 50 and 100 microseconds, with the pulse width being randomly chosen. Each pulse within a Burst will have the same pulse width. Pulses in different Bursts may have different pulse widths.
5. Each pulse has a linear FM chirp between 5 and 20 MHz, with the chirp width being randomly chosen. Each pulse within a transmission period will have the same chirp width. The chirp is centered on the pulse. For example, with a radar frequency of 5300 MHz and a 20 MHz chirped signal, the chirp starts at 5290 MHz and ends at 5310 MHz.
6. If more than one pulse is present in a Burst, the time between the pulses will be between 1000 and 2000 microseconds, with the time being randomly chosen. If three pulses are present in a Burst, the time between the first and second pulses is chosen independently of the time between the second and third pulses.
7. The 12 second transmission period is divided into even intervals. The number of intervals is equal to Burst_Count. Each interval is of length $(12,000,000 / \text{Burst_Count})$ microseconds. Each interval contains one Burst. The start time for the Burst, relative to the beginning of the interval, is between 1 and $[(12,000,000 / \text{Burst_Count}) - (\text{Total Burst Length}) + (\text{One Random PRI Interval})]$ microseconds, with the start time being randomly chosen. The step interval for the start time is 1 microsecond. The start time for each Burst is chosen independently.

A representative example of a Long Pulse radar test waveform:

1. The total test signal length is 12 seconds.
2. 8 Bursts are randomly generated for the Burst_Count
3. Burst 1 has 2 randomly generated pulses.
4. The pulse width (for both pulses) is randomly selected to be 75 microseconds.
5. The PRI is randomly selected to be at 1213 microseconds.
6. Bursts 2 through 8 are generated using steps 3 – 5.
7. Each Burst is contained in even intervals of 1,500,000 microseconds. The starting location for Pulse 1, Burst 1 is randomly generated (1 to 1,500,000 minus the total Burst 1 length + 1 random PRI interval) at the 325,001 microsecond step. Bursts 2 through 8 randomly fall in successive 1,500,000 microsecond intervals (i.e. Burst 2 falls in the 1,500,001 – 3,000,000 microsecond range).

Graphical representation of the Long Pulse Radar Test Waveform.





8.4.3. Frequency Hopping Radar Test Waveform

Radar Type	Pulse Width (μsec)	PRI (μsec)	Pulses per Hop	Hopping Rate (kHz)	Hopping Sequence Length (msec)	Minimum Percentage of Successful Detection	Minimum Trials
6	1	333	9	.333	300	70%	30

For the Frequency Hopping Radar Type, the same Burst parameters are used for each waveform. The hopping sequence is different for each waveform and a 100-length segment is selected from the hopping sequence defined by the following algorithm:

The first frequency in a hopping sequence is selected randomly from the group of 475 integer frequencies from 5250 – 5724 MHz. Next, the frequency that was just chosen is removed from the group and a frequency is randomly selected from the remaining 474 frequencies in the group. This process continues until all 475 frequencies are chosen for the set. For selection of a random frequency, the frequencies remaining within the group are always treated as equally likely.

8.5. Radar Waveform Calibration

The following equipment setup was used to calibrate the Radar Waveform. A spectrum analyzer was used to establish the test signal level for each radar type. During this process there were no transmissions by either the Master or Client Device. The spectrum analyzer was switched to the zero span (Time Domain) mode at the frequency of the Radar Waveform generator. Peak detection was utilized. The spectrum analyzer resolution bandwidth (RBW) and video bandwidth (VBW) were set to 3 MHz.

The signal generator amplitude was set so that the power level measured at the spectrum analyzer was equal to the DFS detection threshold +1dB (Ref Section 9.2).



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8.6. Test Program Details

EUT Type: Master with radar detection

Frequency band(s): 5,250 - 5,350 MHz and 5,470 – 5,725 MHz

Uniform Loading: For the above frequency band(s) the manufacturer declared that the device provides an aggregate uniform loading of the spectrum across all devices by selecting an operating channel among the available channels using a random algorithm.

Test Environment: Radiated

Antenna Gain used for Testing: 5.7 dBi

Radio parameters:

802.11a: Transmit Power: 17 dBm; Data Rate: 6 Mbit/s; Duty Cycle: ~17%

802.11ac-80: Transmit Power: 17 dBm; Data Rate: 29 Mbit/s; Duty Cycle: ~17%

802.11n HT-40: Transmit Power: 17 dBm; Data Rate: 18 Mbit/s; Duty Cycle: ~17%

Number of Antenna Chains: 2

Test Communication Throughput Methodology

The requisite MPEG video file ("TestFile.mpg" available on the NTIA website at the following link <http://ntiacsd.ntia.doc.gov/dfs/>) is used during this video stream.

EUT Software Version: V.4.4.6.R

Test Environmental Conditions - Ambient:

Temperature: 17 to 23 °C

Relative humidity: 31 to 57%

Pressure: 999 to 1012 mbar

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9. TEST RESULTS

9.1. Dynamic Frequency Selection (DFS)

9.1.1. Channel Availability Check

9.1.1.1. Initial CAC

This test verifies that the EUT does not emit pulse, control, or data signals on the test Channel until the power-up sequence has been completed and the U-NII device checks for Radar Waveforms for one minute on the test Channel. This test does not use any Radar Waveforms.

The EUT is instructed to power up at the appropriate center frequency. The spectrum analyzer is set on zero span with a 1 MHz resolution bandwidth and 300 second sweep time to monitor the RF output of the EUT during power up. The analyzer's sweep will be started the same time power is applied to the U-NII device.

The EUT should not transmit any pulse or data transmissions until at least 1 minute after the completion of the power-on cycle.

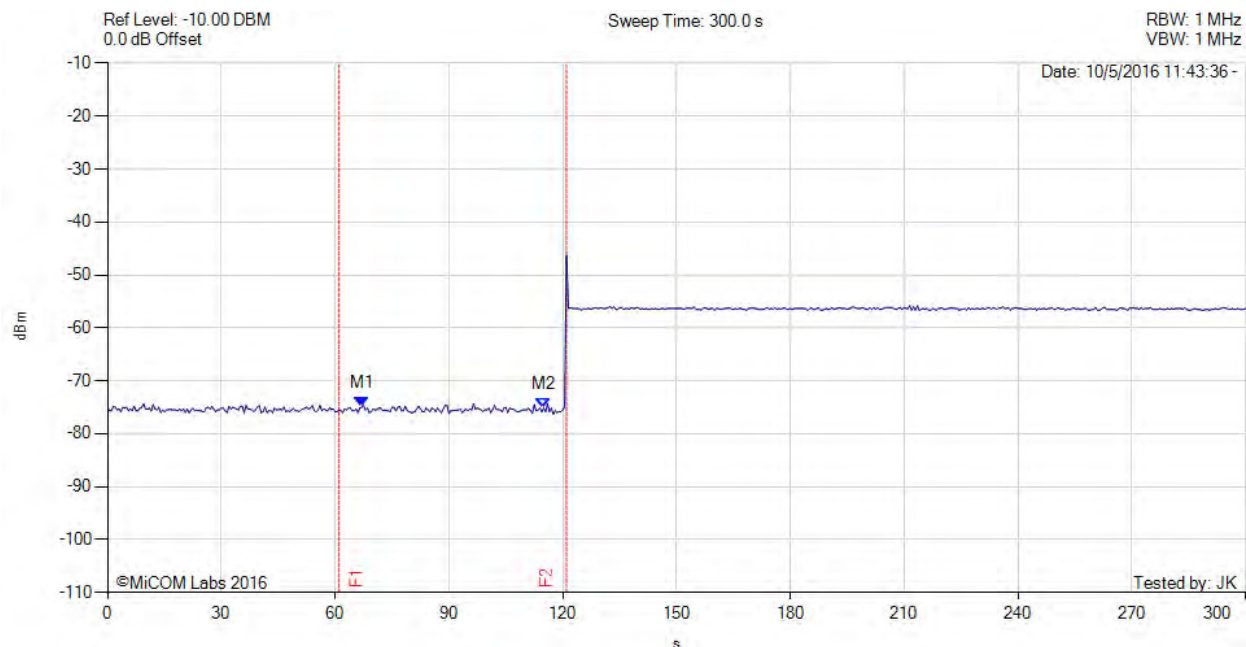
The first red vertical line shown on the following plot denotes the instant when the EUT starts its power-up sequence i.e. T0 (as defined within the FCC's KDB 905462 D02 Section 4.1). The power-up reference T0 is determined by the time it takes for the EUT to start "beaconing" i.e. initial beacon – 60 secs = end of power-up.

The Channel Availability Check Time commences at instant T0 and will end no sooner than T0 + 60 seconds. T0 + 60 is indicated on the plot by the second vertical line.

INITIAL CAC



Variant: 802.11a, Channel: 5500.00 MHz, Data Rate: 6 Mbit/s, Duty Cycle : 17.00%, Antenna Gain: 5.7 dBi



Analyzer Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1 : 67.000 s : -75.000 dBm M2 : 115.000 s : -75.160 dBm	Channel Frequency: 5500.00 MHz F2 - F1 = 121.000 - 61.000 = 60.000 s

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9.1.1.2. Beginning CAC

The steps below define the procedure to verify successful radar detection on the selected Channel during a period equal to the Channel Availability Check Time and avoidance of operation on that Channel when a radar Burst with a level equal to the DFS Detection Threshold +1dB (Ref Section 9.2) occurs at the beginning of the Channel Availability Check Time.

A single Burst of short pulse of radar Type 1 will commence within a 6 second window starting at T0 (first red vertical marker line on the plot).

Visual indication on the EUT of successful detection of the radar Burst is recorded and reported. Observation of emissions at the appropriate center frequency will continue for 2.5 minutes after the radar burst has been generated.

T0 + 60 is indicated on the plot by the second vertical line.

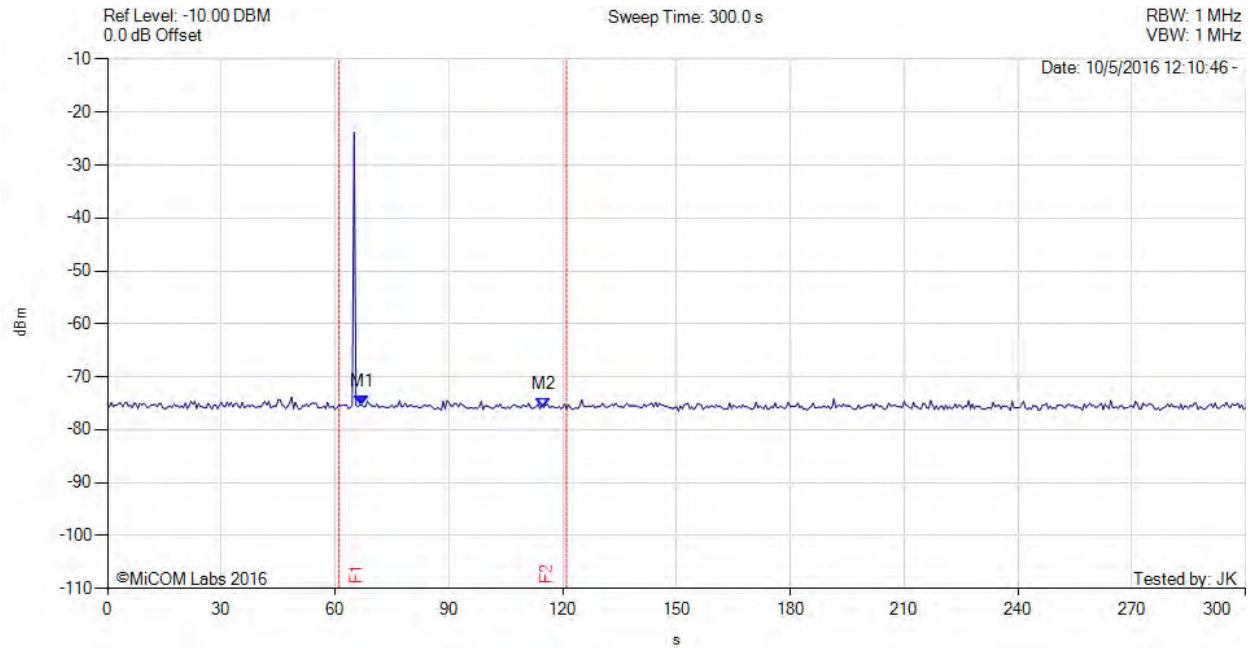


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BEGINNING CAC



Variant: 802.11a, Channel: 5500.00 MHz, Data Rate: 6 Mbit/s, Duty Cycle : 17.00%, Antenna Gain: 5.7 dBi



Analyzer Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1 : 67.000 s : -75.330 dBm M2 : 115.000 s : -75.830 dBm	Channel Frequency: 5500.00 MHz $F2 - F1 = 121.000 - 61.000 = 60.000$ s

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9.1.1.3. End CAC

The steps below define the procedure to verify successful radar detection on the selected Channel during a period equal to the Channel Availability Check Time and avoidance of operation on that Channel when a radar Burst with a level equal to the DFS Detection Threshold occurs at the end of the Channel Availability Check Time.

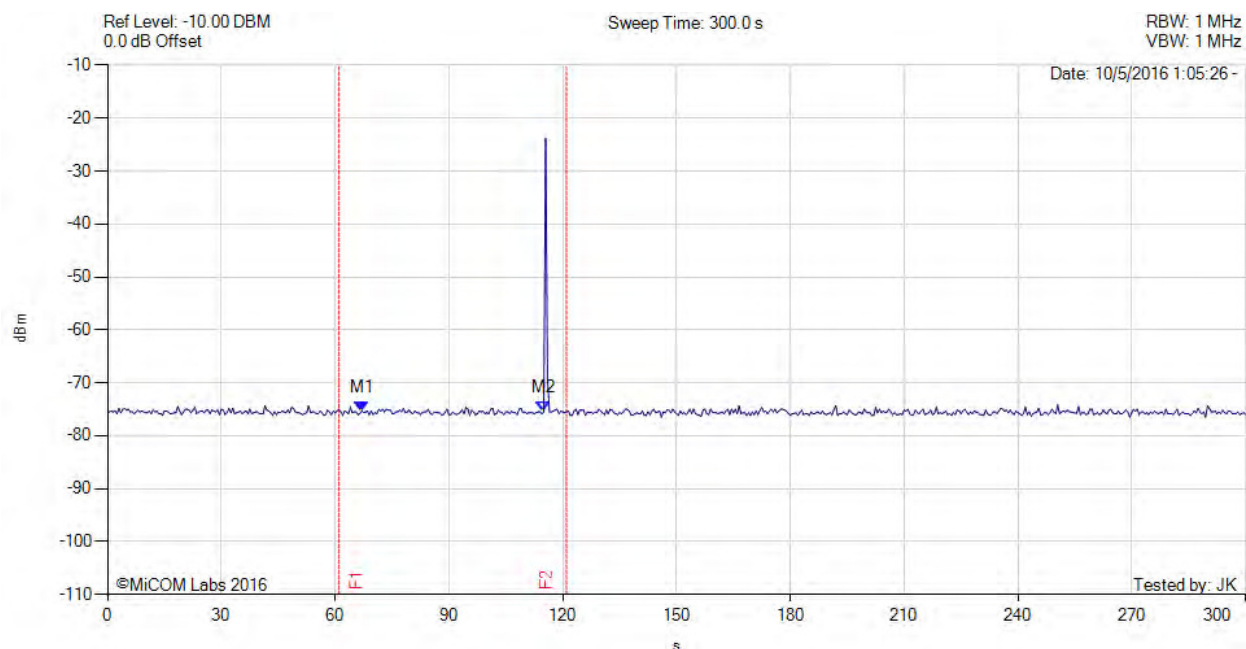
A single Burst of short pulse of radar Type 1 will commence within a 6 second window starting at $T_0 + 54$ seconds. The window will commence at marker 3 and end at the red time line T_2 ($T_0 + 60$ secs)

Visual indication on the EUT of successful detection of the radar Burst is recorded and reported. Observation of emissions at the appropriate center frequency will continue for 2.5 minutes after the radar burst has been generated.

END CAC



Variant: 802.11a, Channel: 5500.00 MHz, Data Rate: 6 Mbit/s, Duty Cycle : 17.00%, Antenna Gain: 5.7 dBi



Analyzer Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1 : 67.000 s : -75.330 dBm M2 : 115.000 s : -75.500 dBm	Channel Frequency: 5500.00 MHz $F2 - F1 = 121.000 - 61.000 = 60.000$ s

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9.1.2. Channel Close / Transmission Time

The steps below define the procedure to determine the above mentioned parameters when a radar Burst with a level equal to the DFS Detection Threshold is generated on the Operating Channel of the U-NII device.

The EUT will be associated with a support U-NII device in order to setup an appropriate transmission media in accordance with the FCC requirements.

Channel Closing Transmission Time and Channel Move Time - Measurement

The test system was set-up to capture all transmission data for access point events above a threshold level of -50 dBm. The test equipment time stamps all captured events.

A Type 0 waveform was introduced to the EUT, from which a 12 second transmission record was digitally captured. The start of the Type 0 radar waveform is indicated in the test result plot as "Start Waveform", the end of the waveform is indicated as "End waveform".

Channel Closing Transmission Time, and the Channel Move Time start immediately after the last radar pulse is transmitted.

The aggregate of all pulses seen after the end of the radar injection are measured as the "Channel Closing Transmission time".

The last EUT activity after the end of the radar pulse is identified and used to determine the "Channel Move Time"



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802.11ac-80: Frequency 5530 MHz Channel 106

The PXI system measures and aggregates the pulses occurring after the end of the radar pulse to determine; -

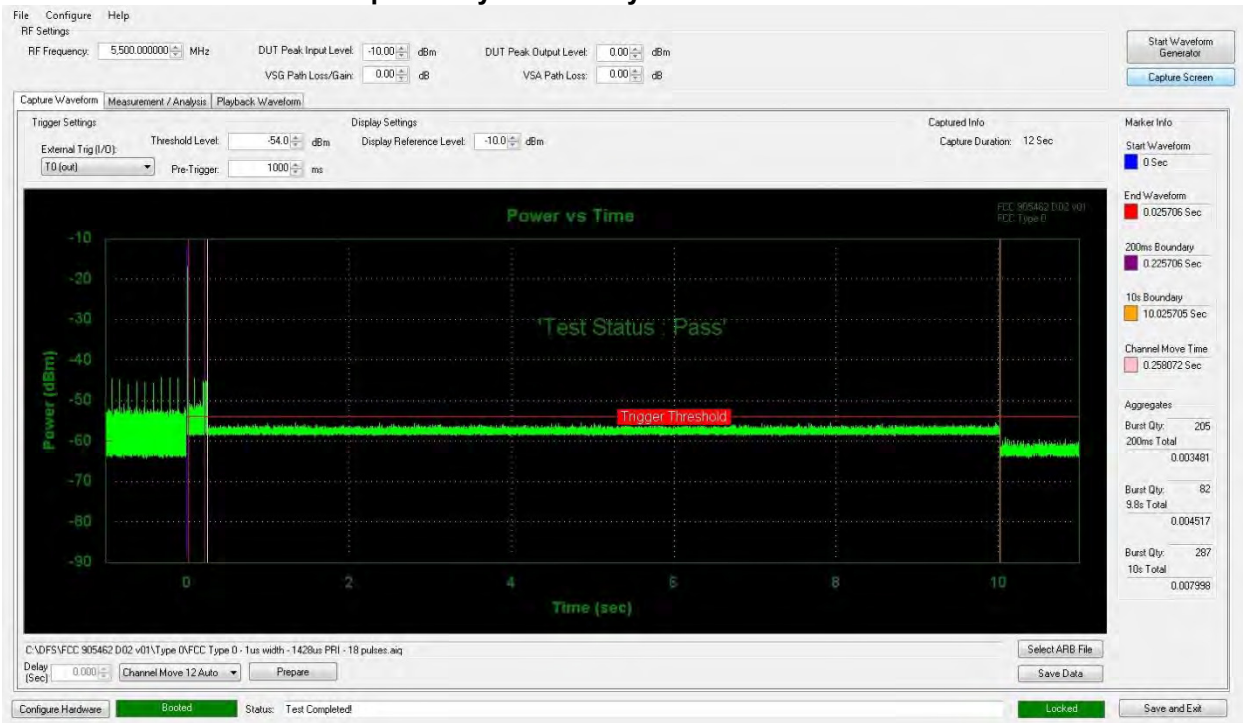
1) Channel Closing Transmission Time (limit is 260 milliseconds)

2) Channel Move Time (limit is 10 seconds)

1) Channel Closing Transmission Time = **7.998 mSecs (limit 260 mSec)**

2) Channel Move Time = **0.258072 Secs (limit is 10 seconds)**

Channel Move Time, Channel Closing Transmission Time for Type 1 Radar Captured by the Test System - 0-12 Seconds



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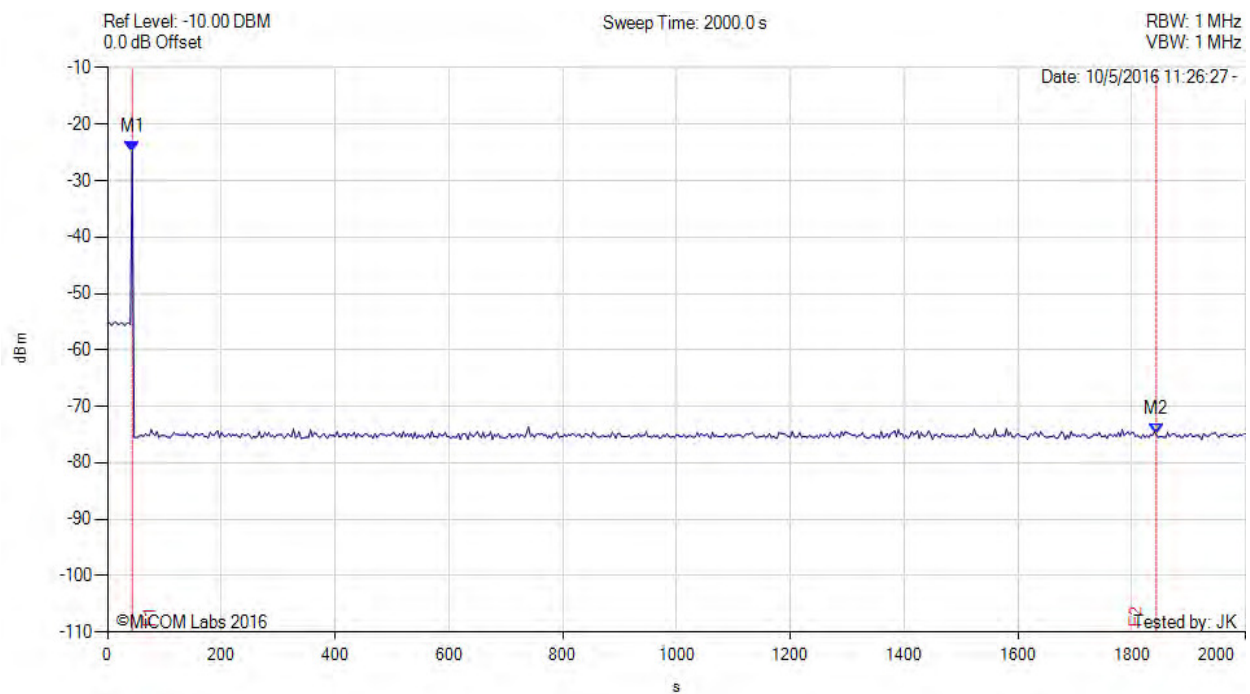
9.1.3. Non-Occupancy Period

The EUT is monitored for more than 30 minutes following the channel close/move time to verify no transmissions resume on this Channel. There should be no transmissions on the frequency of interest during the non-occupancy period.



NON-OCCUPANCY PERIOD

Variant: 802.11ac 80, Channel: 5530.00 MHz, Data Rate: MCS0, Duty Cycle : 17.00%, Antenna Gain: 5.7 dBi



Analyzer Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1 : 43.330 s : -24.830 dBm M2 : 1843.330 s : -75.000 dBm	Channel Frequency: 5530.00 MHz $F2 - F1 = 1843.330 - 43.330 = 1800.00$ s

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9.1.4. Probability of Detection

The steps below define the procedure to determine the minimum percentage of detection when a radar burst with a level equal to the DFS Detection Threshold is generated on the Operating Channel of the U-NII device.

The Radar Waveform generator sends the individual waveform for each of the radar Types 1-6. Statistical data will be gathered to determine the ability of the device to detect the radar test waveforms. The device can utilize a test mode to demonstrate when detection occurs to prevent the need to reset the device between trial runs. The percentage of successful detection is calculated by:

$$\text{Total \# of detections} \div \text{Total \# of Trials} \times 100 = \text{Probability of Detection}$$

The Minimum number of trails, minimum percentage of successful detection and the average minimum percentage of successful detection are found in the Radar Test Waveforms section.

The aggregate is the average of the percentage of successful detections of Short Pulse Radar Types 1-4. For example, the following table indicates how to compute the aggregate of percentage of successful detections;

Example - Calculation of Aggregate Percentage

Radar Type	Number of Trials	Number of Successful Detections	Minimum Percentage of Successful Detections
1	35	29	82.9%
2	30	18	60.0%
3	30	27	90.0%
4	30	44	88.0%
Aggregate (82.9% + 60.0% + 90.0% +88.0%) / 4 = 80.2%			



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802.11a - 5500 MHz

Statistical Performance Check					
Radar Type	Number of Trials	Number of Successful Detections	Percentage of Successful Detections	Result	Data Link
Radar Type 1	30	30	100.00%	Complies	View Data
Radar Type 2	30	30	100.00%	Complies	View Data
Radar Type 3	30	30	100.00%	Complies	View Data
Radar Type 4	30	30	100.00%	Complies	View Data
Aggregate (100.00% + 100.00% + 100.00% + 100.00%) / 4 = 100.00%				Complies	--
Radar Type 5	30	30	100.00%	Complies	View Data
Radar Type 6	30	30	100.00%	Complies	View Data

802.11ac 80 - 5530 MHz

Statistical Performance Check					
Radar Type	Number of Trials	Number of Successful Detections	Percentage of Successful Detections	Result	Data Link
Radar Type 1	30	30	100.00%	Complies	View Data
Radar Type 2	30	30	100.00%	Complies	View Data
Radar Type 3	30	30	100.00%	Complies	View Data
Radar Type 4	30	30	100.00%	Complies	View Data
Aggregate (100.00% + 100.00% + 100.00% + 100.00%) / 4 = 100.00%				Complies	--
Radar Type 5	30	30	100.00%	Complies	View Data
Radar Type 6	30	30	100.00%	Complies	View Data

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g802.11n HT40 - 5510 MHz

Statistical Performance Check					
Radar Type	Number of Trials	Number of Successful Detections	Percentage of Successful Detections	Result	Data Link
Radar Type 1	30	30	100.00%	Complies	View Data
Radar Type 2	30	30	100.00%	Complies	View Data
Radar Type 3	30	30	100.00%	Complies	View Data
Radar Type 4	30	30	100.00%	Complies	View Data
Aggregate (100.00% + 100.00% + 100.00% + 100.00%) / 4 = 100.00%				Complies	--
Radar Type 5	30	30	100.00%	Complies	View Data
Radar Type 6	30	30	100.00%	Complies	View Data

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Equipment Configuration for Radar Type 1

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1	1567	638	83	1	1	100.00%	DETECTED
1	1730	578	92	1	1	100.00%	DETECTED
1	1066	938	57	1	1	100.00%	DETECTED
1	1222	818	65	1	1	100.00%	DETECTED
1	1792	558	95	1	1	100.00%	DETECTED
1	1285	778	68	1	1	100.00%	DETECTED
1	1355	738	72	1	1	100.00%	DETECTED
1	326	3066	18	1	1	100.00%	DETECTED
1	1618	618	86	1	1	100.00%	DETECTED
1	1253	798	67	1	1	100.00%	DETECTED
1	1672	598	89	1	1	100.00%	DETECTED
1	1166	858	62	1	1	100.00%	DETECTED
1	1859	538	99	1	1	100.00%	DETECTED
1	1475	678	78	1	1	100.00%	DETECTED
1	1433	698	76	1	1	100.00%	DETECTED
1	935	1069	50	1	1	100.00%	DETECTED
1	628	1593	34	1	1	100.00%	DETECTED
1	329	3038	18	1	1	100.00%	DETECTED
1	363	2755	20	1	1	100.00%	DETECTED
1	378	2649	20	1	1	100.00%	DETECTED
1	701	1427	37	1	1	100.00%	DETECTED
1	594	1684	32	1	1	100.00%	DETECTED
1	704	1420	38	1	1	100.00%	DETECTED
1	564	1773	30	1	1	100.00%	DETECTED
1	426	2345	23	1	1	100.00%	DETECTED
1	476	2099	26	1	1	100.00%	DETECTED
1	345	2898	19	1	1	100.00%	DETECTED
1	371	2699	20	1	1	100.00%	DETECTED
1	655	1527	35	1	1	100.00%	DETECTED
1	494	2026	27	1	1	100.00%	DETECTED
Aggregate:				30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 2

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1.1	4367	229	26	1	1	100.00%	DETECTED
1.4	5319	188	23	1	1	100.00%	DETECTED
1.8	4587	218	28	1	1	100.00%	DETECTED
2.1	6173	162	24	1	1	100.00%	DETECTED
2.1	4831	207	29	1	1	100.00%	DETECTED
2.1	5650	177	24	1	1	100.00%	DETECTED
2.4	6098	164	26	1	1	100.00%	DETECTED
2.4	4464	224	23	1	1	100.00%	DETECTED
2.7	6410	156	29	1	1	100.00%	DETECTED
2.7	5102	196	26	1	1	100.00%	DETECTED
2.7	4878	205	23	1	1	100.00%	DETECTED
2.8	4831	207	29	1	1	100.00%	DETECTED
3.1	4902	204	29	1	1	100.00%	DETECTED
3.1	5076	197	27	1	1	100.00%	DETECTED
3.3	5814	172	28	1	1	100.00%	DETECTED
3.4	6536	153	24	1	1	100.00%	DETECTED
3.4	4566	219	24	1	1	100.00%	DETECTED
3.5	5263	190	23	1	1	100.00%	DETECTED
3.5	5319	188	29	1	1	100.00%	DETECTED
3.8	5618	178	23	1	1	100.00%	DETECTED
4.2	6135	163	23	1	1	100.00%	DETECTED
4.2	5464	183	27	1	1	100.00%	DETECTED
4.5	4950	202	23	1	1	100.00%	DETECTED
4.5	5587	179	24	1	1	100.00%	DETECTED
4.5	4673	214	27	1	1	100.00%	DETECTED
4.5	5236	191	26	1	1	100.00%	DETECTED
4.5	6369	157	29	1	1	100.00%	DETECTED
4.6	4464	224	26	1	1	100.00%	DETECTED
4.6	5236	191	27	1	1	100.00%	DETECTED
5	5051	198	25	1	1	100.00%	DETECTED
Aggregate:				30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 3

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
6.2	4348	230	17	1	1	100.00%	DETECTED
6.7	2667	375	18	1	1	100.00%	DETECTED
6.7	3650	274	16	1	1	100.00%	DETECTED
6.9	2008	498	17	1	1	100.00%	DETECTED
7.3	3636	275	18	1	1	100.00%	DETECTED
7.5	2994	334	16	1	1	100.00%	DETECTED
7.5	4902	204	17	1	1	100.00%	DETECTED
7.6	2141	467	16	1	1	100.00%	DETECTED
7.7	4808	208	16	1	1	100.00%	DETECTED
8	2141	467	18	1	1	100.00%	DETECTED
8.1	2114	473	18	1	1	100.00%	DETECTED
8.2	4950	202	17	1	1	100.00%	DETECTED
8.4	4975	201	18	1	1	100.00%	DETECTED
8.5	2865	349	18	1	1	100.00%	DETECTED
8.7	3205	312	17	1	1	100.00%	DETECTED
8.7	2404	416	16	1	1	100.00%	DETECTED
8.8	2283	438	17	1	1	100.00%	DETECTED
8.9	2016	496	16	1	1	100.00%	DETECTED
9	2020	495	18	1	1	100.00%	DETECTED
9.2	2457	407	16	1	1	100.00%	DETECTED
9.3	2732	366	17	1	1	100.00%	DETECTED
9.4	2392	418	16	1	1	100.00%	DETECTED
9.4	4831	207	18	1	1	100.00%	DETECTED
9.5	2132	469	16	1	1	100.00%	DETECTED
9.5	3861	259	18	1	1	100.00%	DETECTED
9.6	2907	344	17	1	1	100.00%	DETECTED
9.7	3953	253	18	1	1	100.00%	DETECTED
9.7	2427	412	16	1	1	100.00%	DETECTED
9.8	2041	490	16	1	1	100.00%	DETECTED
9.8	2825	354	18	1	1	100.00%	DETECTED
Aggregate:				30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 4

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
11.1	2041	490	12	1	1	100.00%	DETECTED
11.5	2463	406	12	1	1	100.00%	DETECTED
11.6	2674	374	14	1	1	100.00%	DETECTED
11.7	2028	493	12	1	1	100.00%	DETECTED
12	2841	352	15	1	1	100.00%	DETECTED
12.7	3953	253	12	1	1	100.00%	DETECTED
13.1	3344	299	12	1	1	100.00%	DETECTED
13.1	2433	411	14	1	1	100.00%	DETECTED
13.6	2008	498	15	1	1	100.00%	DETECTED
13.8	4219	237	12	1	1	100.00%	DETECTED
13.9	2353	425	13	1	1	100.00%	DETECTED
14.1	3559	281	16	1	1	100.00%	DETECTED
14.4	4167	240	16	1	1	100.00%	DETECTED
14.8	2326	430	12	1	1	100.00%	DETECTED
14.9	2212	452	16	1	1	100.00%	DETECTED
14.9	2660	376	15	1	1	100.00%	DETECTED
15.1	4608	217	15	1	1	100.00%	DETECTED
15.2	2070	483	13	1	1	100.00%	DETECTED
15.6	3731	268	15	1	1	100.00%	DETECTED
16	2451	408	16	1	1	100.00%	DETECTED
16.4	2203	454	13	1	1	100.00%	DETECTED
16.6	3984	251	13	1	1	100.00%	DETECTED
16.6	3205	312	14	1	1	100.00%	DETECTED
16.9	3401	294	14	1	1	100.00%	DETECTED
17.1	2890	346	16	1	1	100.00%	DETECTED
17.3	4739	211	12	1	1	100.00%	DETECTED
17.4	3185	314	16	1	1	100.00%	DETECTED
17.6	2421	413	16	1	1	100.00%	DETECTED
19.8	2770	361	13	1	1	100.00%	DETECTED
20	2882	347	16	1	1	100.00%	DETECTED
Aggregate:				30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 5

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Injections	Detections	Detection Rate	Result
Type 5 #0 5494.40	1	1	100.00%	DETECTED
Type 5 #1 5505.20	1	1	100.00%	DETECTED
Type 5 #2 5500.00	1	1	100.00%	DETECTED
Type 5 #3 5492.40	1	1	100.00%	DETECTED
Type 5 #4 5505.60	1	1	100.00%	DETECTED
Type 5 #5 5492.80	1	1	100.00%	DETECTED
Type 5 #6 5500.00	1	1	100.00%	DETECTED
Type 5 #7 5496.00	1	1	100.00%	DETECTED
Type 5 #8 5493.20	1	1	100.00%	DETECTED
Type 5 #9 5503.20	1	1	100.00%	DETECTED
Type 5 #10 5500.00	1	1	100.00%	DETECTED
Type 5 #11 5500.00	1	1	100.00%	DETECTED
Type 5 #12 5506.00	1	1	100.00%	DETECTED
Type 5 #13 5500.00	1	1	100.00%	DETECTED
Type 5 #14 5506.40	1	1	100.00%	DETECTED
Type 5 #15 5500.00	1	1	100.00%	DETECTED
Type 5 #16 5500.00	1	1	100.00%	DETECTED
Type 5 #17 5494.80	1	1	100.00%	DETECTED
Type 5 #18 5500.00	1	1	100.00%	DETECTED
Type 5 #19 5492.40	1	1	100.00%	DETECTED
Type 5 #20 5497.60	1	1	100.00%	DETECTED
Type 5 #21 5507.60	1	1	100.00%	DETECTED
Type 5 #22 5503.60	1	1	100.00%	DETECTED
Type 5 #23 5500.00	1	1	100.00%	DETECTED
Type 5 #24 5506.40	1	1	100.00%	DETECTED
Type 5 #25 5504.00	1	1	100.00%	DETECTED
Type 5 #26 5505.60	1	1	100.00%	DETECTED
Type 5 #27 5500.00	1	1	100.00%	DETECTED
Type 5 #28 5493.20	1	1	100.00%	DETECTED
Type 5 #29 5494.00	1	1	100.00%	DETECTED
Aggregate:	30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 6

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Detections	Injection #	Detection Rate	Pass/Fail
Type 6 #1	1	1	100.00%	DETECTED
Type 6 #2	1	1	100.00%	DETECTED
Type 6 #3	1	1	100.00%	DETECTED
Type 6 #4	1	1	100.00%	DETECTED
Type 6 #5	1	1	100.00%	DETECTED
Type 6 #6	1	1	100.00%	DETECTED
Type 6 #7	1	1	100.00%	DETECTED
Type 6 #8	1	1	100.00%	DETECTED
Type 6 #9	1	1	100.00%	DETECTED
Type 6 #10	1	1	100.00%	DETECTED
Type 6 #11	1	1	100.00%	DETECTED
Type 6 #12	1	1	100.00%	DETECTED
Type 6 #13	1	1	100.00%	DETECTED
Type 6 #14	1	1	100.00%	DETECTED
Type 6 #15	1	1	100.00%	DETECTED
Type 6 #16	1	1	100.00%	DETECTED
Type 6 #17	1	1	100.00%	DETECTED
Type 6 #18	1	1	100.00%	DETECTED
Type 6 #19	1	1	100.00%	DETECTED
Type 6 #20	1	1	100.00%	DETECTED
Type 6 #21	1	1	100.00%	DETECTED
Type 6 #22	1	1	100.00%	DETECTED
Type 6 #23	1	1	100.00%	DETECTED
Type 6 #24	1	1	100.00%	DETECTED
Type 6 #25	1	1	100.00%	DETECTED
Type 6 #26	1	1	100.00%	DETECTED
Type 6 #27	1	1	100.00%	DETECTED
Type 6 #28	1	1	100.00%	DETECTED
Type 6 #29	1	1	100.00%	DETECTED
Type 6 #30	1	1	100.00%	DETECTED
Aggregate:	30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 1

Variant:	802.11ac 80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1	1567	638	83	1	1	100.00%	DETECTED
1	1730	578	92	1	1	100.00%	DETECTED
1	1066	938	57	1	1	100.00%	DETECTED
1	1222	818	65	1	1	100.00%	DETECTED
1	1792	558	95	1	1	100.00%	DETECTED
1	1285	778	68	1	1	100.00%	DETECTED
1	1355	738	72	1	1	100.00%	DETECTED
1	326	3066	18	1	1	100.00%	DETECTED
1	1618	618	86	1	1	100.00%	DETECTED
1	1253	798	67	1	1	100.00%	DETECTED
1	1672	598	89	1	1	100.00%	DETECTED
1	1166	858	62	1	1	100.00%	DETECTED
1	1859	538	99	1	1	100.00%	DETECTED
1	1475	678	78	1	1	100.00%	DETECTED
1	1433	698	76	1	1	100.00%	DETECTED
1	935	1069	50	1	1	100.00%	DETECTED
1	628	1593	34	1	1	100.00%	DETECTED
1	329	3038	18	1	1	100.00%	DETECTED
1	363	2755	20	1	1	100.00%	DETECTED
1	378	2649	20	1	1	100.00%	DETECTED
1	701	1427	37	1	1	100.00%	DETECTED
1	594	1684	32	1	1	100.00%	DETECTED
1	704	1420	38	1	1	100.00%	DETECTED
1	564	1773	30	1	1	100.00%	DETECTED
1	426	2345	23	1	1	100.00%	DETECTED
1	476	2099	26	1	1	100.00%	DETECTED
1	345	2898	19	1	1	100.00%	DETECTED
1	371	2699	20	1	1	100.00%	DETECTED
1	655	1527	35	1	1	100.00%	DETECTED
1	494	2026	27	1	1	100.00%	DETECTED
Aggregate:				30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 2

Variant:	802.11ac 80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1.1	4367	229	26	1	1	100.00%	DETECTED
1.4	5319	188	23	1	1	100.00%	DETECTED
1.8	4587	218	28	1	1	100.00%	DETECTED
2.1	6173	162	24	1	1	100.00%	DETECTED
2.1	4831	207	29	1	1	100.00%	DETECTED
2.1	5650	177	24	1	1	100.00%	DETECTED
2.4	6098	164	26	1	1	100.00%	DETECTED
2.4	4464	224	23	1	1	100.00%	DETECTED
2.7	6410	156	29	1	1	100.00%	DETECTED
2.7	5102	196	26	1	1	100.00%	DETECTED
2.7	4878	205	23	1	1	100.00%	DETECTED
2.8	4831	207	29	1	1	100.00%	DETECTED
3.1	4902	204	29	1	1	100.00%	DETECTED
3.1	5076	197	27	1	1	100.00%	DETECTED
3.3	5814	172	28	1	1	100.00%	DETECTED
3.4	6536	153	24	1	1	100.00%	DETECTED
3.4	4566	219	24	1	1	100.00%	DETECTED
3.5	5263	190	23	1	1	100.00%	DETECTED
3.5	5319	188	29	1	1	100.00%	DETECTED
3.8	5618	178	23	1	1	100.00%	DETECTED
4.2	6135	163	23	1	1	100.00%	DETECTED
4.2	5464	183	27	1	1	100.00%	DETECTED
4.5	4950	202	23	1	1	100.00%	DETECTED
4.5	5587	179	24	1	1	100.00%	DETECTED
4.5	4673	214	27	1	1	100.00%	DETECTED
4.5	5236	191	26	1	1	100.00%	DETECTED
4.5	6369	157	29	1	1	100.00%	DETECTED
4.6	4464	224	26	1	1	100.00%	DETECTED
4.6	5236	191	27	1	1	100.00%	DETECTED
5	5051	198	25	1	1	100.00%	DETECTED
Aggregate:				30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 3

Variant:	802.11ac 80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
6.2	4348	230	17	1	1	100.00%	DETECTED
6.7	2667	375	18	1	1	100.00%	DETECTED
6.7	3650	274	16	1	1	100.00%	DETECTED
6.9	2008	498	17	1	1	100.00%	DETECTED
7.3	3636	275	18	1	1	100.00%	DETECTED
7.5	2994	334	16	1	1	100.00%	DETECTED
7.5	4902	204	17	1	1	100.00%	DETECTED
7.6	2141	467	16	1	1	100.00%	DETECTED
7.7	4808	208	16	1	1	100.00%	DETECTED
8	2141	467	18	1	1	100.00%	DETECTED
8.1	2114	473	18	1	1	100.00%	DETECTED
8.2	4950	202	17	1	1	100.00%	DETECTED
8.4	4975	201	18	1	1	100.00%	DETECTED
8.5	2865	349	18	1	1	100.00%	DETECTED
8.7	3205	312	17	1	1	100.00%	DETECTED
8.7	2404	416	16	1	1	100.00%	DETECTED
8.8	2283	438	17	1	1	100.00%	DETECTED
8.9	2016	496	16	1	1	100.00%	DETECTED
9	2020	495	18	1	1	100.00%	DETECTED
9.2	2457	407	16	1	1	100.00%	DETECTED
9.3	2732	366	17	1	1	100.00%	DETECTED
9.4	2392	418	16	1	1	100.00%	DETECTED
9.4	4831	207	18	1	1	100.00%	DETECTED
9.5	2132	469	16	1	1	100.00%	DETECTED
9.5	3861	259	18	1	1	100.00%	DETECTED
9.6	2907	344	17	1	1	100.00%	DETECTED
9.7	3953	253	18	1	1	100.00%	DETECTED
9.7	2427	412	16	1	1	100.00%	DETECTED
9.8	2041	490	16	1	1	100.00%	DETECTED
9.8	2825	354	18	1	1	100.00%	DETECTED
Aggregate:				30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 4

Variant:	802.11ac 80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
11.1	2041	490	12	1	1	100.00%	DETECTED
11.5	2463	406	12	1	1	100.00%	DETECTED
11.6	2674	374	14	1	1	100.00%	DETECTED
11.7	2028	493	12	1	1	100.00%	DETECTED
12	2841	352	15	1	1	100.00%	DETECTED
12.7	3953	253	12	1	1	100.00%	DETECTED
13.1	3344	299	12	1	1	100.00%	DETECTED
13.1	2433	411	14	1	1	100.00%	DETECTED
13.6	2008	498	15	1	1	100.00%	DETECTED
13.8	4219	237	12	1	1	100.00%	DETECTED
13.9	2353	425	13	1	1	100.00%	DETECTED
14.1	3559	281	16	1	1	100.00%	DETECTED
14.4	4167	240	16	1	1	100.00%	DETECTED
14.8	2326	430	12	1	1	100.00%	DETECTED
14.9	2212	452	16	1	1	100.00%	DETECTED
14.9	2660	376	15	1	1	100.00%	DETECTED
15.1	4608	217	15	1	1	100.00%	DETECTED
15.2	2070	483	13	1	1	100.00%	DETECTED
15.6	3731	268	15	1	1	100.00%	DETECTED
16	2451	408	16	1	1	100.00%	DETECTED
16.4	2203	454	13	1	1	100.00%	DETECTED
16.6	3984	251	13	1	1	100.00%	DETECTED
16.6	3205	312	14	1	1	100.00%	DETECTED
16.9	3401	294	14	1	1	100.00%	DETECTED
17.1	2890	346	16	1	1	100.00%	DETECTED
17.3	4739	211	12	1	1	100.00%	DETECTED
17.4	3185	314	16	1	1	100.00%	DETECTED
17.6	2421	413	16	1	1	100.00%	DETECTED
19.8	2770	361	13	1	1	100.00%	DETECTED
20	2882	347	16	1	1	100.00%	DETECTED
Aggregate:				30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 5

Variant:	802.11ac 80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Injections	Detections	Detection Rate	Result
Type 5 #0 5530.00	1	1	100.00%	DETECTED
Type 5 #1 5565.20	1	1	100.00%	DETECTED
Type 5 #2 5492.40	1	1	100.00%	DETECTED
Type 5 #3 5567.60	1	1	100.00%	DETECTED
Type 5 #4 5530.00	1	1	100.00%	DETECTED
Type 5 #5 5530.00	1	1	100.00%	DETECTED
Type 5 #6 5530.00	1	1	100.00%	DETECTED
Type 5 #7 5530.00	1	1	100.00%	DETECTED
Type 5 #8 5530.00	1	1	100.00%	DETECTED
Type 5 #9 5563.20	1	1	100.00%	DETECTED
Type 5 #10 5530.00	1	1	100.00%	DETECTED
Type 5 #11 5565.60	1	1	100.00%	DETECTED
Type 5 #12 5566.00	1	1	100.00%	DETECTED
Type 5 #13 5493.60	1	1	100.00%	DETECTED
Type 5 #14 5493.60	1	1	100.00%	DETECTED
Type 5 #15 5562.80	1	1	100.00%	DETECTED
Type 5 #16 5492.40	1	1	100.00%	DETECTED
Type 5 #17 5494.80	1	1	100.00%	DETECTED
Type 5 #18 5530.00	1	1	100.00%	DETECTED
Type 5 #19 5567.60	1	1	100.00%	DETECTED
Type 5 #20 5562.40	1	1	100.00%	DETECTED
Type 5 #21 5567.60	1	1	100.00%	DETECTED
Type 5 #22 5496.40	1	1	100.00%	DETECTED
Type 5 #23 5492.00	1	1	100.00%	DETECTED
Type 5 #24 5530.00	1	1	100.00%	DETECTED
Type 5 #25 5496.00	1	1	100.00%	DETECTED
Type 5 #26 5530.00	1	1	100.00%	DETECTED
Type 5 #27 5495.60	1	1	100.00%	DETECTED
Type 5 #28 5566.80	1	1	100.00%	DETECTED
Type 5 #29 5494.00	1	1	100.00%	DETECTED
Aggregate:	30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 6

Variant:	802.11ac 80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Detections	Injection #	Detection Rate	Pass/Fail
Type 6 #1	1	1	100.00%	DETECTED
Type 6 #2	1	1	100.00%	DETECTED
Type 6 #3	1	1	100.00%	DETECTED
Type 6 #4	1	1	100.00%	DETECTED
Type 6 #5	1	1	100.00%	DETECTED
Type 6 #6	1	1	100.00%	DETECTED
Type 6 #7	1	1	100.00%	DETECTED
Type 6 #8	1	1	100.00%	DETECTED
Type 6 #9	1	1	100.00%	DETECTED
Type 6 #10	1	1	100.00%	DETECTED
Type 6 #11	1	1	100.00%	DETECTED
Type 6 #12	1	1	100.00%	DETECTED
Type 6 #13	1	1	100.00%	DETECTED
Type 6 #14	1	1	100.00%	DETECTED
Type 6 #15	1	1	100.00%	DETECTED
Type 6 #16	1	1	100.00%	DETECTED
Type 6 #17	1	1	100.00%	DETECTED
Type 6 #18	1	1	100.00%	DETECTED
Type 6 #19	1	1	100.00%	DETECTED
Type 6 #20	1	1	100.00%	DETECTED
Type 6 #21	1	1	100.00%	DETECTED
Type 6 #22	1	1	100.00%	DETECTED
Type 6 #23	1	1	100.00%	DETECTED
Type 6 #24	1	1	100.00%	DETECTED
Type 6 #25	1	1	100.00%	DETECTED
Type 6 #26	1	1	100.00%	DETECTED
Type 6 #27	1	1	100.00%	DETECTED
Type 6 #28	1	1	100.00%	DETECTED
Type 6 #29	1	1	100.00%	DETECTED
Type 6 #30	1	1	100.00%	DETECTED
Aggregate:	30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 1

Variant:	802.11n HT40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1	1567	638	83	1	1	100.00%	DETECTED
1	1730	578	92	1	1	100.00%	DETECTED
1	1066	938	57	1	1	100.00%	DETECTED
1	1222	818	65	1	1	100.00%	DETECTED
1	1792	558	95	1	1	100.00%	DETECTED
1	1285	778	68	1	1	100.00%	DETECTED
1	1355	738	72	1	1	100.00%	DETECTED
1	326	3066	18	1	1	100.00%	DETECTED
1	1618	618	86	1	1	100.00%	DETECTED
1	1253	798	67	1	1	100.00%	DETECTED
1	1672	598	89	1	1	100.00%	DETECTED
1	1166	858	62	1	1	100.00%	DETECTED
1	1859	538	99	1	1	100.00%	DETECTED
1	1475	678	78	1	1	100.00%	DETECTED
1	1433	698	76	1	1	100.00%	DETECTED
1	935	1069	50	1	1	100.00%	DETECTED
1	628	1593	34	1	1	100.00%	DETECTED
1	329	3038	18	1	1	100.00%	DETECTED
1	363	2755	20	1	1	100.00%	DETECTED
1	378	2649	20	1	1	100.00%	DETECTED
1	701	1427	37	1	1	100.00%	DETECTED
1	594	1684	32	1	1	100.00%	DETECTED
1	704	1420	38	1	1	100.00%	DETECTED
1	564	1773	30	1	1	100.00%	DETECTED
1	426	2345	23	1	1	100.00%	DETECTED
1	476	2099	26	1	1	100.00%	DETECTED
1	345	2898	19	1	1	100.00%	DETECTED
1	371	2699	20	1	1	100.00%	DETECTED
1	655	1527	35	1	1	100.00%	DETECTED
1	494	2026	27	1	1	100.00%	DETECTED
Aggregate:				30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 2

Variant:	802.11n HT40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
1.1	4367	229	26	1	1	100.00%	DETECTED
1.4	5319	188	23	1	1	100.00%	DETECTED
1.8	4587	218	28	1	1	100.00%	DETECTED
2.1	6173	162	24	1	1	100.00%	DETECTED
2.1	4831	207	29	1	1	100.00%	DETECTED
2.1	5650	177	24	1	1	100.00%	DETECTED
2.4	6098	164	26	1	1	100.00%	DETECTED
2.4	4464	224	23	1	1	100.00%	DETECTED
2.7	6410	156	29	1	1	100.00%	DETECTED
2.7	5102	196	26	1	1	100.00%	DETECTED
2.7	4878	205	23	1	1	100.00%	DETECTED
2.8	4831	207	29	1	1	100.00%	DETECTED
3.1	4902	204	29	1	1	100.00%	DETECTED
3.1	5076	197	27	1	1	100.00%	DETECTED
3.3	5814	172	28	1	1	100.00%	DETECTED
3.4	6536	153	24	1	1	100.00%	DETECTED
3.4	4566	219	24	1	1	100.00%	DETECTED
3.5	5263	190	23	1	1	100.00%	DETECTED
3.5	5319	188	29	1	1	100.00%	DETECTED
3.8	5618	178	23	1	1	100.00%	DETECTED
4.2	6135	163	23	1	1	100.00%	DETECTED
4.2	5464	183	27	1	1	100.00%	DETECTED
4.5	4950	202	23	1	1	100.00%	DETECTED
4.5	5587	179	24	1	1	100.00%	DETECTED
4.5	4673	214	27	1	1	100.00%	DETECTED
4.5	5236	191	26	1	1	100.00%	DETECTED
4.5	6369	157	29	1	1	100.00%	DETECTED
4.6	4464	224	26	1	1	100.00%	DETECTED
4.6	5236	191	27	1	1	100.00%	DETECTED
5	5051	198	25	1	1	100.00%	DETECTED
Aggregate:				30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 3

Variant:	802.11n HT40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
6.2	4348	230	17	1	1	100.00%	DETECTED
6.7	2667	375	18	1	1	100.00%	DETECTED
6.7	3650	274	16	1	1	100.00%	DETECTED
6.9	2008	498	17	1	1	100.00%	DETECTED
7.3	3636	275	18	1	1	100.00%	DETECTED
7.5	2994	334	16	1	1	100.00%	DETECTED
7.5	4902	204	17	1	1	100.00%	DETECTED
7.6	2141	467	16	1	1	100.00%	DETECTED
7.7	4808	208	16	1	1	100.00%	DETECTED
8	2141	467	18	1	1	100.00%	DETECTED
8.1	2114	473	18	1	1	100.00%	DETECTED
8.2	4950	202	17	1	1	100.00%	DETECTED
8.4	4975	201	18	1	1	100.00%	DETECTED
8.5	2865	349	18	1	1	100.00%	DETECTED
8.7	3205	312	17	1	1	100.00%	DETECTED
8.7	2404	416	16	1	1	100.00%	DETECTED
8.8	2283	438	17	1	1	100.00%	DETECTED
8.9	2016	496	16	1	1	100.00%	DETECTED
9	2020	495	18	1	1	100.00%	DETECTED
9.2	2457	407	16	1	1	100.00%	DETECTED
9.3	2732	366	17	1	1	100.00%	DETECTED
9.4	2392	418	16	1	1	100.00%	DETECTED
9.4	4831	207	18	1	1	100.00%	DETECTED
9.5	2132	469	16	1	1	100.00%	DETECTED
9.5	3861	259	18	1	1	100.00%	DETECTED
9.6	2907	344	17	1	1	100.00%	DETECTED
9.7	3953	253	18	1	1	100.00%	DETECTED
9.7	2427	412	16	1	1	100.00%	DETECTED
9.8	2041	490	16	1	1	100.00%	DETECTED
9.8	2825	354	18	1	1	100.00%	DETECTED
Aggregate:				30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 4

Variant:	802.11n HT40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Pulse Width (us)	PRF (Hz)	PRI	# Pulses	Injections	Detections	Detection Rate	Result
11.1	2041	490	12	1	1	100.00%	DETECTED
11.5	2463	406	12	1	1	100.00%	DETECTED
11.6	2674	374	14	1	1	100.00%	DETECTED
11.7	2028	493	12	1	1	100.00%	DETECTED
12	2841	352	15	1	1	100.00%	DETECTED
12.7	3953	253	12	1	1	100.00%	DETECTED
13.1	3344	299	12	1	1	100.00%	DETECTED
13.1	2433	411	14	1	1	100.00%	DETECTED
13.6	2008	498	15	1	1	100.00%	DETECTED
13.8	4219	237	12	1	1	100.00%	DETECTED
13.9	2353	425	13	1	1	100.00%	DETECTED
14.1	3559	281	16	1	1	100.00%	DETECTED
14.4	4167	240	16	1	1	100.00%	DETECTED
14.8	2326	430	12	1	1	100.00%	DETECTED
14.9	2212	452	16	1	1	100.00%	DETECTED
14.9	2660	376	15	1	1	100.00%	DETECTED
15.1	4608	217	15	1	1	100.00%	DETECTED
15.2	2070	483	13	1	1	100.00%	DETECTED
15.6	3731	268	15	1	1	100.00%	DETECTED
16	2451	408	16	1	1	100.00%	DETECTED
16.4	2203	454	13	1	1	100.00%	DETECTED
16.6	3984	251	13	1	1	100.00%	DETECTED
16.6	3205	312	14	1	1	100.00%	DETECTED
16.9	3401	294	14	1	1	100.00%	DETECTED
17.1	2890	346	16	1	1	100.00%	DETECTED
17.3	4739	211	12	1	1	100.00%	DETECTED
17.4	3185	314	16	1	1	100.00%	DETECTED
17.6	2421	413	16	1	1	100.00%	DETECTED
19.8	2770	361	13	1	1	100.00%	DETECTED
20	2882	347	16	1	1	100.00%	DETECTED
Aggregate:				30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 5

Variant:	802.11n HT40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Injections	Detections	Detection Rate	Result
Type 5 #0 5494.40	1	1	100.00%	DETECTED
Type 5 #1 5494.80	1	1	100.00%	DETECTED
Type 5 #2 5510.00	1	1	100.00%	DETECTED
Type 5 #3 5492.40	1	1	100.00%	DETECTED
Type 5 #4 5510.00	1	1	100.00%	DETECTED
Type 5 #5 5510.00	1	1	100.00%	DETECTED
Type 5 #6 5510.00	1	1	100.00%	DETECTED
Type 5 #7 5524.00	1	1	100.00%	DETECTED
Type 5 #8 5493.20	1	1	100.00%	DETECTED
Type 5 #9 5523.20	1	1	100.00%	DETECTED
Type 5 #10 5510.00	1	1	100.00%	DETECTED
Type 5 #11 5525.60	1	1	100.00%	DETECTED
Type 5 #12 5526.00	1	1	100.00%	DETECTED
Type 5 #13 5510.00	1	1	100.00%	DETECTED
Type 5 #14 5493.60	1	1	100.00%	DETECTED
Type 5 #15 5522.80	1	1	100.00%	DETECTED
Type 5 #16 5492.40	1	1	100.00%	DETECTED
Type 5 #17 5525.20	1	1	100.00%	DETECTED
Type 5 #18 5527.20	1	1	100.00%	DETECTED
Type 5 #19 5492.40	1	1	100.00%	DETECTED
Type 5 #20 5510.00	1	1	100.00%	DETECTED
Type 5 #21 5510.00	1	1	100.00%	DETECTED
Type 5 #22 5510.00	1	1	100.00%	DETECTED
Type 5 #23 5492.00	1	1	100.00%	DETECTED
Type 5 #24 5493.60	1	1	100.00%	DETECTED
Type 5 #25 5524.00	1	1	100.00%	DETECTED
Type 5 #26 5525.60	1	1	100.00%	DETECTED
Type 5 #27 5524.40	1	1	100.00%	DETECTED
Type 5 #28 5493.20	1	1	100.00%	DETECTED
Type 5 #29 5510.00	1	1	100.00%	DETECTED
Aggregate:	30.00	30.00	100.00%	Pass

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Equipment Configuration for Radar Type 6

Variant:	802.11n HT40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Detections	Injection #	Detection Rate	Pass/Fail
Type 6 #1	1	1	100.00%	DETECTED
Type 6 #2	1	1	100.00%	DETECTED
Type 6 #3	1	1	100.00%	DETECTED
Type 6 #4	1	1	100.00%	DETECTED
Type 6 #5	1	1	100.00%	DETECTED
Type 6 #6	1	1	100.00%	DETECTED
Type 6 #7	1	1	100.00%	DETECTED
Type 6 #8	1	1	100.00%	DETECTED
Type 6 #9	1	1	100.00%	DETECTED
Type 6 #10	1	1	100.00%	DETECTED
Type 6 #11	1	1	100.00%	DETECTED
Type 6 #12	1	1	100.00%	DETECTED
Type 6 #13	1	1	100.00%	DETECTED
Type 6 #14	1	1	100.00%	DETECTED
Type 6 #15	1	1	100.00%	DETECTED
Type 6 #16	1	1	100.00%	DETECTED
Type 6 #17	1	1	100.00%	DETECTED
Type 6 #18	1	1	100.00%	DETECTED
Type 6 #19	1	1	100.00%	DETECTED
Type 6 #20	1	1	100.00%	DETECTED
Type 6 #21	1	1	100.00%	DETECTED
Type 6 #22	1	1	100.00%	DETECTED
Type 6 #23	1	1	100.00%	DETECTED
Type 6 #24	1	1	100.00%	DETECTED
Type 6 #25	1	1	100.00%	DETECTED
Type 6 #26	1	1	100.00%	DETECTED
Type 6 #27	1	1	100.00%	DETECTED
Type 6 #28	1	1	100.00%	DETECTED
Type 6 #29	1	1	100.00%	DETECTED
Type 6 #30	1	1	100.00%	DETECTED
Aggregate:	30.00	30.00	100.00%	Pass

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9.1.5. Detection Bandwidth

To determine the equipment Detection Bandwidth for each applicable operational mode a single burst of the short pulse radar Type 0 was produced at the appropriate power level. The EUT was set up as a standalone device (no associated Client or Master, as appropriate) and no traffic. Frame based systems will be set to a talk/listen ratio reflecting the worst case (maximum) that is user configurable during this test.

To determine the actual receiver bandwidth a single radar burst is generated for a minimum of 10 trials and the response of the EUT noted. The EUT must detect the Radar Waveform until it fails to detect, at this point testing is stopped and the frequency noted.

Starting from the actual channel center frequency the radar frequency is increased in 5 MHz steps, repeating the above test sequence, until the detection rate falls below 90%. The previous 5 MHz are tested again with a 1 MHz step size. The highest frequency at which detection is greater than or equal to 90% is denoted as F_H . Note for the higher bandwidths ac-80 etc. the step size can be increased.

The radar frequency is decreased in 5 MHz steps, repeating the above test sequence, until the detection rate falls below 90%. The lowest frequency at which detection is greater than or equal to 90% is denoted as F_L .

The U-NII Detection Bandwidth is calculated as follows:

$$\text{U-NII Detection Bandwidth} = F_H - F_L$$

The U-NII Detection Bandwidth must meet the U-NII Detection Bandwidth criterion specified. Otherwise, the UUT does not comply with DFS requirements. This is essential to ensure that the UUT is capable of detecting Radar Waveforms across the same frequency spectrum that contains the significant energy from the system. In the case that the U-NII Detection Bandwidth is greater than or equal to the 99% power bandwidth for the measured F_H and F_L , the test can be truncated and the U-NII Detection Bandwidth can be reported as the measured F_H and F_L .



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Equipment Configuration for Detection Bandwidth

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency	Injections	Detections	Detection Rate	Result
5485 MHz	10	0		
5486 MHz	10	0		
5487 MHz	10	0		
5488 MHz	10	0		
5489 MHz	10	0		
5490 MHz	10	10	100.00%	Detected
5495 MHz	10	10	100.00%	Detected
5500	10	10	100.00%	Detected
5505 MHz	10	10	100.00%	Detected
5506 MHz	10	10	100.00%	Detected
5507 MHz	10	10	100.00%	Detected
5508 MHz	10	10	100.00%	Detected
5509 MHz	10	10	100.00%	Detected
5510 MHz	10	6	60.00%	Not Detected

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Equipment Configuration for Detection Bandwidth

Variant:	802.11ac 80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency	Injections	Detections	Detection Rate	Result
5490 MHz	10	5	50.00%	Not Detected
5491 MHz	10	10	100.00%	Detected
5492 MHz	10	10	100.00%	Detected
5493 MHz	10	10	100.00%	Detected
5494 MHz	10	10	100.00%	Detected
5495 MHz	10	10	100.00%	Detected
5500 MHz	10	10	100.00%	Detected
5505 MHz	10	10	100.00%	Detected
5510 MHz	10	10	100.00%	Detected
5515 MHz	10	10	100.00%	Detected
5520 MHz	10	10	100.00%	Detected
5525 MHz	10	10	100.00%	Detected
5530	10	10	100.00%	Detected
5535 MHz	10	10	100.00%	Detected
5540 MHz	10	10	100.00%	Detected
5545 MHz	10	10	100.00%	Detected
5550 MHz	10	10	100.00%	Detected
5555 MHz	10	10	100.00%	Detected
5560 MHz	10	10	100.00%	Detected
5565 MHz	10	10	100.00%	Detected
5570 MHz	10	10	100.00%	Detected
5571 MHz	10	0		
5572 MHz	10	0		
5573 MHz	10	0		
5574 MHz	10	0		
5575 MHz	10	0		

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Equipment Configuration for Detection Bandwidth

Variant:	802.11n HT40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	5.7
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency	Injections	Detections	Detection Rate	Result
5485 MHz	10	0		
5486 MHz	10	0		
5487 MHz	10	0		
5488 MHz	10	0		
5489 MHz	10	0		
5490 MHz	10	10	100.00%	Detected
5495 MHz	10	10	100.00%	Detected
5500 MHz	10	10	100.00%	Detected
5505 MHz	10	10	100.00%	Detected
5510	10	10	100.00%	Detected
5515 MHz	10	10	100.00%	Detected
5520 MHz	10	10	100.00%	Detected
5525 MHz	10	10	100.00%	Detected
5530 MHz	10	10	100.00%	Detected
5531 MHz	10	0		
5532 MHz	10	0		
5533 MHz	10	0		
5534 MHz	10	0		
5535 MHz	10	0		

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A. APPENDIX – RADAR SIGNATURES

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Type 5 #0 5494.40 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	82573	83	0	0	548922	631578
2	1	6	94954	90	0	0	536534	631578
3	3	17	140883	78	1105	1686	487670	631578
4	3	20	66537	95	1090	1028	562638	631578
5	1	18	58146	57	0	0	573375	631578
6	2	20	524935	88	1644	0	104823	631578
7	3	11	321993	94	1300	1352	306651	631578
8	2	11	394690	54	1591	0	235189	631578
9	2	11	2024	74	1361	0	628045	631578
10	2	16	514932	81	1317	0	115167	631578
11	2	5	343498	50	1864	0	286116	631578
12	1	19	293192	90	0	0	338296	631578
13	2	10	91862	94	1223	0	538305	631578
14	3	17	130005	70	1247	1642	498474	631578
15	3	13	534364	80	1417	1534	94023	631578
16	3	6	122412	70	1071	1067	506818	631578
17	2	7	217816	50	1809	0	411853	631578
18	2	11	108539	95	1737	0	521112	631578
19	3	17	163398	65	1066	1095	465824	631578

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Type 5 #1 5505.20 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	9	134636	87	944	0	570128	705882
2	1	12	394003	98	0	0	311781	705882
3	1	10	276849	85	0	0	428948	705882
4	3	8	211281	66	1604	960	491839	705882
5	3	5	210278	92	1217	1325	492786	705882
6	2	16	517464	81	1155	0	187101	705882
7	2	12	337163	85	1575	0	366974	705882
8	2	7	696533	92	1051	0	8114	705882
9	1	17	127171	69	0	0	578642	705882
10	1	12	237670	52	0	0	468160	705882
11	2	6	606178	55	1049	0	98545	705882
12	1	14	300880	97	0	0	404905	705882
13	3	18	166119	87	1324	1173	537005	705882
14	3	5	250551	91	1802	1642	451614	705882
15	3	13	518671	68	1816	1244	183947	705882
16	2	7	177823	63	1148	0	526785	705882
17	3	6	265906	64	1070	1578	437136	705882

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Type 5 #2 5500.00 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	19	652684	87	0	0	13895	666666
2	3	10	99407	72	1506	1894	563643	666666
3	3	8	650394	68	1086	1640	13342	666666
4	3	14	370107	87	1133	1461	293704	666666
5	2	9	318886	65	1606	0	346044	666666
6	3	7	291928	56	1046	1125	372399	666666
7	1	20	293804	86	0	0	372776	666666
8	3	6	512592	70	1487	1665	150712	666666
9	1	17	7334	65	0	0	659267	666666
10	1	9	290911	61	0	0	375694	666666
11	2	7	412669	52	1229	0	252664	666666
12	1	15	189790	81	0	0	476795	666666
13	3	12	519213	72	1741	975	144521	666666
14	3	12	485784	51	1662	1488	177579	666666
15	1	15	542472	76	0	0	124118	666666
16	3	5	252980	59	1471	1601	410437	666666
17	2	16	83277	92	1614	0	581591	666666
18	1	6	493008	95	0	0	173563	666666

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Type 5 #3 5492.40 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	73701	56	0	0	592909	666666
2	1	8	342257	98	0	0	324311	666666
3	3	15	467024	100	1415	1662	196265	666666
4	1	12	311695	77	0	0	354894	666666
5	3	14	378820	53	1098	1572	285017	666666
6	3	6	425533	81	1261	1576	238053	666666
7	1	20	474122	67	0	0	192477	666666
8	2	11	350173	60	1494	0	314879	666666
9	3	12	479096	98	1589	1576	184111	666666
10	1	5	424932	53	0	0	241681	666666
11	2	11	449034	90	1169	0	216283	666666
12	1	12	368113	55	0	0	298498	666666
13	1	18	600388	84	0	0	66194	666666
14	3	18	33184	60	1254	1482	630566	666666
15	1	7	626596	94	0	0	39976	666666
16	3	6	631578	50	1061	1415	32462	666666
17	3	13	51190	83	1000	1622	612605	666666
18	3	6	246242	85	1213	1404	417552	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	18	448075	62	1898	984	254739	705882
2	2	11	13331	91	1505	0	690864	705882
3	3	11	174147	89	1760	1397	528311	705882
4	2	15	495782	55	1493	0	208497	705882
5	2	17	549145	56	1139	0	155486	705882
6	2	8	395408	57	1187	0	309173	705882
7	3	10	36326	58	1647	1026	666709	705882
8	1	20	95222	74	0	0	610586	705882
9	2	13	655474	52	1247	0	49057	705882
10	2	8	521074	50	1788	0	182920	705882
11	2	7	402794	87	1045	0	301869	705882
12	3	18	465090	59	1800	1076	237739	705882
13	1	12	654267	67	0	0	51548	705882
14	2	7	138238	55	1346	0	566188	705882
15	2	15	185893	82	1331	0	518494	705882
16	2	12	87980	80	1185	0	616557	705882
17	2	11	129182	97	1407	0	575099	705882

Type 5 #5 5492.80 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	7	291502	59	1292	1815	1038547	1333333
2	2	12	941450	93	1167	0	390530	1333333
3	1	10	737468	68	0	0	595797	1333333
4	3	15	94614	91	1162	1650	1235634	1333333
5	3	20	779543	94	1046	1601	550861	1333333
6	3	16	364726	90	1699	1758	964880	1333333
7	3	19	429106	81	929	968	902087	1333333
8	1	18	1253398	51	0	0	79884	1333333
9	1	13	148146	95	0	0	1185092	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	150441	74	1675	0	447736	600000
2	2	9	99921	52	1269	0	498706	600000
3	1	15	529357	59	0	0	70584	600000
4	1	12	515703	88	0	0	84209	600000
5	3	16	456822	79	1562	1772	139607	600000
6	1	16	153876	100	0	0	446024	600000
7	3	6	377868	94	1525	1490	218835	600000
8	1	14	23832	65	0	0	576103	600000
9	2	16	353529	92	1272	0	245015	600000
10	3	7	453814	92	1543	1047	143320	600000
11	1	5	434912	77	0	0	165011	600000
12	2	19	212879	63	1570	0	385425	600000
13	2	16	269446	63	1736	0	328692	600000
14	2	14	598328	55	1540	0	22	600000
15	3	7	576613	88	1344	1176	20603	600000
16	3	5	105004	66	940	1861	491997	600000
17	2	12	198835	79	1534	0	399473	600000
18	1	5	224707	95	0	0	375198	600000
19	1	8	365749	84	0	0	234167	600000
20	1	20	547924	55	0	0	52021	600000

Type 5 #7 5496.00 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	13	16301	62	1573	1356	1313917	1333333
2	1	17	1012553	55	0	0	320725	1333333
3	3	19	338094	97	1530	1332	992086	1333333
4	3	9	95120	57	1781	1067	1235194	1333333
5	3	15	1197666	78	1412	996	133025	1333333
6	3	18	1219151	97	1783	1320	110788	1333333
7	1	15	952735	84	0	0	380514	1333333
8	1	14	309101	74	0	0	1024158	1333333
9	1	10	594795	56	0	0	738482	1333333

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Type 5 #8 5493.20 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	10	411448	91	0	0	588461	1000000
2	3	6	547685	82	927	1591	449551	1000000
3	3	19	277612	50	1889	1094	719255	1000000
4	3	18	363214	95	1417	1869	633215	1000000
5	3	8	267280	81	1901	1737	728839	1000000
6	3	14	138481	91	1130	1088	859028	1000000
7	1	12	523668	54	0	0	476278	1000000
8	3	10	129323	62	1846	1528	867117	1000000
9	2	8	423792	85	1461	0	574577	1000000
10	3	8	386208	71	1425	1864	610290	1000000
11	3	16	823445	53	1156	1930	173310	1000000
12	3	18	827182	55	1931	1720	169002	1000000

Type 5 #9 5503.20 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	17	397714	53	1263	955	266575	666666
2	1	17	413660	52	0	0	252954	666666
3	3	16	623207	75	1197	1769	40268	666666
4	2	16	499857	66	1178	0	165499	666666
5	2	16	606022	50	1265	0	59279	666666
6	2	17	96206	77	1659	0	568647	666666
7	3	12	93817	94	1542	1269	569756	666666
8	1	19	509242	61	0	0	157363	666666
9	1	12	489582	96	0	0	176988	666666
10	3	13	297591	61	1903	1116	365873	666666
11	2	14	376484	52	986	0	289092	666666
12	1	5	65077	53	0	0	601536	666666
13	1	9	26244	82	0	0	640340	666666
14	2	14	423461	57	1248	0	241843	666666
15	2	9	551143	90	1018	0	114325	666666
16	2	12	1842	71	1498	0	663184	666666
17	2	18	407894	84	1485	0	257119	666666
18	1	17	192607	75	0	0	473984	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	87914	66	0	0	835096	923076
2	1	7	61187	86	0	0	861803	923076
3	3	14	844297	99	989	1830	75663	923076
4	2	7	204111	69	1476	0	717351	923076
5	1	7	439812	81	0	0	483183	923076
6	1	11	308535	70	0	0	614471	923076
7	1	17	908644	83	0	0	14349	923076
8	1	19	523119	67	0	0	399890	923076
9	1	8	906123	87	0	0	16866	923076
10	1	10	525853	68	0	0	397155	923076
11	2	13	863533	70	1679	0	57724	923076
12	1	7	873176	61	0	0	49839	923076
13	2	17	774145	59	1883	0	146930	923076

Type 5 #11 5500.00 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	10	69069	85	972	1329	528375	600000
2	3	17	190586	63	964	1288	406973	600000
3	2	14	449414	97	1004	0	149388	600000
4	1	19	399063	78	0	0	200859	600000
5	3	11	360915	84	1899	1334	235600	600000
6	1	7	68759	88	0	0	531153	600000
7	2	16	165081	66	1450	0	433337	600000
8	3	20	85132	65	1389	1548	511736	600000
9	3	14	132112	86	1682	1500	464448	600000
10	2	11	229550	74	1447	0	368855	600000
11	3	18	45092	66	968	1911	551831	600000
12	3	20	544836	76	1441	1528	51967	600000
13	3	19	211651	100	1310	1188	385551	600000
14	2	6	312841	66	1199	0	285828	600000
15	1	17	129023	98	0	0	470879	600000
16	3	15	354598	69	1194	1648	242353	600000
17	1	11	419977	68	0	0	179955	600000
18	1	8	565499	89	0	0	34412	600000
19	3	15	513548	83	1075	1726	83402	600000
20	3	17	585459	84	1010	1045	12234	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	17	835549	85	0	0	364366	1200000
2	1	18	197003	58	0	0	1002939	1200000
3	1	9	1064324	64	0	0	135612	1200000
4	1	15	605407	74	0	0	594519	1200000
5	3	14	192243	52	1181	1332	1005088	1200000
6	2	20	1139187	95	1046	0	59577	1200000
7	2	14	159764	58	1504	0	1038616	1200000
8	3	20	4429	70	1593	1530	1192238	1200000
9	1	10	934090	80	0	0	265830	1200000
10	3	10	449618	69	1202	1421	747552	1200000

Type 5 #13 5500.00 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	726941	55	0	0	606337	1333333
2	3	6	977885	91	1006	1819	352350	1333333
3	3	11	971468	61	945	1494	359243	1333333
4	1	19	697145	57	0	0	636131	1333333
5	3	16	1159697	96	1795	1885	169668	1333333
6	2	8	918613	67	1460	0	413126	1333333
7	2	9	626117	79	1910	0	705148	1333333
8	2	20	1122454	79	1510	0	209211	1333333
9	2	9	517177	85	1127	0	814859	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	15	340995	63	1186	1058	256572	600000
2	3	9	337500	58	1337	1099	259890	600000
3	3	17	27052	60	1811	1323	569634	600000
4	1	6	10652	82	0	0	589266	600000
5	1	13	95579	61	0	0	504360	600000
6	1	11	128377	84	0	0	471539	600000
7	2	14	498109	84	1845	0	99878	600000
8	1	9	340875	79	0	0	259046	600000
9	1	7	433845	86	0	0	166069	600000
10	1	5	69774	68	0	0	530158	600000
11	2	16	133642	53	1254	0	464998	600000
12	3	18	254818	88	1667	1089	342162	600000
13	3	8	30579	99	1073	1661	566390	600000
14	3	20	413168	74	1872	1298	183440	600000
15	1	12	127220	55	0	0	472725	600000
16	3	9	304472	99	910	1762	292559	600000
17	1	14	426397	98	0	0	173505	600000
18	3	17	46814	60	1785	1036	550185	600000
19	3	13	327685	57	1549	1783	268812	600000
20	2	6	30014	84	1793	0	568025	600000

Type 5 #15 5500.00 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	11	241313	69	0	0	958618	1200000
2	3	18	199910	86	1776	1374	996682	1200000
3	2	19	672044	60	1235	0	526601	1200000
4	1	16	865601	57	0	0	334342	1200000
5	1	9	944406	93	0	0	255501	1200000
6	1	18	446731	77	0	0	753192	1200000
7	2	14	1179455	80	1813	0	18572	1200000
8	2	19	363169	94	1142	0	835501	1200000
9	3	5	740679	73	943	1162	456997	1200000
10	3	10	1183142	80	1607	1464	13547	1200000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	7	322105	69	1853	0	675904	1000000
2	3	9	334068	80	1576	1795	662321	1000000
3	2	18	580939	63	1211	0	417724	1000000
4	3	10	437569	52	1272	1694	559309	1000000
5	1	6	612739	84	0	0	387177	1000000
6	3	13	825842	52	1139	1132	171731	1000000
7	2	6	828420	63	1457	0	169997	1000000
8	2	8	25707	78	1570	0	972567	1000000
9	1	16	557911	80	0	0	442009	1000000
10	3	12	637591	89	919	1518	359705	1000000
11	1	14	88482	83	0	0	911435	1000000
12	1	17	709904	74	0	0	290022	1000000

Type 5 #17 5494.80 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	12	760239	87	1604	0	737983	1500000
2	1	16	1130965	50	0	0	368985	1500000
3	3	12	1078604	60	1086	1616	418514	1500000
4	2	20	970946	84	1470	0	527416	1500000
5	3	13	965612	79	1505	1466	531180	1500000
6	3	5	1088936	84	1338	1261	408213	1500000
7	3	6	1351837	58	1230	1529	145230	1500000
8	1	20	58347	74	0	0	1441579	1500000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	7	25680	70	0	0	680132	705882
2	3	16	180470	94	1322	1435	522373	705882
3	1	20	145119	57	0	0	560706	705882
4	3	18	517124	57	1304	1280	186003	705882
5	1	12	465106	70	0	0	240706	705882
6	3	11	524581	78	1725	1701	177641	705882
7	1	18	616732	85	0	0	89065	705882
8	1	11	429662	59	0	0	276161	705882
9	3	9	330795	91	915	1726	372173	705882
10	3	7	532817	51	1032	1656	170224	705882
11	2	14	266790	56	1247	0	437733	705882
12	3	12	304350	96	966	1325	398953	705882
13	3	17	206204	82	1101	1285	497046	705882
14	1	16	523008	97	0	0	182777	705882
15	1	13	302427	82	0	0	403373	705882
16	1	5	622309	80	0	0	83493	705882
17	3	10	282370	71	1024	950	421325	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	12	254638	78	0	0	345284	600000
2	1	13	183613	97	0	0	416290	600000
3	2	10	171962	70	964	0	426934	600000
4	2	6	8258	87	1065	0	590503	600000
5	1	12	53526	54	0	0	546420	600000
6	3	9	67155	52	1854	1549	529286	600000
7	1	17	369147	54	0	0	230799	600000
8	2	9	350855	61	1681	0	247342	600000
9	2	18	196009	71	1637	0	402212	600000
10	1	20	333259	50	0	0	266691	600000
11	3	8	48611	74	1269	1122	548776	600000
12	1	12	593375	65	0	0	6560	600000
13	3	7	258972	72	1291	1249	338272	600000
14	1	14	452836	64	0	0	147100	600000
15	2	6	289962	52	1938	0	307996	600000
16	2	8	94362	80	1305	0	504173	600000
17	3	6	76844	93	1612	1089	520176	600000
18	3	19	42776	83	1638	1528	553809	600000
19	3	6	36240	65	1080	1277	561208	600000
20	2	5	246228	63	1794	0	351852	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	10	659001	83	1147	1775	537828	1200000
2	2	19	59735	91	1220	0	1138863	1200000
3	3	12	647008	67	1114	1125	550552	1200000
4	2	19	697664	70	1074	0	501122	1200000
5	1	19	407926	91	0	0	791983	1200000
6	1	16	133282	76	0	0	1066642	1200000
7	1	12	1077968	54	0	0	121978	1200000
8	3	17	403193	76	1588	1731	793260	1200000
9	1	7	538507	91	0	0	661402	1200000
10	1	17	1059702	62	0	0	140236	1200000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	11	285081	87	0	0	346410	631578
2	2	10	333930	52	1316	0	296228	631578
3	1	8	607938	76	0	0	23564	631578
4	1	7	610976	91	0	0	20511	631578
5	2	15	261300	72	1594	0	368540	631578
6	3	6	273091	92	1565	1247	355399	631578
7	3	15	408527	79	1459	1341	220014	631578
8	2	16	578830	69	1562	0	51048	631578
9	3	7	181647	74	1174	1285	447250	631578
10	1	16	211108	63	0	0	420407	631578
11	1	18	225629	64	0	0	405885	631578
12	1	19	541031	60	0	0	90487	631578
13	2	18	557561	69	1648	0	72231	631578
14	2	14	520433	98	1882	0	109067	631578
15	1	11	283196	86	0	0	348296	631578
16	2	14	326326	73	1100	0	304006	631578
17	1	13	617991	76	0	0	13511	631578
18	2	6	181535	82	1501	0	448378	631578
19	3	8	327413	59	1377	1446	301165	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	7	717514	52	0	0	482434	1200000
2	2	16	315400	64	1245	0	883227	1200000
3	3	19	489046	100	1718	1846	707090	1200000
4	3	16	34053	52	1671	1287	1162833	1200000
5	2	6	1121574	74	1711	0	76567	1200000
6	3	17	247073	91	1543	1786	949325	1200000
7	3	6	688170	64	1343	1413	508882	1200000
8	3	17	522871	94	1135	1622	674090	1200000
9	2	17	487098	60	1282	0	711500	1200000
10	2	16	218231	57	1725	0	979930	1200000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	5	821676	79	1734	1614	508072	1333333
2	3	15	1309131	76	1001	1704	21269	1333333
3	2	5	638410	93	1184	0	693553	1333333
4	3	13	54172	93	1706	1596	1275580	1333333
5	2	7	534417	79	1250	0	797508	1333333
6	2	7	975648	75	1350	0	356185	1333333
7	1	18	568912	62	0	0	764359	1333333
8	3	9	113992	59	1795	1661	1215708	1333333
9	2	8	645990	94	1135	0	686020	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	19	864617	83	0	0	58376	923076
2	2	7	582101	67	1465	0	339376	923076
3	1	9	486480	76	0	0	436520	923076
4	1	20	327624	56	0	0	595396	923076
5	1	14	155137	70	0	0	767869	923076
6	3	14	72564	86	1499	1617	847138	923076
7	2	13	868347	84	1282	0	53279	923076
8	3	8	448860	100	1735	1101	471080	923076
9	1	6	278136	90	0	0	644850	923076
10	3	15	536195	77	1894	1250	383506	923076
11	3	13	802373	71	1896	1765	116829	923076
12	1	20	297846	65	0	0	625165	923076
13	2	9	784073	97	1455	0	137354	923076

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	12	400474	79	1451	1834	929337	1333333
2	3	7	1152866	94	1496	1428	177261	1333333
3	1	19	818596	59	0	0	514678	1333333
4	2	15	28544	75	1189	0	1303450	1333333
5	2	20	1233194	55	1706	0	98323	1333333
6	3	7	717144	94	1090	1448	613369	1333333
7	2	15	699989	86	1008	0	632164	1333333
8	3	15	1092816	84	1592	1570	237103	1333333
9	1	10	323291	67	0	0	1009975	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	13	632612	87	1678	0	71418	705882
2	2	12	334333	53	1420	0	370023	705882
3	3	11	673914	100	1762	1631	28275	705882
4	1	11	246779	100	0	0	459003	705882
5	2	6	581284	92	1488	0	122926	705882
6	1	10	408151	80	0	0	297651	705882
7	3	11	346805	81	1603	1052	356179	705882
8	2	17	608418	82	1559	0	95741	705882
9	2	14	18515	60	990	0	686257	705882
10	3	18	138566	62	1862	1800	563468	705882
11	2	19	382258	98	1145	0	322283	705882
12	2	20	702515	99	1796	0	1373	705882
13	3	14	212683	95	1761	1284	489869	705882
14	1	10	226833	68	0	0	478981	705882
15	1	13	502013	67	0	0	203802	705882
16	1	5	390775	61	0	0	315046	705882
17	1	17	313295	88	0	0	392499	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	11	627295	62	1729	0	76734	705882
2	3	15	608104	88	1750	1658	94106	705882
3	3	5	268054	66	1129	1581	434920	705882
4	3	14	18707	72	1469	1855	683635	705882
5	2	19	430885	59	1262	0	273617	705882
6	2	7	180725	90	1134	0	523843	705882
7	1	14	665074	98	0	0	40710	705882
8	2	11	457298	69	1515	0	246931	705882
9	2	15	695484	80	1694	0	8544	705882
10	1	19	536461	92	0	0	169329	705882
11	3	18	157515	66	1109	1672	545388	705882
12	1	20	444552	81	0	0	261249	705882
13	1	5	434283	63	0	0	271536	705882
14	2	7	416624	84	978	0	288112	705882
15	3	14	627220	94	933	912	76535	705882
16	2	16	666310	71	1337	0	38093	705882
17	1	13	26872	89	0	0	678921	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	20	903821	70	1140	1310	93519	1000000
2	3	17	392211	71	1375	1319	604882	1000000
3	3	6	250166	52	1784	1097	746797	1000000
4	1	8	300306	95	0	0	699599	1000000
5	3	8	200308	64	1730	1257	796513	1000000
6	1	10	753455	76	0	0	246469	1000000
7	1	16	278267	64	0	0	721669	1000000
8	1	8	798146	93	0	0	201761	1000000
9	3	8	100164	57	1503	1444	896718	1000000
10	2	10	958252	84	1026	0	40554	1000000
11	2	7	594736	65	1045	0	404089	1000000
12	2	20	583957	86	1501	0	414370	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	275946	63	1574	0	428236	705882
2	3	18	28188	65	1611	1232	674656	705882
3	2	6	201714	97	963	0	503011	705882
4	3	10	632610	57	1594	1828	69679	705882
5	2	12	123064	93	1761	0	580871	705882
6	1	12	624940	86	0	0	80856	705882
7	2	9	684979	60	1677	0	19106	705882
8	2	16	262083	94	1659	0	441952	705882
9	2	15	633323	72	1406	0	71009	705882
10	1	13	190925	52	0	0	514905	705882
11	3	8	361715	92	1843	1726	340322	705882
12	3	7	103611	61	1477	1460	599151	705882
13	1	11	293494	61	0	0	412327	705882
14	1	10	61749	83	0	0	644050	705882
15	3	11	267981	96	1496	1182	434935	705882
16	2	10	443994	95	1456	0	260242	705882
17	1	12	370943	81	0	0	334858	705882

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Type 6 #1 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5279	#02-5431	#03-5382	#04-5462	#05-5354	#06-5376	#07-5369	#08-5572	#09-5331	#10-5359
#11-5356	#12-5445	#13-5349	#14-5368	#15-5586	#16-5518	#17-5587	#18-5471	#19-5253	#20-5434
#21-5558	#22-5561	#23-5457	#24-5273	#25-5632	#26-5657	#27-5551	#28-5680	#29-5502	#30-5554
#31-5582	#32-5416	#33-5265	#34-5683	#35-5350	#36-5302	#37-5639	#38-5512	#39-5364	#40-5375
#41-5421	#42-5275	#43-5710	#44-5371	#45-5396	#46-5650	#47-5281	#48-5450	#49-5329	#50-5718
#51-5496	#52-5569	#53-5597	#54-5546	#55-5255	#56-5468	#57-5436	#58-5270	#59-5579	#60-5615
#61-5492	#62-5677	#63-5263	#64-5628	#65-5418	#66-5534	#67-5547	#68-5614	#69-5309	#70-5387
#71-5535	#72-5626	#73-5324	#74-5511	#75-5649	#76-5708	#77-5422	#78-5335	#79-5571	#80-5393
#81-5386	#82-5344	#83-5695	#84-5420	#85-5325	#86-5343	#87-5250	#88-5495	#89-5604	#90-5606
#91-5271	#92-5641	#93-5506	#94-5284	#95-5607	#96-5509	#97-5459	#98-5260	#99-5430	#100-5394

Type 6 #2 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5650	#02-5368	#03-5450	#04-5666	#05-5406	#06-5304	#07-5355	#08-5595	#09-5491	#10-5323
#11-5563	#12-5377	#13-5607	#14-5520	#15-5309	#16-5617	#17-5364	#18-5376	#19-5271	#20-5442
#21-5379	#22-5604	#23-5311	#24-5317	#25-5640	#26-5526	#27-5453	#28-5312	#29-5658	#30-5560
#31-5515	#32-5275	#33-5400	#34-5699	#35-5524	#36-5553	#37-5264	#38-5290	#39-5448	#40-5501
#41-5511	#42-5505	#43-5514	#44-5327	#45-5401	#46-5336	#47-5567	#48-5621	#49-5382	#50-5408
#51-5676	#52-5489	#53-5388	#54-5599	#55-5490	#56-5502	#57-5677	#58-5293	#59-5662	#60-5365
#61-5488	#62-5298	#63-5351	#64-5456	#65-5545	#66-5509	#67-5313	#68-5349	#69-5548	#70-5592
#71-5522	#72-5714	#73-5375	#74-5366	#75-5587	#76-5340	#77-5480	#78-5427	#79-5356	#80-5324
#81-5605	#82-5460	#83-5386	#84-5679	#85-5499	#86-5512	#87-5495	#88-5457	#89-5574	#90-5390
#91-5279	#92-5278	#93-5669	#94-5516	#95-5665	#96-5504	#97-5521	#98-5296	#99-5585	#100-5259

Type 6 #3 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5653	#02-5389	#03-5590	#04-5609	#05-5704	#06-5377	#07-5561	#08-5431	#09-5571	#10-5310
#11-5666	#12-5277	#13-5576	#14-5334	#15-5373	#16-5359	#17-5575	#18-5548	#19-5303	#20-5459
#21-5268	#22-5684	#23-5497	#24-5685	#25-5483	#26-5430	#27-5646	#28-5683	#29-5381	#30-5496
#31-5314	#32-5676	#33-5321	#34-5521	#35-5319	#36-5520	#37-5385	#38-5659	#39-5276	#40-5252
#41-5505	#42-5689	#43-5338	#44-5251	#45-5343	#46-5432	#47-5541	#48-5394	#49-5671	#50-5472
#51-5532	#52-5525	#53-5635	#54-5649	#55-5471	#56-5711	#57-5509	#58-5260	#59-5651	#60-5654
#61-5419	#62-5687	#63-5624	#64-5263	#65-5577	#66-5289	#67-5305	#68-5413	#69-5369	#70-5265
#71-5429	#72-5597	#73-5482	#74-5337	#75-5393	#76-5354	#77-5416	#78-5262	#79-5633	#80-5513
#81-5291	#82-5615	#83-5427	#84-5395	#85-5299	#86-5438	#87-5672	#88-5492	#89-5717	#90-5579
#91-5284	#92-5643	#93-5288	#94-5443	#95-5418	#96-5355	#97-5616	#98-5309	#99-5619	#100-5535

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Type 6 #4 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5302	#02-5713	#03-5584	#04-5568	#05-5404	#06-5638	#07-5271	#08-5454	#09-5424	#10-5583
#11-5373	#12-5399	#13-5619	#14-5255	#15-5699	#16-5421	#17-5664	#18-5273	#19-5575	#20-5497
#21-5678	#22-5443	#23-5390	#24-5311	#25-5371	#26-5573	#27-5526	#28-5419	#29-5397	#30-5613
#31-5616	#32-5343	#33-5310	#34-5579	#35-5354	#36-5338	#37-5665	#38-5263	#39-5439	#40-5588
#41-5295	#42-5539	#43-5460	#44-5610	#45-5335	#46-5716	#47-5596	#48-5401	#49-5288	#50-5349
#51-5519	#52-5689	#53-5593	#54-5506	#55-5517	#56-5423	#57-5653	#58-5254	#59-5436	#60-5484
#61-5507	#62-5670	#63-5369	#64-5316	#65-5576	#66-5598	#67-5634	#68-5488	#69-5284	#70-5654
#71-5485	#72-5487	#73-5534	#74-5265	#75-5525	#76-5462	#77-5578	#78-5718	#79-5515	#80-5614
#81-5324	#82-5617	#83-5398	#84-5565	#85-5511	#86-5536	#87-5282	#88-5659	#89-5691	#90-5650
#91-5552	#92-5722	#93-5491	#94-5529	#95-5585	#96-5655	#97-5413	#98-5281	#99-5660	#100-5368

Type 6 #5 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5713	#02-5635	#03-5271	#04-5654	#05-5532	#06-5405	#07-5479	#08-5555	#09-5501	#10-5705
#11-5486	#12-5644	#13-5702	#14-5720	#15-5611	#16-5368	#17-5543	#18-5641	#19-5546	#20-5521
#21-5609	#22-5438	#23-5528	#24-5695	#25-5298	#26-5383	#27-5575	#28-5684	#29-5687	#30-5366
#31-5629	#32-5392	#33-5596	#34-5488	#35-5514	#36-5352	#37-5377	#38-5509	#39-5461	#40-5344
#41-5301	#42-5266	#43-5255	#44-5610	#45-5607	#46-5669	#47-5294	#48-5595	#49-5263	#50-5459
#51-5388	#52-5483	#53-5525	#54-5357	#55-5300	#56-5605	#57-5398	#58-5520	#59-5259	#60-5590
#61-5268	#62-5369	#63-5264	#64-5559	#65-5373	#66-5578	#67-5440	#68-5287	#69-5310	#70-5387
#71-5511	#72-5690	#73-5413	#74-5500	#75-5630	#76-5640	#77-5250	#78-5290	#79-5673	#80-5632
#81-5490	#82-5634	#83-5321	#84-5381	#85-5463	#86-5472	#87-5703	#88-5678	#89-5665	#90-5335
#91-5435	#92-5723	#93-5545	#94-5646	#95-5692	#96-5474	#97-5422	#98-5328	#99-5694	#100-5570

Type 6 #6 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5335	#02-5441	#03-5623	#04-5649	#05-5605	#06-5259	#07-5550	#08-5319	#09-5462	#10-5499
#11-5650	#12-5302	#13-5716	#14-5365	#15-5693	#16-5535	#17-5333	#18-5369	#19-5428	#20-5676
#21-5513	#22-5329	#23-5542	#24-5452	#25-5334	#26-5719	#27-5282	#28-5610	#29-5448	#30-5459
#31-5412	#32-5664	#33-5658	#34-5377	#35-5280	#36-5279	#37-5310	#38-5326	#39-5609	#40-5653
#41-5398	#42-5346	#43-5372	#44-5493	#45-5654	#46-5577	#47-5436	#48-5663	#49-5339	#50-5683
#51-5515	#52-5306	#53-5255	#54-5421	#55-5565	#56-5701	#57-5665	#58-5595	#59-5253	#60-5337
#61-5710	#62-5431	#63-5712	#64-5662	#65-5456	#66-5303	#67-5309	#68-5352	#69-5317	#70-5584
#71-5656	#72-5446	#73-5566	#74-5315	#75-5429	#76-5423	#77-5509	#78-5453	#79-5399	#80-5472
#81-5478	#82-5381	#83-5633	#84-5439	#85-5424	#86-5349	#87-5669	#88-5308	#89-5395	#90-5386
#91-5374	#92-5590	#93-5457	#94-5285	#95-5624	#96-5413	#97-5368	#98-5447	#99-5324	#100-5427

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Type 6 #7 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5341	#02-5723	#03-5545	#04-5522	#05-5491	#06-5335	#07-5608	#08-5561	#09-5622	#10-5677
#11-5589	#12-5530	#13-5547	#14-5609	#15-5252	#16-5373	#17-5526	#18-5511	#19-5436	#20-5667
#21-5441	#22-5567	#23-5563	#24-5649	#25-5302	#26-5334	#27-5554	#28-5710	#29-5353	#30-5281
#31-5297	#32-5679	#33-5541	#34-5440	#35-5604	#36-5552	#37-5427	#38-5697	#39-5376	#40-5550
#41-5477	#42-5520	#43-5250	#44-5693	#45-5635	#46-5420	#47-5264	#48-5411	#49-5720	#50-5646
#51-5537	#52-5715	#53-5399	#54-5531	#55-5703	#56-5683	#57-5283	#58-5523	#59-5304	#60-5576
#61-5518	#62-5542	#63-5256	#64-5255	#65-5424	#66-5670	#67-5724	#68-5310	#69-5367	#70-5689
#71-5296	#72-5680	#73-5392	#74-5638	#75-5539	#76-5549	#77-5357	#78-5360	#79-5485	#80-5688
#81-5633	#82-5625	#83-5594	#84-5585	#85-5663	#86-5713	#87-5321	#88-5698	#89-5599	#90-5433
#91-5366	#92-5628	#93-5271	#94-5259	#95-5711	#96-5300	#97-5538	#98-5654	#99-5656	#100-5370

Type 6 #8 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5611	#02-5616	#03-5609	#04-5489	#05-5277	#06-5410	#07-5535	#08-5306	#09-5613	#10-5589
#11-5490	#12-5354	#13-5555	#14-5335	#15-5261	#16-5714	#17-5393	#18-5256	#19-5422	#20-5379
#21-5564	#22-5488	#23-5617	#24-5530	#25-5562	#26-5307	#27-5268	#28-5671	#29-5283	#30-5360
#31-5316	#32-5694	#33-5474	#34-5698	#35-5296	#36-5353	#37-5556	#38-5522	#39-5313	#40-5376
#41-5478	#42-5289	#43-5505	#44-5629	#45-5406	#46-5689	#47-5450	#48-5527	#49-5665	#50-5560
#51-5483	#52-5715	#53-5297	#54-5378	#55-5717	#56-5684	#57-5440	#58-5517	#59-5579	#60-5424
#61-5384	#62-5331	#63-5362	#64-5569	#65-5632	#66-5407	#67-5447	#68-5459	#69-5359	#70-5253
#71-5448	#72-5361	#73-5625	#74-5405	#75-5342	#76-5542	#77-5394	#78-5343	#79-5472	#80-5481
#81-5461	#82-5650	#83-5642	#84-5596	#85-5418	#86-5521	#87-5266	#88-5624	#89-5536	#90-5495
#91-5324	#92-5577	#93-5606	#94-5620	#95-5508	#96-5415	#97-5351	#98-5374	#99-5712	#100-5687

Type 6 #9 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5655	#02-5605	#03-5309	#04-5284	#05-5260	#06-5699	#07-5691	#08-5486	#09-5256	#10-5668
#11-5648	#12-5572	#13-5436	#14-5651	#15-5521	#16-5535	#17-5690	#18-5290	#19-5562	#20-5712
#21-5637	#22-5280	#23-5379	#24-5330	#25-5489	#26-5661	#27-5498	#28-5559	#29-5306	#30-5336
#31-5496	#32-5688	#33-5480	#34-5536	#35-5447	#36-5408	#37-5546	#38-5299	#39-5387	#40-5529
#41-5388	#42-5571	#43-5477	#44-5391	#45-5679	#46-5349	#47-5697	#48-5450	#49-5311	#50-5250
#51-5501	#52-5267	#53-5575	#54-5678	#55-5287	#56-5442	#57-5675	#58-5538	#59-5561	#60-5325
#61-5473	#62-5664	#63-5723	#64-5493	#65-5607	#66-5266	#67-5662	#68-5298	#69-5357	#70-5616
#71-5532	#72-5578	#73-5348	#74-5707	#75-5399	#76-5587	#77-5581	#78-5318	#79-5525	#80-5695
#81-5629	#82-5606	#83-5494	#84-5636	#85-5509	#86-5582	#87-5461	#88-5579	#89-5574	#90-5259
#91-5401	#92-5642	#93-5265	#94-5308	#95-5698	#96-5681	#97-5428	#98-5520	#99-5312	#100-5452

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Type 6 #10 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5634	#02-5683	#03-5372	#04-5349	#05-5397	#06-5305	#07-5292	#08-5314	#09-5344	#10-5469
#11-5286	#12-5554	#13-5694	#14-5385	#15-5366	#16-5724	#17-5695	#18-5481	#19-5329	#20-5562
#21-5503	#22-5523	#23-5426	#24-5430	#25-5692	#26-5341	#27-5613	#28-5624	#29-5614	#30-5254
#31-5433	#32-5708	#33-5310	#34-5671	#35-5484	#36-5394	#37-5489	#38-5454	#39-5539	#40-5396
#41-5485	#42-5354	#43-5698	#44-5572	#45-5606	#46-5296	#47-5647	#48-5582	#49-5682	#50-5458
#51-5288	#52-5707	#53-5615	#54-5381	#55-5641	#56-5574	#57-5337	#58-5676	#59-5444	#60-5579
#61-5281	#62-5370	#63-5302	#64-5633	#65-5439	#66-5456	#67-5277	#68-5515	#69-5415	#70-5268
#71-5662	#72-5549	#73-5645	#74-5418	#75-5666	#76-5406	#77-5691	#78-5450	#79-5342	#80-5653
#81-5279	#82-5635	#83-5471	#84-5521	#85-5588	#86-5290	#87-5499	#88-5452	#89-5553	#90-5387
#91-5700	#92-5352	#93-5252	#94-5260	#95-5442	#96-5363	#97-5703	#98-5274	#99-5318	#100-5392

Type 6 #11 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5417	#02-5507	#03-5395	#04-5502	#05-5423	#06-5315	#07-5644	#08-5684	#09-5704	#10-5409
#11-5696	#12-5358	#13-5659	#14-5636	#15-5651	#16-5444	#17-5702	#18-5412	#19-5607	#20-5376
#21-5721	#22-5508	#23-5685	#24-5305	#25-5564	#26-5403	#27-5680	#28-5258	#29-5617	#30-5540
#31-5300	#32-5611	#33-5402	#34-5378	#35-5674	#36-5330	#37-5550	#38-5512	#39-5326	#40-5601
#41-5533	#42-5593	#43-5407	#44-5298	#45-5253	#46-5719	#47-5318	#48-5349	#49-5516	#50-5255
#51-5385	#52-5541	#53-5391	#54-5667	#55-5396	#56-5633	#57-5547	#58-5339	#59-5663	#60-5269
#61-5359	#62-5317	#63-5414	#64-5334	#65-5530	#66-5687	#67-5571	#68-5619	#69-5439	#70-5336
#71-5256	#72-5568	#73-5377	#74-5350	#75-5301	#76-5569	#77-5335	#78-5581	#79-5466	#80-5405
#81-5484	#82-5470	#83-5460	#84-5707	#85-5290	#86-5574	#87-5306	#88-5491	#89-5622	#90-5525
#91-5718	#92-5664	#93-5289	#94-5387	#95-5670	#96-5361	#97-5455	#98-5348	#99-5268	#100-5532

Type 6 #12 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5636	#02-5287	#03-5344	#04-5658	#05-5503	#06-5419	#07-5431	#08-5258	#09-5599	#10-5589
#11-5469	#12-5548	#13-5646	#14-5313	#15-5408	#16-5590	#17-5279	#18-5489	#19-5670	#20-5577
#21-5357	#22-5696	#23-5382	#24-5530	#25-5443	#26-5521	#27-5500	#28-5459	#29-5335	#30-5361
#31-5688	#32-5482	#33-5596	#34-5423	#35-5479	#36-5373	#37-5713	#38-5453	#39-5709	#40-5315
#41-5304	#42-5544	#43-5689	#44-5465	#45-5606	#46-5677	#47-5330	#48-5426	#49-5620	#50-5403
#51-5416	#52-5425	#53-5664	#54-5629	#55-5538	#56-5360	#57-5309	#58-5622	#59-5655	#60-5524
#61-5569	#62-5504	#63-5584	#64-5414	#65-5441	#66-5710	#67-5631	#68-5467	#69-5372	#70-5630
#71-5328	#72-5703	#73-5639	#74-5379	#75-5578	#76-5439	#77-5683	#78-5522	#79-5307	#80-5656
#81-5518	#82-5666	#83-5262	#84-5653	#85-5555	#86-5435	#87-5470	#88-5437	#89-5354	#90-5301
#91-5415	#92-5691	#93-5694	#94-5519	#95-5369	#96-5660	#97-5302	#98-5284	#99-5551	#100-5552

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5501	#02-5330	#03-5707	#04-5357	#05-5395	#06-5716	#07-5315	#08-5398	#09-5312	#10-5356
#11-5509	#12-5442	#13-5419	#14-5618	#15-5571	#16-5636	#17-5318	#18-5662	#19-5409	#20-5528
#21-5523	#22-5479	#23-5652	#24-5474	#25-5581	#26-5308	#27-5319	#28-5273	#29-5588	#30-5254
#31-5622	#32-5691	#33-5363	#34-5486	#35-5573	#36-5572	#37-5306	#38-5289	#39-5478	#40-5459
#41-5288	#42-5292	#43-5669	#44-5630	#45-5499	#46-5525	#47-5626	#48-5522	#49-5590	#50-5364
#51-5599	#52-5278	#53-5272	#54-5403	#55-5483	#56-5500	#57-5710	#58-5658	#59-5720	#60-5375
#61-5448	#62-5351	#63-5612	#64-5475	#65-5305	#66-5381	#67-5723	#68-5314	#69-5261	#70-5655
#71-5485	#72-5436	#73-5708	#74-5568	#75-5332	#76-5609	#77-5406	#78-5521	#79-5724	#80-5614
#81-5667	#82-5334	#83-5464	#84-5339	#85-5531	#86-5304	#87-5545	#88-5637	#89-5569	#90-5567
#91-5268	#92-5469	#93-5494	#94-5524	#95-5684	#96-5578	#97-5467	#98-5668	#99-5680	#100-5518

Type 6 #14 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5560	#02-5420	#03-5639	#04-5418	#05-5351	#06-5502	#07-5449	#08-5375	#09-5461	#10-5588
#11-5532	#12-5696	#13-5642	#14-5554	#15-5700	#16-5455	#17-5568	#18-5360	#19-5579	#20-5572
#21-5591	#22-5390	#23-5550	#24-5308	#25-5636	#26-5722	#27-5290	#28-5395	#29-5397	#30-5329
#31-5712	#32-5541	#33-5628	#34-5724	#35-5424	#36-5362	#37-5678	#38-5292	#39-5264	#40-5511
#41-5369	#42-5355	#43-5404	#44-5465	#45-5497	#46-5577	#47-5694	#48-5709	#49-5372	#50-5623
#51-5557	#52-5350	#53-5670	#54-5693	#55-5279	#56-5339	#57-5685	#58-5590	#59-5451	#60-5335
#61-5304	#62-5314	#63-5509	#64-5545	#65-5405	#66-5263	#67-5525	#68-5343	#69-5615	#70-5318
#71-5564	#72-5310	#73-5472	#74-5284	#75-5567	#76-5617	#77-5309	#78-5277	#79-5305	#80-5272
#81-5498	#82-5611	#83-5595	#84-5659	#85-5334	#86-5252	#87-5717	#88-5426	#89-5538	#90-5291
#91-5620	#92-5645	#93-5342	#94-5563	#95-5433	#96-5258	#97-5489	#98-5609	#99-5471	#100-5719

Type 6 #15 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5668	#02-5517	#03-5318	#04-5531	#05-5423	#06-5280	#07-5282	#08-5540	#09-5261	#10-5658
#11-5535	#12-5329	#13-5585	#14-5441	#15-5340	#16-5622	#17-5616	#18-5275	#19-5609	#20-5407
#21-5718	#22-5500	#23-5646	#24-5525	#25-5471	#26-5612	#27-5597	#28-5717	#29-5490	#30-5257
#31-5350	#32-5710	#33-5438	#34-5699	#35-5390	#36-5460	#37-5649	#38-5620	#39-5364	#40-5395
#41-5476	#42-5608	#43-5712	#44-5532	#45-5484	#46-5529	#47-5664	#48-5360	#49-5485	#50-5724
#51-5313	#52-5251	#53-5418	#54-5595	#55-5310	#56-5289	#57-5300	#58-5253	#59-5557	#60-5549
#61-5615	#62-5610	#63-5605	#64-5698	#65-5721	#66-5636	#67-5464	#68-5375	#69-5492	#70-5659
#71-5711	#72-5332	#73-5604	#74-5303	#75-5379	#76-5385	#77-5589	#78-5374	#79-5697	#80-5381
#81-5560	#82-5554	#83-5426	#84-5404	#85-5707	#86-5593	#87-5644	#88-5667	#89-5308	#90-5386
#91-5601	#92-5574	#93-5510	#94-5663	#95-5483	#96-5527	#97-5660	#98-5524	#99-5323	#100-5452

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Type 6 #16 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5528	#02-5711	#03-5645	#04-5593	#05-5692	#06-5563	#07-5491	#08-5637	#09-5328	#10-5265
#11-5567	#12-5410	#13-5331	#14-5476	#15-5382	#16-5316	#17-5261	#18-5505	#19-5260	#20-5367
#21-5413	#22-5662	#23-5719	#24-5717	#25-5508	#26-5450	#27-5435	#28-5464	#29-5419	#30-5653
#31-5582	#32-5486	#33-5351	#34-5434	#35-5256	#36-5436	#37-5394	#38-5352	#39-5257	#40-5589
#41-5293	#42-5544	#43-5440	#44-5492	#45-5284	#46-5531	#47-5417	#48-5515	#49-5405	#50-5513
#51-5680	#52-5289	#53-5591	#54-5716	#55-5652	#56-5335	#57-5677	#58-5362	#59-5305	#60-5422
#61-5633	#62-5336	#63-5710	#64-5649	#65-5705	#66-5291	#67-5375	#68-5535	#69-5724	#70-5318
#71-5590	#72-5406	#73-5323	#74-5676	#75-5423	#76-5317	#77-5498	#78-5416	#79-5629	#80-5296
#81-5628	#82-5497	#83-5311	#84-5568	#85-5264	#86-5578	#87-5651	#88-5484	#89-5281	#90-5297
#91-5559	#92-5681	#93-5558	#94-5516	#95-5511	#96-5607	#97-5337	#98-5647	#99-5665	#100-5608

Type 6 #17 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5518	#02-5290	#03-5478	#04-5267	#05-5429	#06-5671	#07-5401	#08-5376	#09-5254	#10-5564
#11-5642	#12-5368	#13-5644	#14-5448	#15-5361	#16-5682	#17-5323	#18-5559	#19-5692	#20-5571
#21-5367	#22-5720	#23-5589	#24-5525	#25-5711	#26-5423	#27-5473	#28-5414	#29-5362	#30-5410
#31-5395	#32-5590	#33-5428	#34-5300	#35-5699	#36-5349	#37-5633	#38-5304	#39-5335	#40-5620
#41-5433	#42-5676	#43-5641	#44-5398	#45-5592	#46-5519	#47-5294	#48-5649	#49-5442	#50-5503
#51-5338	#52-5697	#53-5286	#54-5400	#55-5614	#56-5467	#57-5498	#58-5652	#59-5686	#60-5616
#61-5403	#62-5496	#63-5502	#64-5465	#65-5386	#66-5582	#67-5415	#68-5504	#69-5321	#70-5388
#71-5603	#72-5672	#73-5369	#74-5628	#75-5489	#76-5645	#77-5632	#78-5306	#79-5618	#80-5391
#81-5624	#82-5655	#83-5460	#84-5416	#85-5587	#86-5561	#87-5693	#88-5472	#89-5309	#90-5688
#91-5621	#92-5371	#93-5317	#94-5277	#95-5723	#96-5625	#97-5623	#98-5710	#99-5666	#100-5340

Type 6 #18 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5323	#02-5594	#03-5473	#04-5446	#05-5696	#06-5496	#07-5439	#08-5609	#09-5324	#10-5499
#11-5456	#12-5372	#13-5723	#14-5642	#15-5636	#16-5353	#17-5641	#18-5356	#19-5639	#20-5527
#21-5480	#22-5718	#23-5507	#24-5521	#25-5422	#26-5617	#27-5633	#28-5441	#29-5717	#30-5493
#31-5488	#32-5519	#33-5326	#34-5513	#35-5691	#36-5469	#37-5275	#38-5338	#39-5680	#40-5261
#41-5302	#42-5597	#43-5426	#44-5669	#45-5278	#46-5331	#47-5678	#48-5706	#49-5603	#50-5501
#51-5389	#52-5584	#53-5330	#54-5337	#55-5677	#56-5273	#57-5328	#58-5588	#59-5722	#60-5616
#61-5555	#62-5585	#63-5692	#64-5578	#65-5647	#66-5378	#67-5615	#68-5267	#69-5448	#70-5571
#71-5665	#72-5635	#73-5344	#74-5477	#75-5589	#76-5551	#77-5445	#78-5511	#79-5285	#80-5712
#81-5380	#82-5466	#83-5433	#84-5604	#85-5516	#86-5252	#87-5259	#88-5683	#89-5370	#90-5471
#91-5262	#92-5458	#93-5341	#94-5355	#95-5258	#96-5637	#97-5586	#98-5303	#99-5542	#100-5365

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Type 6 #19 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5389	#02-5427	#03-5582	#04-5520	#05-5464	#06-5286	#07-5483	#08-5420	#09-5293	#10-5549
#11-5705	#12-5448	#13-5431	#14-5670	#15-5315	#16-5343	#17-5613	#18-5258	#19-5594	#20-5349
#21-5443	#22-5622	#23-5611	#24-5385	#25-5598	#26-5480	#27-5533	#28-5423	#29-5659	#30-5562
#31-5351	#32-5426	#33-5658	#34-5456	#35-5541	#36-5449	#37-5674	#38-5428	#39-5437	#40-5478
#41-5618	#42-5649	#43-5257	#44-5667	#45-5543	#46-5452	#47-5578	#48-5433	#49-5654	#50-5266
#51-5529	#52-5696	#53-5413	#54-5253	#55-5597	#56-5376	#57-5295	#58-5610	#59-5329	#60-5626
#61-5409	#62-5407	#63-5462	#64-5302	#65-5414	#66-5399	#67-5265	#68-5435	#69-5382	#70-5492
#71-5559	#72-5590	#73-5538	#74-5715	#75-5692	#76-5570	#77-5475	#78-5633	#79-5334	#80-5347
#81-5687	#82-5320	#83-5540	#84-5378	#85-5445	#86-5312	#87-5555	#88-5311	#89-5432	#90-5569
#91-5355	#92-5303	#93-5384	#94-5365	#95-5380	#96-5489	#97-5591	#98-5655	#99-5563	#100-5395

Type 6 #20 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5547	#02-5440	#03-5621	#04-5630	#05-5530	#06-5544	#07-5701	#08-5719	#09-5529	#10-5716
#11-5447	#12-5336	#13-5646	#14-5649	#15-5693	#16-5337	#17-5434	#18-5374	#19-5674	#20-5483
#21-5714	#22-5485	#23-5484	#24-5581	#25-5455	#26-5344	#27-5393	#28-5468	#29-5417	#30-5528
#31-5373	#32-5427	#33-5394	#34-5555	#35-5255	#36-5415	#37-5650	#38-5505	#39-5613	#40-5281
#41-5574	#42-5551	#43-5312	#44-5661	#45-5684	#46-5444	#47-5521	#48-5503	#49-5470	#50-5384
#51-5405	#52-5680	#53-5290	#54-5708	#55-5325	#56-5449	#57-5558	#58-5501	#59-5361	#60-5437
#61-5323	#62-5633	#63-5687	#64-5647	#65-5508	#66-5593	#67-5311	#68-5452	#69-5390	#70-5658
#71-5422	#72-5644	#73-5260	#74-5614	#75-5597	#76-5689	#77-5671	#78-5559	#79-5293	#80-5492
#81-5300	#82-5667	#83-5430	#84-5413	#85-5448	#86-5439	#87-5599	#88-5588	#89-5350	#90-5657
#91-5265	#92-5379	#93-5507	#94-5371	#95-5270	#96-5314	#97-5560	#98-5686	#99-5536	#100-5414

Type 6 #21 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5602	#02-5563	#03-5590	#04-5512	#05-5577	#06-5636	#07-5522	#08-5565	#09-5412	#10-5623
#11-5254	#12-5316	#13-5468	#14-5548	#15-5306	#16-5318	#17-5502	#18-5288	#19-5357	#20-5709
#21-5459	#22-5658	#23-5361	#24-5698	#25-5363	#26-5517	#27-5253	#28-5647	#29-5366	#30-5487
#31-5511	#32-5275	#33-5721	#34-5274	#35-5435	#36-5404	#37-5508	#38-5309	#39-5371	#40-5662
#41-5653	#42-5673	#43-5635	#44-5684	#45-5315	#46-5358	#47-5720	#48-5307	#49-5648	#50-5428
#51-5430	#52-5393	#53-5630	#54-5478	#55-5539	#56-5464	#57-5369	#58-5518	#59-5643	#60-5296
#61-5492	#62-5530	#63-5443	#64-5551	#65-5281	#66-5451	#67-5639	#68-5719	#69-5365	#70-5298
#71-5587	#72-5433	#73-5452	#74-5558	#75-5663	#76-5538	#77-5519	#78-5564	#79-5332	#80-5569
#81-5368	#82-5681	#83-5294	#84-5528	#85-5515	#86-5615	#87-5607	#88-5410	#89-5441	#90-5382
#91-5283	#92-5632	#93-5331	#94-5313	#95-5532	#96-5380	#97-5568	#98-5596	#99-5625	#100-5295

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Type 6 #22 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5514	#02-5261	#03-5535	#04-5580	#05-5355	#06-5650	#07-5501	#08-5652	#09-5447	#10-5599
#11-5698	#12-5637	#13-5494	#14-5298	#15-5674	#16-5562	#17-5507	#18-5384	#19-5631	#20-5372
#21-5272	#22-5606	#23-5260	#24-5425	#25-5629	#26-5289	#27-5455	#28-5281	#29-5676	#30-5251
#31-5706	#32-5467	#33-5636	#34-5326	#35-5283	#36-5717	#37-5659	#38-5347	#39-5690	#40-5483
#41-5670	#42-5567	#43-5409	#44-5370	#45-5387	#46-5282	#47-5364	#48-5695	#49-5597	#50-5433
#51-5689	#52-5503	#53-5273	#54-5632	#55-5250	#56-5360	#57-5449	#58-5610	#59-5295	#60-5621
#61-5496	#62-5716	#63-5419	#64-5582	#65-5697	#66-5641	#67-5569	#68-5573	#69-5287	#70-5665
#71-5266	#72-5661	#73-5418	#74-5508	#75-5493	#76-5257	#77-5341	#78-5311	#79-5329	#80-5543
#81-5267	#82-5613	#83-5708	#84-5623	#85-5330	#86-5310	#87-5586	#88-5424	#89-5694	#90-5417
#91-5530	#92-5309	#93-5448	#94-5375	#95-5274	#96-5395	#97-5487	#98-5557	#99-5344	#100-5681

Type 6 #23 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5602	#02-5679	#03-5559	#04-5416	#05-5304	#06-5699	#07-5455	#08-5694	#09-5528	#10-5607
#11-5687	#12-5590	#13-5389	#14-5585	#15-5681	#16-5652	#17-5487	#18-5448	#19-5574	#20-5557
#21-5688	#22-5672	#23-5618	#24-5661	#25-5397	#26-5717	#27-5451	#28-5379	#29-5447	#30-5512
#31-5539	#32-5666	#33-5452	#34-5355	#35-5276	#36-5257	#37-5639	#38-5442	#39-5470	#40-5560
#41-5505	#42-5565	#43-5412	#44-5409	#45-5255	#46-5413	#47-5531	#48-5556	#49-5458	#50-5358
#51-5494	#52-5718	#53-5655	#54-5310	#55-5623	#56-5362	#57-5632	#58-5707	#59-5253	#60-5331
#61-5406	#62-5425	#63-5300	#64-5382	#65-5575	#66-5625	#67-5480	#68-5533	#69-5336	#70-5377
#71-5302	#72-5498	#73-5620	#74-5391	#75-5553	#76-5645	#77-5547	#78-5714	#79-5342	#80-5267
#81-5673	#82-5522	#83-5294	#84-5378	#85-5460	#86-5467	#87-5719	#88-5424	#89-5408	#90-5712
#91-5281	#92-5680	#93-5703	#94-5549	#95-5499	#96-5488	#97-5258	#98-5374	#99-5466	#100-5490

Type 6 #24 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5403	#02-5332	#03-5267	#04-5341	#05-5314	#06-5407	#07-5346	#08-5498	#09-5584	#10-5530
#11-5497	#12-5585	#13-5525	#14-5647	#15-5594	#16-5383	#17-5717	#18-5619	#19-5511	#20-5583
#21-5522	#22-5690	#23-5617	#24-5261	#25-5517	#26-5629	#27-5429	#28-5333	#29-5284	#30-5286
#31-5253	#32-5492	#33-5307	#34-5384	#35-5701	#36-5344	#37-5554	#38-5262	#39-5421	#40-5400
#41-5367	#42-5274	#43-5440	#44-5630	#45-5456	#46-5496	#47-5363	#48-5587	#49-5680	#50-5631
#51-5605	#52-5375	#53-5330	#54-5521	#55-5502	#56-5641	#57-5415	#58-5550	#59-5493	#60-5432
#61-5282	#62-5589	#63-5459	#64-5406	#65-5634	#66-5524	#67-5682	#68-5549	#69-5350	#70-5540
#71-5618	#72-5438	#73-5601	#74-5512	#75-5648	#76-5390	#77-5447	#78-5586	#79-5426	#80-5576
#81-5252	#82-5547	#83-5302	#84-5345	#85-5593	#86-5595	#87-5638	#88-5660	#89-5716	#90-5575
#91-5420	#92-5300	#93-5563	#94-5431	#95-5331	#96-5504	#97-5552	#98-5640	#99-5436	#100-5278



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Type 6 #25 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5313	#02-5367	#03-5538	#04-5288	#05-5570	#06-5353	#07-5709	#08-5421	#09-5413	#10-5442
#11-5555	#12-5631	#13-5702	#14-5630	#15-5403	#16-5680	#17-5480	#18-5633	#19-5545	#20-5682
#21-5501	#22-5588	#23-5551	#24-5650	#25-5334	#26-5485	#27-5266	#28-5504	#29-5646	#30-5440
#31-5660	#32-5541	#33-5519	#34-5713	#35-5703	#36-5305	#37-5557	#38-5311	#39-5535	#40-5676
#41-5544	#42-5412	#43-5470	#44-5586	#45-5250	#46-5278	#47-5375	#48-5274	#49-5643	#50-5345
#51-5478	#52-5450	#53-5264	#54-5711	#55-5362	#56-5593	#57-5692	#58-5641	#59-5491	#60-5252
#61-5619	#62-5340	#63-5432	#64-5424	#65-5625	#66-5648	#67-5572	#68-5259	#69-5256	#70-5425
#71-5331	#72-5694	#73-5472	#74-5484	#75-5379	#76-5622	#77-5522	#78-5565	#79-5312	#80-5268
#81-5512	#82-5689	#83-5319	#84-5444	#85-5550	#86-5667	#87-5708	#88-5628	#89-5645	#90-5700
#91-5575	#92-5590	#93-5333	#94-5578	#95-5475	#96-5351	#97-5320	#98-5335	#99-5275	#100-5613

Type 6 #26 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5629	#02-5393	#03-5263	#04-5358	#05-5704	#06-5512	#07-5594	#08-5455	#09-5304	#10-5278
#11-5414	#12-5378	#13-5460	#14-5555	#15-5453	#16-5272	#17-5317	#18-5303	#19-5504	#20-5399
#21-5480	#22-5353	#23-5318	#24-5400	#25-5384	#26-5628	#27-5521	#28-5451	#29-5479	#30-5564
#31-5448	#32-5487	#33-5325	#34-5300	#35-5537	#36-5558	#37-5254	#38-5366	#39-5301	#40-5495
#41-5562	#42-5714	#43-5679	#44-5367	#45-5644	#46-5622	#47-5297	#48-5267	#49-5450	#50-5490
#51-5464	#52-5398	#53-5289	#54-5669	#55-5683	#56-5570	#57-5608	#58-5322	#59-5253	#60-5549
#61-5439	#62-5690	#63-5616	#64-5385	#65-5391	#66-5403	#67-5483	#68-5662	#69-5452	#70-5684
#71-5516	#72-5329	#73-5445	#74-5266	#75-5708	#76-5624	#77-5462	#78-5363	#79-5717	#80-5586
#81-5265	#82-5260	#83-5592	#84-5600	#85-5409	#86-5482	#87-5492	#88-5697	#89-5373	#90-5273
#91-5313	#92-5707	#93-5503	#94-5468	#95-5509	#96-5433	#97-5553	#98-5292	#99-5560	#100-5498

Type 6 #27 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5589	#02-5487	#03-5553	#04-5625	#05-5423	#06-5574	#07-5337	#08-5325	#09-5257	#10-5624
#11-5523	#12-5376	#13-5392	#14-5592	#15-5608	#16-5583	#17-5430	#18-5473	#19-5386	#20-5711
#21-5393	#22-5305	#23-5381	#24-5283	#25-5455	#26-5405	#27-5566	#28-5677	#29-5655	#30-5380
#31-5674	#32-5276	#33-5550	#34-5253	#35-5362	#36-5580	#37-5582	#38-5530	#39-5642	#40-5610
#41-5297	#42-5266	#43-5414	#44-5434	#45-5377	#46-5326	#47-5694	#48-5372	#49-5543	#50-5452
#51-5355	#52-5533	#53-5356	#54-5520	#55-5419	#56-5268	#57-5258	#58-5384	#59-5395	#60-5602
#61-5497	#62-5630	#63-5496	#64-5573	#65-5668	#66-5469	#67-5351	#68-5345	#69-5289	#70-5692
#71-5327	#72-5328	#73-5597	#74-5302	#75-5330	#76-5577	#77-5347	#78-5444	#79-5256	#80-5310
#81-5412	#82-5511	#83-5634	#84-5476	#85-5626	#86-5389	#87-5464	#88-5661	#89-5551	#90-5421
#91-5378	#92-5571	#93-5524	#94-5600	#95-5679	#96-5259	#97-5493	#98-5388	#99-5671	#100-5342

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5664	#02-5385	#03-5331	#04-5314	#05-5594	#06-5544	#07-5645	#08-5452	#09-5498	#10-5394
#11-5490	#12-5668	#13-5411	#14-5406	#15-5560	#16-5600	#17-5443	#18-5625	#19-5477	#20-5637
#21-5501	#22-5632	#23-5492	#24-5648	#25-5484	#26-5458	#27-5504	#28-5622	#29-5720	#30-5372
#31-5676	#32-5592	#33-5364	#34-5320	#35-5571	#36-5562	#37-5519	#38-5266	#39-5348	#40-5647
#41-5685	#42-5613	#43-5628	#44-5362	#45-5444	#46-5369	#47-5476	#48-5541	#49-5593	#50-5635
#51-5283	#52-5565	#53-5282	#54-5618	#55-5407	#56-5555	#57-5386	#58-5289	#59-5272	#60-5456
#61-5376	#62-5553	#63-5341	#64-5559	#65-5311	#66-5455	#67-5606	#68-5356	#69-5557	#70-5620
#71-5402	#72-5709	#73-5531	#74-5285	#75-5581	#76-5345	#77-5310	#78-5503	#79-5494	#80-5556
#81-5333	#82-5682	#83-5330	#84-5479	#85-5539	#86-5605	#87-5711	#88-5256	#89-5383	#90-5719
#91-5617	#92-5521	#93-5715	#94-5324	#95-5271	#96-5609	#97-5307	#98-5659	#99-5486	#100-5327

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5388	#02-5413	#03-5297	#04-5336	#05-5372	#06-5699	#07-5290	#08-5704	#09-5493	#10-5687
#11-5545	#12-5359	#13-5665	#14-5473	#15-5587	#16-5269	#17-5431	#18-5468	#19-5600	#20-5698
#21-5676	#22-5626	#23-5510	#24-5438	#25-5288	#26-5295	#27-5506	#28-5323	#29-5425	#30-5446
#31-5621	#32-5571	#33-5604	#34-5667	#35-5315	#36-5492	#37-5518	#38-5589	#39-5282	#40-5342
#41-5475	#42-5654	#43-5700	#44-5383	#45-5299	#46-5575	#47-5409	#48-5590	#49-5601	#50-5527
#51-5309	#52-5513	#53-5376	#54-5486	#55-5628	#56-5583	#57-5298	#58-5326	#59-5442	#60-5691
#61-5528	#62-5464	#63-5648	#64-5311	#65-5531	#66-5521	#67-5502	#68-5638	#69-5603	#70-5567
#71-5605	#72-5300	#73-5400	#74-5580	#75-5462	#76-5630	#77-5721	#78-5656	#79-5639	#80-5560
#81-5569	#82-5670	#83-5562	#84-5307	#85-5478	#86-5430	#87-5412	#88-5633	#89-5469	#90-5512
#91-5564	#92-5375	#93-5348	#94-5428	#95-5439	#96-5302	#97-5594	#98-5712	#99-5294	#100-5613

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5337	#02-5688	#03-5648	#04-5466	#05-5632	#06-5325	#07-5336	#08-5297	#09-5370	#10-5393
#11-5330	#12-5511	#13-5302	#14-5693	#15-5452	#16-5519	#17-5455	#18-5558	#19-5350	#20-5359
#21-5594	#22-5418	#23-5341	#24-5252	#25-5479	#26-5676	#27-5697	#28-5390	#29-5410	#30-5285
#31-5258	#32-5611	#33-5276	#34-5473	#35-5606	#36-5271	#37-5345	#38-5399	#39-5402	#40-5344
#41-5364	#42-5512	#43-5326	#44-5431	#45-5303	#46-5323	#47-5380	#48-5700	#49-5645	#50-5690
#51-5389	#52-5403	#53-5669	#54-5503	#55-5467	#56-5520	#57-5557	#58-5463	#59-5373	#60-5685
#61-5357	#62-5322	#63-5625	#64-5469	#65-5571	#66-5497	#67-5715	#68-5305	#69-5406	#70-5256
#71-5720	#72-5332	#73-5634	#74-5674	#75-5546	#76-5721	#77-5444	#78-5621	#79-5579	#80-5667
#81-5255	#82-5439	#83-5607	#84-5278	#85-5705	#86-5457	#87-5552	#88-5694	#89-5296	#90-5635
#91-5378	#92-5398	#93-5334	#94-5722	#95-5663	#96-5508	#97-5385	#98-5428	#99-5514	#100-5551

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	82573	83	0	0	548922	631578
2	1	6	94954	90	0	0	536534	631578
3	3	17	140883	78	1105	1686	487670	631578
4	3	20	66537	95	1090	1028	562638	631578
5	1	18	58146	57	0	0	573375	631578
6	2	20	524935	88	1644	0	104823	631578
7	3	11	321993	94	1300	1352	306651	631578
8	2	11	394690	54	1591	0	235189	631578
9	2	11	2024	74	1361	0	628045	631578
10	2	16	514932	81	1317	0	115167	631578
11	2	5	343498	50	1864	0	286116	631578
12	1	19	293192	90	0	0	338296	631578
13	2	10	91862	94	1223	0	538305	631578
14	3	17	130005	70	1247	1642	498474	631578
15	3	13	534364	80	1417	1534	94023	631578
16	3	6	122412	70	1071	1067	506818	631578
17	2	7	217816	50	1809	0	411853	631578
18	2	11	108539	95	1737	0	521112	631578
19	3	17	163398	65	1066	1095	465824	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	9	134636	87	944	0	570128	705882
2	1	12	394003	98	0	0	311781	705882
3	1	10	276849	85	0	0	428948	705882
4	3	8	211281	66	1604	960	491839	705882
5	3	5	210278	92	1217	1325	492786	705882
6	2	16	517464	81	1155	0	187101	705882
7	2	12	337163	85	1575	0	366974	705882
8	2	7	696533	92	1051	0	8114	705882
9	1	17	127171	69	0	0	578642	705882
10	1	12	237670	52	0	0	468160	705882
11	2	6	606178	55	1049	0	98545	705882
12	1	14	300880	97	0	0	404905	705882
13	3	18	166119	87	1324	1173	537005	705882
14	3	5	250551	91	1802	1642	451614	705882
15	3	13	518671	68	1816	1244	183947	705882
16	2	7	177823	63	1148	0	526785	705882
17	3	6	265906	64	1070	1578	437136	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	19	652684	87	0	0	13895	666666
2	3	10	99407	72	1506	1894	563643	666666
3	3	8	650394	68	1086	1640	13342	666666
4	3	14	370107	87	1133	1461	293704	666666
5	2	9	318886	65	1606	0	346044	666666
6	3	7	291928	56	1046	1125	372399	666666
7	1	20	293804	86	0	0	372776	666666
8	3	6	512592	70	1487	1665	150712	666666
9	1	17	7334	65	0	0	659267	666666
10	1	9	290911	61	0	0	375694	666666
11	2	7	412669	52	1229	0	252664	666666
12	1	15	189790	81	0	0	476795	666666
13	3	12	519213	72	1741	975	144521	666666
14	3	12	485784	51	1662	1488	177579	666666
15	1	15	542472	76	0	0	124118	666666
16	3	5	252980	59	1471	1601	410437	666666
17	2	16	83277	92	1614	0	581591	666666
18	1	6	493008	95	0	0	173563	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	73701	56	0	0	592909	666666
2	1	8	342257	98	0	0	324311	666666
3	3	15	467024	100	1415	1662	196265	666666
4	1	12	311695	77	0	0	354894	666666
5	3	14	378820	53	1098	1572	285017	666666
6	3	6	425533	81	1261	1576	238053	666666
7	1	20	474122	67	0	0	192477	666666
8	2	11	350173	60	1494	0	314879	666666
9	3	12	479096	98	1589	1576	184111	666666
10	1	5	424932	53	0	0	241681	666666
11	2	11	449034	90	1169	0	216283	666666
12	1	12	368113	55	0	0	298498	666666
13	1	18	600388	84	0	0	66194	666666
14	3	18	33184	60	1254	1482	630566	666666
15	1	7	626596	94	0	0	39976	666666
16	3	6	631578	50	1061	1415	32462	666666
17	3	13	51190	83	1000	1622	612605	666666
18	3	6	246242	85	1213	1404	417552	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	18	448075	62	1898	984	254739	705882
2	2	11	13331	91	1505	0	690864	705882
3	3	11	174147	89	1760	1397	528311	705882
4	2	15	495782	55	1493	0	208497	705882
5	2	17	549145	56	1139	0	155486	705882
6	2	8	395408	57	1187	0	309173	705882
7	3	10	36326	58	1647	1026	666709	705882
8	1	20	95222	74	0	0	610586	705882
9	2	13	655474	52	1247	0	49057	705882
10	2	8	521074	50	1788	0	182920	705882
11	2	7	402794	87	1045	0	301869	705882
12	3	18	465090	59	1800	1076	237739	705882
13	1	12	654267	67	0	0	51548	705882
14	2	7	138238	55	1346	0	566188	705882
15	2	15	185893	82	1331	0	518494	705882
16	2	12	87980	80	1185	0	616557	705882
17	2	11	129182	97	1407	0	575099	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	7	291502	59	1292	1815	1038547	1333333
2	2	12	941450	93	1167	0	390530	1333333
3	1	10	737468	68	0	0	595797	1333333
4	3	15	94614	91	1162	1650	1235634	1333333
5	3	20	779543	94	1046	1601	550861	1333333
6	3	16	364726	90	1699	1758	964880	1333333
7	3	19	429106	81	929	968	902087	1333333
8	1	18	1253398	51	0	0	79884	1333333
9	1	13	148146	95	0	0	1185092	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	150441	74	1675	0	447736	600000
2	2	9	99921	52	1269	0	498706	600000
3	1	15	529357	59	0	0	70584	600000
4	1	12	515703	88	0	0	84209	600000
5	3	16	456822	79	1562	1772	139607	600000
6	1	16	153876	100	0	0	446024	600000
7	3	6	377868	94	1525	1490	218835	600000
8	1	14	23832	65	0	0	576103	600000
9	2	16	353529	92	1272	0	245015	600000
10	3	7	453814	92	1543	1047	143320	600000
11	1	5	434912	77	0	0	165011	600000
12	2	19	212879	63	1570	0	385425	600000
13	2	16	269446	63	1736	0	328692	600000
14	2	14	598328	55	1540	0	22	600000
15	3	7	576613	88	1344	1176	20603	600000
16	3	5	105004	66	940	1861	491997	600000
17	2	12	198835	79	1534	0	399473	600000
18	1	5	224707	95	0	0	375198	600000
19	1	8	365749	84	0	0	234167	600000
20	1	20	547924	55	0	0	52021	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	13	16301	62	1573	1356	1313917	1333333
2	1	17	1012553	55	0	0	320725	1333333
3	3	19	338094	97	1530	1332	992086	1333333
4	3	9	95120	57	1781	1067	1235194	1333333
5	3	15	1197666	78	1412	996	133025	1333333
6	3	18	1219151	97	1783	1320	110788	1333333
7	1	15	952735	84	0	0	380514	1333333
8	1	14	309101	74	0	0	1024158	1333333
9	1	10	594795	56	0	0	738482	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	10	411448	91	0	0	588461	1000000
2	3	6	547685	82	927	1591	449551	1000000
3	3	19	277612	50	1889	1094	719255	1000000
4	3	18	363214	95	1417	1869	633215	1000000
5	3	8	267280	81	1901	1737	728839	1000000
6	3	14	138481	91	1130	1088	859028	1000000
7	1	12	523668	54	0	0	476278	1000000
8	3	10	129323	62	1846	1528	867117	1000000
9	2	8	423792	85	1461	0	574577	1000000
10	3	8	386208	71	1425	1864	610290	1000000
11	3	16	823445	53	1156	1930	173310	1000000
12	3	18	827182	55	1931	1720	169002	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	17	397714	53	1263	955	266575	666666
2	1	17	413660	52	0	0	252954	666666
3	3	16	623207	75	1197	1769	40268	666666
4	2	16	499857	66	1178	0	165499	666666
5	2	16	606022	50	1265	0	59279	666666
6	2	17	96206	77	1659	0	568647	666666
7	3	12	93817	94	1542	1269	569756	666666
8	1	19	509242	61	0	0	157363	666666
9	1	12	489582	96	0	0	176988	666666
10	3	13	297591	61	1903	1116	365873	666666
11	2	14	376484	52	986	0	289092	666666
12	1	5	65077	53	0	0	601536	666666
13	1	9	26244	82	0	0	640340	666666
14	2	14	423461	57	1248	0	241843	666666
15	2	9	551143	90	1018	0	114325	666666
16	2	12	1842	71	1498	0	663184	666666
17	2	18	407894	84	1485	0	257119	666666
18	1	17	192607	75	0	0	473984	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	87914	66	0	0	835096	923076
2	1	7	61187	86	0	0	861803	923076
3	3	14	844297	99	989	1830	75663	923076
4	2	7	204111	69	1476	0	717351	923076
5	1	7	439812	81	0	0	483183	923076
6	1	11	308535	70	0	0	614471	923076
7	1	17	908644	83	0	0	14349	923076
8	1	19	523119	67	0	0	399890	923076
9	1	8	906123	87	0	0	16866	923076
10	1	10	525853	68	0	0	397155	923076
11	2	13	863533	70	1679	0	57724	923076
12	1	7	873176	61	0	0	49839	923076
13	2	17	774145	59	1883	0	146930	923076

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	10	69069	85	972	1329	528375	600000
2	3	17	190586	63	964	1288	406973	600000
3	2	14	449414	97	1004	0	149388	600000
4	1	19	399063	78	0	0	200859	600000
5	3	11	360915	84	1899	1334	235600	600000
6	1	7	68759	88	0	0	531153	600000
7	2	16	165081	66	1450	0	433337	600000
8	3	20	85132	65	1389	1548	511736	600000
9	3	14	132112	86	1682	1500	464448	600000
10	2	11	229550	74	1447	0	368855	600000
11	3	18	45092	66	968	1911	551831	600000
12	3	20	544836	76	1441	1528	51967	600000
13	3	19	211651	100	1310	1188	385551	600000
14	2	6	312841	66	1199	0	285828	600000
15	1	17	129023	98	0	0	470879	600000
16	3	15	354598	69	1194	1648	242353	600000
17	1	11	419977	68	0	0	179955	600000
18	1	8	565499	89	0	0	34412	600000
19	3	15	513548	83	1075	1726	83402	600000
20	3	17	585459	84	1010	1045	12234	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	17	835549	85	0	0	364366	1200000
2	1	18	197003	58	0	0	1002939	1200000
3	1	9	1064324	64	0	0	135612	1200000
4	1	15	605407	74	0	0	594519	1200000
5	3	14	192243	52	1181	1332	1005088	1200000
6	2	20	1139187	95	1046	0	59577	1200000
7	2	14	159764	58	1504	0	1038616	1200000
8	3	20	4429	70	1593	1530	1192238	1200000
9	1	10	934090	80	0	0	265830	1200000
10	3	10	449618	69	1202	1421	747552	1200000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	726941	55	0	0	606337	1333333
2	3	6	977885	91	1006	1819	352350	1333333
3	3	11	971468	61	945	1494	359243	1333333
4	1	19	697145	57	0	0	636131	1333333
5	3	16	1159697	96	1795	1885	169668	1333333
6	2	8	918613	67	1460	0	413126	1333333
7	2	9	626117	79	1910	0	705148	1333333
8	2	20	1122454	79	1510	0	209211	1333333
9	2	9	517177	85	1127	0	814859	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	15	340995	63	1186	1058	256572	600000
2	3	9	337500	58	1337	1099	259890	600000
3	3	17	27052	60	1811	1323	569634	600000
4	1	6	10652	82	0	0	589266	600000
5	1	13	95579	61	0	0	504360	600000
6	1	11	128377	84	0	0	471539	600000
7	2	14	498109	84	1845	0	99878	600000
8	1	9	340875	79	0	0	259046	600000
9	1	7	433845	86	0	0	166069	600000
10	1	5	69774	68	0	0	530158	600000
11	2	16	133642	53	1254	0	464998	600000
12	3	18	254818	88	1667	1089	342162	600000
13	3	8	30579	99	1073	1661	566390	600000
14	3	20	413168	74	1872	1298	183440	600000
15	1	12	127220	55	0	0	472725	600000
16	3	9	304472	99	910	1762	292559	600000
17	1	14	426397	98	0	0	173505	600000
18	3	17	46814	60	1785	1036	550185	600000
19	3	13	327685	57	1549	1783	268812	600000
20	2	6	30014	84	1793	0	568025	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	11	241313	69	0	0	958618	1200000
2	3	18	199910	86	1776	1374	996682	1200000
3	2	19	672044	60	1235	0	526601	1200000
4	1	16	865601	57	0	0	334342	1200000
5	1	9	944406	93	0	0	255501	1200000
6	1	18	446731	77	0	0	753192	1200000
7	2	14	1179455	80	1813	0	18572	1200000
8	2	19	363169	94	1142	0	835501	1200000
9	3	5	740679	73	943	1162	456997	1200000
10	3	10	1183142	80	1607	1464	13547	1200000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	7	322105	69	1853	0	675904	1000000
2	3	9	334068	80	1576	1795	662321	1000000
3	2	18	580939	63	1211	0	417724	1000000
4	3	10	437569	52	1272	1694	559309	1000000
5	1	6	612739	84	0	0	387177	1000000
6	3	13	825842	52	1139	1132	171731	1000000
7	2	6	828420	63	1457	0	169997	1000000
8	2	8	25707	78	1570	0	972567	1000000
9	1	16	557911	80	0	0	442009	1000000
10	3	12	637591	89	919	1518	359705	1000000
11	1	14	88482	83	0	0	911435	1000000
12	1	17	709904	74	0	0	290022	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	12	760239	87	1604	0	737983	1500000
2	1	16	1130965	50	0	0	368985	1500000
3	3	12	1078604	60	1086	1616	418514	1500000
4	2	20	970946	84	1470	0	527416	1500000
5	3	13	965612	79	1505	1466	531180	1500000
6	3	5	1088936	84	1338	1261	408213	1500000
7	3	6	1351837	58	1230	1529	145230	1500000
8	1	20	58347	74	0	0	1441579	1500000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	7	25680	70	0	0	680132	705882
2	3	16	180470	94	1322	1435	522373	705882
3	1	20	145119	57	0	0	560706	705882
4	3	18	517124	57	1304	1280	186003	705882
5	1	12	465106	70	0	0	240706	705882
6	3	11	524581	78	1725	1701	177641	705882
7	1	18	616732	85	0	0	89065	705882
8	1	11	429662	59	0	0	276161	705882
9	3	9	330795	91	915	1726	372173	705882
10	3	7	532817	51	1032	1656	170224	705882
11	2	14	266790	56	1247	0	437733	705882
12	3	12	304350	96	966	1325	398953	705882
13	3	17	206204	82	1101	1285	497046	705882
14	1	16	523008	97	0	0	182777	705882
15	1	13	302427	82	0	0	403373	705882
16	1	5	622309	80	0	0	83493	705882
17	3	10	282370	71	1024	950	421325	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	12	254638	78	0	0	345284	600000
2	1	13	183613	97	0	0	416290	600000
3	2	10	171962	70	964	0	426934	600000
4	2	6	8258	87	1065	0	590503	600000
5	1	12	53526	54	0	0	546420	600000
6	3	9	67155	52	1854	1549	529286	600000
7	1	17	369147	54	0	0	230799	600000
8	2	9	350855	61	1681	0	247342	600000
9	2	18	196009	71	1637	0	402212	600000
10	1	20	333259	50	0	0	266691	600000
11	3	8	48611	74	1269	1122	548776	600000
12	1	12	593375	65	0	0	6560	600000
13	3	7	258972	72	1291	1249	338272	600000
14	1	14	452836	64	0	0	147100	600000
15	2	6	289962	52	1938	0	307996	600000
16	2	8	94362	80	1305	0	504173	600000
17	3	6	76844	93	1612	1089	520176	600000
18	3	19	42776	83	1638	1528	553809	600000
19	3	6	36240	65	1080	1277	561208	600000
20	2	5	246228	63	1794	0	351852	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	10	659001	83	1147	1775	537828	1200000
2	2	19	59735	91	1220	0	1138863	1200000
3	3	12	647008	67	1114	1125	550552	1200000
4	2	19	697664	70	1074	0	501122	1200000
5	1	19	407926	91	0	0	791983	1200000
6	1	16	133282	76	0	0	1066642	1200000
7	1	12	1077968	54	0	0	121978	1200000
8	3	17	403193	76	1588	1731	793260	1200000
9	1	7	538507	91	0	0	661402	1200000
10	1	17	1059702	62	0	0	140236	1200000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	11	285081	87	0	0	346410	631578
2	2	10	333930	52	1316	0	296228	631578
3	1	8	607938	76	0	0	23564	631578
4	1	7	610976	91	0	0	20511	631578
5	2	15	261300	72	1594	0	368540	631578
6	3	6	273091	92	1565	1247	355399	631578
7	3	15	408527	79	1459	1341	220014	631578
8	2	16	578830	69	1562	0	51048	631578
9	3	7	181647	74	1174	1285	447250	631578
10	1	16	211108	63	0	0	420407	631578
11	1	18	225629	64	0	0	405885	631578
12	1	19	541031	60	0	0	90487	631578
13	2	18	557561	69	1648	0	72231	631578
14	2	14	520433	98	1882	0	109067	631578
15	1	11	283196	86	0	0	348296	631578
16	2	14	326326	73	1100	0	304006	631578
17	1	13	617991	76	0	0	13511	631578
18	2	6	181535	82	1501	0	448378	631578
19	3	8	327413	59	1377	1446	301165	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	7	717514	52	0	0	482434	1200000
2	2	16	315400	64	1245	0	883227	1200000
3	3	19	489046	100	1718	1846	707090	1200000
4	3	16	34053	52	1671	1287	1162833	1200000
5	2	6	1121574	74	1711	0	76567	1200000
6	3	17	247073	91	1543	1786	949325	1200000
7	3	6	688170	64	1343	1413	508882	1200000
8	3	17	522871	94	1135	1622	674090	1200000
9	2	17	487098	60	1282	0	711500	1200000
10	2	16	218231	57	1725	0	979930	1200000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	5	821676	79	1734	1614	508072	1333333
2	3	15	1309131	76	1001	1704	21269	1333333
3	2	5	638410	93	1184	0	693553	1333333
4	3	13	54172	93	1706	1596	1275580	1333333
5	2	7	534417	79	1250	0	797508	1333333
6	2	7	975648	75	1350	0	356185	1333333
7	1	18	568912	62	0	0	764359	1333333
8	3	9	113992	59	1795	1661	1215708	1333333
9	2	8	645990	94	1135	0	686020	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	19	864617	83	0	0	58376	923076
2	2	7	582101	67	1465	0	339376	923076
3	1	9	486480	76	0	0	436520	923076
4	1	20	327624	56	0	0	595396	923076
5	1	14	155137	70	0	0	767869	923076
6	3	14	72564	86	1499	1617	847138	923076
7	2	13	868347	84	1282	0	53279	923076
8	3	8	448860	100	1735	1101	471080	923076
9	1	6	278136	90	0	0	644850	923076
10	3	15	536195	77	1894	1250	383506	923076
11	3	13	802373	71	1896	1765	116829	923076
12	1	20	297846	65	0	0	625165	923076
13	2	9	784073	97	1455	0	137354	923076

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	12	400474	79	1451	1834	929337	1333333
2	3	7	1152866	94	1496	1428	177261	1333333
3	1	19	818596	59	0	0	514678	1333333
4	2	15	28544	75	1189	0	1303450	1333333
5	2	20	1233194	55	1706	0	98323	1333333
6	3	7	717144	94	1090	1448	613369	1333333
7	2	15	699989	86	1008	0	632164	1333333
8	3	15	1092816	84	1592	1570	237103	1333333
9	1	10	323291	67	0	0	1009975	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	13	632612	87	1678	0	71418	705882
2	2	12	334333	53	1420	0	370023	705882
3	3	11	673914	100	1762	1631	28275	705882
4	1	11	246779	100	0	0	459003	705882
5	2	6	581284	92	1488	0	122926	705882
6	1	10	408151	80	0	0	297651	705882
7	3	11	346805	81	1603	1052	356179	705882
8	2	17	608418	82	1559	0	95741	705882
9	2	14	18515	60	990	0	686257	705882
10	3	18	138566	62	1862	1800	563468	705882
11	2	19	382258	98	1145	0	322283	705882
12	2	20	702515	99	1796	0	1373	705882
13	3	14	212683	95	1761	1284	489869	705882
14	1	10	226833	68	0	0	478981	705882
15	1	13	502013	67	0	0	203802	705882
16	1	5	390775	61	0	0	315046	705882
17	1	17	313295	88	0	0	392499	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	11	627295	62	1729	0	76734	705882
2	3	15	608104	88	1750	1658	94106	705882
3	3	5	268054	66	1129	1581	434920	705882
4	3	14	18707	72	1469	1855	683635	705882
5	2	19	430885	59	1262	0	273617	705882
6	2	7	180725	90	1134	0	523843	705882
7	1	14	665074	98	0	0	40710	705882
8	2	11	457298	69	1515	0	246931	705882
9	2	15	695484	80	1694	0	8544	705882
10	1	19	536461	92	0	0	169329	705882
11	3	18	157515	66	1109	1672	545388	705882
12	1	20	444552	81	0	0	261249	705882
13	1	5	434283	63	0	0	271536	705882
14	2	7	416624	84	978	0	288112	705882
15	3	14	627220	94	933	912	76535	705882
16	2	16	666310	71	1337	0	38093	705882
17	1	13	26872	89	0	0	678921	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	20	903821	70	1140	1310	93519	1000000
2	3	17	392211	71	1375	1319	604882	1000000
3	3	6	250166	52	1784	1097	746797	1000000
4	1	8	300306	95	0	0	699599	1000000
5	3	8	200308	64	1730	1257	796513	1000000
6	1	10	753455	76	0	0	246469	1000000
7	1	16	278267	64	0	0	721669	1000000
8	1	8	798146	93	0	0	201761	1000000
9	3	8	100164	57	1503	1444	896718	1000000
10	2	10	958252	84	1026	0	40554	1000000
11	2	7	594736	65	1045	0	404089	1000000
12	2	20	583957	86	1501	0	414370	1000000

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Type 5 #29 5494.00 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	275946	63	1574	0	428236	705882
2	3	18	28188	65	1611	1232	674656	705882
3	2	6	201714	97	963	0	503011	705882
4	3	10	632610	57	1594	1828	69679	705882
5	2	12	123064	93	1761	0	580871	705882
6	1	12	624940	86	0	0	80856	705882
7	2	9	684979	60	1677	0	19106	705882
8	2	16	262083	94	1659	0	441952	705882
9	2	15	633323	72	1406	0	71009	705882
10	1	13	190925	52	0	0	514905	705882
11	3	8	361715	92	1843	1726	340322	705882
12	3	7	103611	61	1477	1460	599151	705882
13	1	11	293494	61	0	0	412327	705882
14	1	10	61749	83	0	0	644050	705882
15	3	11	267981	96	1496	1182	434935	705882
16	2	10	443994	95	1456	0	260242	705882
17	1	12	370943	81	0	0	334858	705882

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Type 6 #1 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5279	#02-5431	#03-5382	#04-5462	#05-5354	#06-5376	#07-5369	#08-5572	#09-5331	#10-5359
#11-5356	#12-5445	#13-5349	#14-5368	#15-5586	#16-5518	#17-5587	#18-5471	#19-5253	#20-5434
#21-5558	#22-5561	#23-5457	#24-5273	#25-5632	#26-5657	#27-5551	#28-5680	#29-5502	#30-5554
#31-5582	#32-5416	#33-5265	#34-5683	#35-5350	#36-5302	#37-5639	#38-5512	#39-5364	#40-5375
#41-5421	#42-5275	#43-5710	#44-5371	#45-5396	#46-5650	#47-5281	#48-5450	#49-5329	#50-5718
#51-5496	#52-5569	#53-5597	#54-5546	#55-5255	#56-5468	#57-5436	#58-5270	#59-5579	#60-5615
#61-5492	#62-5677	#63-5263	#64-5628	#65-5418	#66-5534	#67-5547	#68-5614	#69-5309	#70-5387
#71-5535	#72-5626	#73-5324	#74-5511	#75-5649	#76-5708	#77-5422	#78-5335	#79-5571	#80-5393
#81-5386	#82-5344	#83-5695	#84-5420	#85-5325	#86-5343	#87-5250	#88-5495	#89-5604	#90-5606
#91-5271	#92-5641	#93-5506	#94-5284	#95-5607	#96-5509	#97-5459	#98-5260	#99-5430	#100-5394

Type 6 #2 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5650	#02-5368	#03-5450	#04-5666	#05-5406	#06-5304	#07-5355	#08-5595	#09-5491	#10-5323
#11-5563	#12-5377	#13-5607	#14-5520	#15-5309	#16-5617	#17-5364	#18-5376	#19-5271	#20-5442
#21-5379	#22-5604	#23-5311	#24-5317	#25-5640	#26-5526	#27-5453	#28-5312	#29-5658	#30-5560
#31-5515	#32-5275	#33-5400	#34-5699	#35-5524	#36-5553	#37-5264	#38-5290	#39-5448	#40-5501
#41-5511	#42-5505	#43-5514	#44-5327	#45-5401	#46-5336	#47-5567	#48-5621	#49-5382	#50-5408
#51-5676	#52-5489	#53-5388	#54-5599	#55-5490	#56-5502	#57-5677	#58-5293	#59-5662	#60-5365
#61-5488	#62-5298	#63-5351	#64-5456	#65-5545	#66-5509	#67-5313	#68-5349	#69-5548	#70-5592
#71-5522	#72-5714	#73-5375	#74-5366	#75-5587	#76-5340	#77-5480	#78-5427	#79-5356	#80-5324
#81-5605	#82-5460	#83-5386	#84-5679	#85-5499	#86-5512	#87-5495	#88-5457	#89-5574	#90-5390
#91-5279	#92-5278	#93-5669	#94-5516	#95-5665	#96-5504	#97-5521	#98-5296	#99-5585	#100-5259

Type 6 #3 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5653	#02-5389	#03-5590	#04-5609	#05-5704	#06-5377	#07-5561	#08-5431	#09-5571	#10-5310
#11-5666	#12-5277	#13-5576	#14-5334	#15-5373	#16-5359	#17-5575	#18-5548	#19-5303	#20-5459
#21-5268	#22-5684	#23-5497	#24-5685	#25-5483	#26-5430	#27-5646	#28-5683	#29-5381	#30-5496
#31-5314	#32-5676	#33-5321	#34-5521	#35-5319	#36-5520	#37-5385	#38-5659	#39-5276	#40-5252
#41-5505	#42-5689	#43-5338	#44-5251	#45-5343	#46-5432	#47-5541	#48-5394	#49-5671	#50-5472
#51-5532	#52-5525	#53-5635	#54-5649	#55-5471	#56-5711	#57-5509	#58-5260	#59-5651	#60-5654
#61-5419	#62-5687	#63-5624	#64-5263	#65-5577	#66-5289	#67-5305	#68-5413	#69-5369	#70-5265
#71-5429	#72-5597	#73-5482	#74-5337	#75-5393	#76-5354	#77-5416	#78-5262	#79-5633	#80-5513
#81-5291	#82-5615	#83-5427	#84-5395	#85-5299	#86-5438	#87-5672	#88-5492	#89-5717	#90-5579
#91-5284	#92-5643	#93-5288	#94-5443	#95-5418	#96-5355	#97-5616	#98-5309	#99-5619	#100-5535

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Type 6 #4 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5302	#02-5713	#03-5584	#04-5568	#05-5404	#06-5638	#07-5271	#08-5454	#09-5424	#10-5583
#11-5373	#12-5399	#13-5619	#14-5255	#15-5699	#16-5421	#17-5664	#18-5273	#19-5575	#20-5497
#21-5678	#22-5443	#23-5390	#24-5311	#25-5371	#26-5573	#27-5526	#28-5419	#29-5397	#30-5613
#31-5616	#32-5343	#33-5310	#34-5579	#35-5354	#36-5338	#37-5665	#38-5263	#39-5439	#40-5588
#41-5295	#42-5539	#43-5460	#44-5610	#45-5335	#46-5716	#47-5596	#48-5401	#49-5288	#50-5349
#51-5519	#52-5689	#53-5593	#54-5506	#55-5517	#56-5423	#57-5653	#58-5254	#59-5436	#60-5484
#61-5507	#62-5670	#63-5369	#64-5316	#65-5576	#66-5598	#67-5634	#68-5488	#69-5284	#70-5654
#71-5485	#72-5487	#73-5534	#74-5265	#75-5525	#76-5462	#77-5578	#78-5718	#79-5515	#80-5614
#81-5324	#82-5617	#83-5398	#84-5565	#85-5511	#86-5536	#87-5282	#88-5659	#89-5691	#90-5650
#91-5552	#92-5722	#93-5491	#94-5529	#95-5585	#96-5655	#97-5413	#98-5281	#99-5660	#100-5368

Type 6 #5 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5713	#02-5635	#03-5271	#04-5654	#05-5532	#06-5405	#07-5479	#08-5555	#09-5501	#10-5705
#11-5486	#12-5644	#13-5702	#14-5720	#15-5611	#16-5368	#17-5543	#18-5641	#19-5546	#20-5521
#21-5609	#22-5438	#23-5528	#24-5695	#25-5298	#26-5383	#27-5575	#28-5684	#29-5687	#30-5366
#31-5629	#32-5392	#33-5596	#34-5488	#35-5514	#36-5352	#37-5377	#38-5509	#39-5461	#40-5344
#41-5301	#42-5266	#43-5255	#44-5610	#45-5607	#46-5669	#47-5294	#48-5595	#49-5263	#50-5459
#51-5388	#52-5483	#53-5525	#54-5357	#55-5300	#56-5605	#57-5398	#58-5520	#59-5259	#60-5590
#61-5268	#62-5369	#63-5264	#64-5559	#65-5373	#66-5578	#67-5440	#68-5287	#69-5310	#70-5387
#71-5511	#72-5690	#73-5413	#74-5500	#75-5630	#76-5640	#77-5250	#78-5290	#79-5673	#80-5632
#81-5490	#82-5634	#83-5321	#84-5381	#85-5463	#86-5472	#87-5703	#88-5678	#89-5665	#90-5335
#91-5435	#92-5723	#93-5545	#94-5646	#95-5692	#96-5474	#97-5422	#98-5328	#99-5694	#100-5570

Type 6 #6 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5335	#02-5441	#03-5623	#04-5649	#05-5605	#06-5259	#07-5550	#08-5319	#09-5462	#10-5499
#11-5650	#12-5302	#13-5716	#14-5365	#15-5693	#16-5535	#17-5333	#18-5369	#19-5428	#20-5676
#21-5513	#22-5329	#23-5542	#24-5452	#25-5334	#26-5719	#27-5282	#28-5610	#29-5448	#30-5459
#31-5412	#32-5664	#33-5658	#34-5377	#35-5280	#36-5279	#37-5310	#38-5326	#39-5609	#40-5653
#41-5398	#42-5346	#43-5372	#44-5493	#45-5654	#46-5577	#47-5436	#48-5663	#49-5339	#50-5683
#51-5515	#52-5306	#53-5255	#54-5421	#55-5565	#56-5701	#57-5665	#58-5595	#59-5253	#60-5337
#61-5710	#62-5431	#63-5712	#64-5662	#65-5456	#66-5303	#67-5309	#68-5352	#69-5317	#70-5584
#71-5656	#72-5446	#73-5566	#74-5315	#75-5429	#76-5423	#77-5509	#78-5453	#79-5399	#80-5472
#81-5478	#82-5381	#83-5633	#84-5439	#85-5424	#86-5349	#87-5669	#88-5308	#89-5395	#90-5386
#91-5374	#92-5590	#93-5457	#94-5285	#95-5624	#96-5413	#97-5368	#98-5447	#99-5324	#100-5427

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Type 6 #7 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5341	#02-5723	#03-5545	#04-5522	#05-5491	#06-5335	#07-5608	#08-5561	#09-5622	#10-5677
#11-5589	#12-5530	#13-5547	#14-5609	#15-5252	#16-5373	#17-5526	#18-5511	#19-5436	#20-5667
#21-5441	#22-5567	#23-5563	#24-5649	#25-5302	#26-5334	#27-5554	#28-5710	#29-5353	#30-5281
#31-5297	#32-5679	#33-5541	#34-5440	#35-5604	#36-5552	#37-5427	#38-5697	#39-5376	#40-5550
#41-5477	#42-5520	#43-5250	#44-5693	#45-5635	#46-5420	#47-5264	#48-5411	#49-5720	#50-5646
#51-5537	#52-5715	#53-5399	#54-5531	#55-5703	#56-5683	#57-5283	#58-5523	#59-5304	#60-5576
#61-5518	#62-5542	#63-5256	#64-5255	#65-5424	#66-5670	#67-5724	#68-5310	#69-5367	#70-5689
#71-5296	#72-5680	#73-5392	#74-5638	#75-5539	#76-5549	#77-5357	#78-5360	#79-5485	#80-5688
#81-5633	#82-5625	#83-5594	#84-5585	#85-5663	#86-5713	#87-5321	#88-5698	#89-5599	#90-5433
#91-5366	#92-5628	#93-5271	#94-5259	#95-5711	#96-5300	#97-5538	#98-5654	#99-5656	#100-5370

Type 6 #8 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5611	#02-5616	#03-5609	#04-5489	#05-5277	#06-5410	#07-5535	#08-5306	#09-5613	#10-5589
#11-5490	#12-5354	#13-5555	#14-5335	#15-5261	#16-5714	#17-5393	#18-5256	#19-5422	#20-5379
#21-5564	#22-5488	#23-5617	#24-5530	#25-5562	#26-5307	#27-5268	#28-5671	#29-5283	#30-5360
#31-5316	#32-5694	#33-5474	#34-5698	#35-5296	#36-5353	#37-5556	#38-5522	#39-5313	#40-5376
#41-5478	#42-5289	#43-5505	#44-5629	#45-5406	#46-5689	#47-5450	#48-5527	#49-5665	#50-5560
#51-5483	#52-5715	#53-5297	#54-5378	#55-5717	#56-5684	#57-5440	#58-5517	#59-5579	#60-5424
#61-5384	#62-5331	#63-5362	#64-5569	#65-5632	#66-5407	#67-5447	#68-5459	#69-5359	#70-5253
#71-5448	#72-5361	#73-5625	#74-5405	#75-5342	#76-5542	#77-5394	#78-5343	#79-5472	#80-5481
#81-5461	#82-5650	#83-5642	#84-5596	#85-5418	#86-5521	#87-5266	#88-5624	#89-5536	#90-5495
#91-5324	#92-5577	#93-5606	#94-5620	#95-5508	#96-5415	#97-5351	#98-5374	#99-5712	#100-5687

Type 6 #9 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5655	#02-5605	#03-5309	#04-5284	#05-5260	#06-5699	#07-5691	#08-5486	#09-5256	#10-5668
#11-5648	#12-5572	#13-5436	#14-5651	#15-5521	#16-5535	#17-5690	#18-5290	#19-5562	#20-5712
#21-5637	#22-5280	#23-5379	#24-5330	#25-5489	#26-5661	#27-5498	#28-5559	#29-5306	#30-5336
#31-5496	#32-5688	#33-5480	#34-5536	#35-5447	#36-5408	#37-5546	#38-5299	#39-5387	#40-5529
#41-5388	#42-5571	#43-5477	#44-5391	#45-5679	#46-5349	#47-5697	#48-5450	#49-5311	#50-5250
#51-5501	#52-5267	#53-5575	#54-5678	#55-5287	#56-5442	#57-5675	#58-5538	#59-5561	#60-5325
#61-5473	#62-5664	#63-5723	#64-5493	#65-5607	#66-5266	#67-5662	#68-5298	#69-5357	#70-5616
#71-5532	#72-5578	#73-5348	#74-5707	#75-5399	#76-5587	#77-5581	#78-5318	#79-5525	#80-5695
#81-5629	#82-5606	#83-5494	#84-5636	#85-5509	#86-5582	#87-5461	#88-5579	#89-5574	#90-5259
#91-5401	#92-5642	#93-5265	#94-5308	#95-5698	#96-5681	#97-5428	#98-5520	#99-5312	#100-5452

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Type 6 #10 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5634	#02-5683	#03-5372	#04-5349	#05-5397	#06-5305	#07-5292	#08-5314	#09-5344	#10-5469
#11-5286	#12-5554	#13-5694	#14-5385	#15-5366	#16-5724	#17-5695	#18-5481	#19-5329	#20-5562
#21-5503	#22-5523	#23-5426	#24-5430	#25-5692	#26-5341	#27-5613	#28-5624	#29-5614	#30-5254
#31-5433	#32-5708	#33-5310	#34-5671	#35-5484	#36-5394	#37-5489	#38-5454	#39-5539	#40-5396
#41-5485	#42-5354	#43-5698	#44-5572	#45-5606	#46-5296	#47-5647	#48-5582	#49-5682	#50-5458
#51-5288	#52-5707	#53-5615	#54-5381	#55-5641	#56-5574	#57-5337	#58-5676	#59-5444	#60-5579
#61-5281	#62-5370	#63-5302	#64-5633	#65-5439	#66-5456	#67-5277	#68-5515	#69-5415	#70-5268
#71-5662	#72-5549	#73-5645	#74-5418	#75-5666	#76-5406	#77-5691	#78-5450	#79-5342	#80-5653
#81-5279	#82-5635	#83-5471	#84-5521	#85-5588	#86-5290	#87-5499	#88-5452	#89-5553	#90-5387
#91-5700	#92-5352	#93-5252	#94-5260	#95-5442	#96-5363	#97-5703	#98-5274	#99-5318	#100-5392

Type 6 #11 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5417	#02-5507	#03-5395	#04-5502	#05-5423	#06-5315	#07-5644	#08-5684	#09-5704	#10-5409
#11-5696	#12-5358	#13-5659	#14-5636	#15-5651	#16-5444	#17-5702	#18-5412	#19-5607	#20-5376
#21-5721	#22-5508	#23-5685	#24-5305	#25-5564	#26-5403	#27-5680	#28-5258	#29-5617	#30-5540
#31-5300	#32-5611	#33-5402	#34-5378	#35-5674	#36-5330	#37-5550	#38-5512	#39-5326	#40-5601
#41-5533	#42-5593	#43-5407	#44-5298	#45-5253	#46-5719	#47-5318	#48-5349	#49-5516	#50-5255
#51-5385	#52-5541	#53-5391	#54-5667	#55-5396	#56-5633	#57-5547	#58-5339	#59-5663	#60-5269
#61-5359	#62-5317	#63-5414	#64-5334	#65-5530	#66-5687	#67-5571	#68-5619	#69-5439	#70-5336
#71-5256	#72-5568	#73-5377	#74-5350	#75-5301	#76-5569	#77-5335	#78-5581	#79-5466	#80-5405
#81-5484	#82-5470	#83-5460	#84-5707	#85-5290	#86-5574	#87-5306	#88-5491	#89-5622	#90-5525
#91-5718	#92-5664	#93-5289	#94-5387	#95-5670	#96-5361	#97-5455	#98-5348	#99-5268	#100-5532

Type 6 #12 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5636	#02-5287	#03-5344	#04-5658	#05-5503	#06-5419	#07-5431	#08-5258	#09-5599	#10-5589
#11-5469	#12-5548	#13-5646	#14-5313	#15-5408	#16-5590	#17-5279	#18-5489	#19-5670	#20-5577
#21-5357	#22-5696	#23-5382	#24-5530	#25-5443	#26-5521	#27-5500	#28-5459	#29-5335	#30-5361
#31-5688	#32-5482	#33-5596	#34-5423	#35-5479	#36-5373	#37-5713	#38-5453	#39-5709	#40-5315
#41-5304	#42-5544	#43-5689	#44-5465	#45-5606	#46-5677	#47-5330	#48-5426	#49-5620	#50-5403
#51-5416	#52-5425	#53-5664	#54-5629	#55-5538	#56-5360	#57-5309	#58-5622	#59-5655	#60-5524
#61-5569	#62-5504	#63-5584	#64-5414	#65-5441	#66-5710	#67-5631	#68-5467	#69-5372	#70-5630
#71-5328	#72-5703	#73-5639	#74-5379	#75-5578	#76-5439	#77-5683	#78-5522	#79-5307	#80-5656
#81-5518	#82-5666	#83-5262	#84-5653	#85-5555	#86-5435	#87-5470	#88-5437	#89-5354	#90-5301
#91-5415	#92-5691	#93-5694	#94-5519	#95-5369	#96-5660	#97-5302	#98-5284	#99-5551	#100-5552

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Type 6 #13 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5501	#02-5330	#03-5707	#04-5357	#05-5395	#06-5716	#07-5315	#08-5398	#09-5312	#10-5356
#11-5509	#12-5442	#13-5419	#14-5618	#15-5571	#16-5636	#17-5318	#18-5662	#19-5409	#20-5528
#21-5523	#22-5479	#23-5652	#24-5474	#25-5581	#26-5308	#27-5319	#28-5273	#29-5588	#30-5254
#31-5622	#32-5691	#33-5363	#34-5486	#35-5573	#36-5572	#37-5306	#38-5289	#39-5478	#40-5459
#41-5288	#42-5292	#43-5669	#44-5630	#45-5499	#46-5525	#47-5626	#48-5522	#49-5590	#50-5364
#51-5599	#52-5278	#53-5272	#54-5403	#55-5483	#56-5500	#57-5710	#58-5658	#59-5720	#60-5375
#61-5448	#62-5351	#63-5612	#64-5475	#65-5305	#66-5381	#67-5723	#68-5314	#69-5261	#70-5655
#71-5485	#72-5436	#73-5708	#74-5568	#75-5332	#76-5609	#77-5406	#78-5521	#79-5724	#80-5614
#81-5667	#82-5334	#83-5464	#84-5339	#85-5531	#86-5304	#87-5545	#88-5637	#89-5569	#90-5567
#91-5268	#92-5469	#93-5494	#94-5524	#95-5684	#96-5578	#97-5467	#98-5668	#99-5680	#100-5518

Type 6 #14 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5560	#02-5420	#03-5639	#04-5418	#05-5351	#06-5502	#07-5449	#08-5375	#09-5461	#10-5588
#11-5532	#12-5696	#13-5642	#14-5554	#15-5700	#16-5455	#17-5568	#18-5360	#19-5579	#20-5572
#21-5591	#22-5390	#23-5550	#24-5308	#25-5636	#26-5722	#27-5290	#28-5395	#29-5397	#30-5329
#31-5712	#32-5541	#33-5628	#34-5724	#35-5424	#36-5362	#37-5678	#38-5292	#39-5264	#40-5511
#41-5369	#42-5355	#43-5404	#44-5465	#45-5497	#46-5577	#47-5694	#48-5709	#49-5372	#50-5623
#51-5557	#52-5350	#53-5670	#54-5693	#55-5279	#56-5339	#57-5685	#58-5590	#59-5451	#60-5335
#61-5304	#62-5314	#63-5509	#64-5545	#65-5405	#66-5263	#67-5525	#68-5343	#69-5615	#70-5318
#71-5564	#72-5310	#73-5472	#74-5284	#75-5567	#76-5617	#77-5309	#78-5277	#79-5305	#80-5272
#81-5498	#82-5611	#83-5595	#84-5659	#85-5334	#86-5252	#87-5717	#88-5426	#89-5538	#90-5291
#91-5620	#92-5645	#93-5342	#94-5563	#95-5433	#96-5258	#97-5489	#98-5609	#99-5471	#100-5719

Type 6 #15 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5668	#02-5517	#03-5318	#04-5531	#05-5423	#06-5280	#07-5282	#08-5540	#09-5261	#10-5658
#11-5535	#12-5329	#13-5585	#14-5441	#15-5340	#16-5622	#17-5616	#18-5275	#19-5609	#20-5407
#21-5718	#22-5500	#23-5646	#24-5525	#25-5471	#26-5612	#27-5597	#28-5717	#29-5490	#30-5257
#31-5350	#32-5710	#33-5438	#34-5699	#35-5390	#36-5460	#37-5649	#38-5620	#39-5364	#40-5395
#41-5476	#42-5608	#43-5712	#44-5532	#45-5484	#46-5529	#47-5664	#48-5360	#49-5485	#50-5724
#51-5313	#52-5251	#53-5418	#54-5595	#55-5310	#56-5289	#57-5300	#58-5253	#59-5557	#60-5549
#61-5615	#62-5610	#63-5605	#64-5698	#65-5721	#66-5636	#67-5464	#68-5375	#69-5492	#70-5659
#71-5711	#72-5332	#73-5604	#74-5303	#75-5379	#76-5385	#77-5589	#78-5374	#79-5697	#80-5381
#81-5560	#82-5554	#83-5426	#84-5404	#85-5707	#86-5593	#87-5644	#88-5667	#89-5308	#90-5386
#91-5601	#92-5574	#93-5510	#94-5663	#95-5483	#96-5527	#97-5660	#98-5524	#99-5323	#100-5452

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Type 6 #16 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5528	#02-5711	#03-5645	#04-5593	#05-5692	#06-5563	#07-5491	#08-5637	#09-5328	#10-5265
#11-5567	#12-5410	#13-5331	#14-5476	#15-5382	#16-5316	#17-5261	#18-5505	#19-5260	#20-5367
#21-5413	#22-5662	#23-5719	#24-5717	#25-5508	#26-5450	#27-5435	#28-5464	#29-5419	#30-5653
#31-5582	#32-5486	#33-5351	#34-5434	#35-5256	#36-5436	#37-5394	#38-5352	#39-5257	#40-5589
#41-5293	#42-5544	#43-5440	#44-5492	#45-5284	#46-5531	#47-5417	#48-5515	#49-5405	#50-5513
#51-5680	#52-5289	#53-5591	#54-5716	#55-5652	#56-5335	#57-5677	#58-5362	#59-5305	#60-5422
#61-5633	#62-5336	#63-5710	#64-5649	#65-5705	#66-5291	#67-5375	#68-5535	#69-5724	#70-5318
#71-5590	#72-5406	#73-5323	#74-5676	#75-5423	#76-5317	#77-5498	#78-5416	#79-5629	#80-5296
#81-5628	#82-5497	#83-5311	#84-5568	#85-5264	#86-5578	#87-5651	#88-5484	#89-5281	#90-5297
#91-5559	#92-5681	#93-5558	#94-5516	#95-5511	#96-5607	#97-5337	#98-5647	#99-5665	#100-5608

Type 6 #17 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5518	#02-5290	#03-5478	#04-5267	#05-5429	#06-5671	#07-5401	#08-5376	#09-5254	#10-5564
#11-5642	#12-5368	#13-5644	#14-5448	#15-5361	#16-5682	#17-5323	#18-5559	#19-5692	#20-5571
#21-5367	#22-5720	#23-5589	#24-5525	#25-5711	#26-5423	#27-5473	#28-5414	#29-5362	#30-5410
#31-5395	#32-5590	#33-5428	#34-5300	#35-5699	#36-5349	#37-5633	#38-5304	#39-5335	#40-5620
#41-5433	#42-5676	#43-5641	#44-5398	#45-5592	#46-5519	#47-5294	#48-5649	#49-5442	#50-5503
#51-5338	#52-5697	#53-5286	#54-5400	#55-5614	#56-5467	#57-5498	#58-5652	#59-5686	#60-5616
#61-5403	#62-5496	#63-5502	#64-5465	#65-5386	#66-5582	#67-5415	#68-5504	#69-5321	#70-5388
#71-5603	#72-5672	#73-5369	#74-5628	#75-5489	#76-5645	#77-5632	#78-5306	#79-5618	#80-5391
#81-5624	#82-5655	#83-5460	#84-5416	#85-5587	#86-5561	#87-5693	#88-5472	#89-5309	#90-5688
#91-5621	#92-5371	#93-5317	#94-5277	#95-5723	#96-5625	#97-5623	#98-5710	#99-5666	#100-5340

Type 6 #18 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5323	#02-5594	#03-5473	#04-5446	#05-5696	#06-5496	#07-5439	#08-5609	#09-5324	#10-5499
#11-5456	#12-5372	#13-5723	#14-5642	#15-5636	#16-5353	#17-5641	#18-5356	#19-5639	#20-5527
#21-5480	#22-5718	#23-5507	#24-5521	#25-5422	#26-5617	#27-5633	#28-5441	#29-5717	#30-5493
#31-5488	#32-5519	#33-5326	#34-5513	#35-5691	#36-5469	#37-5275	#38-5338	#39-5680	#40-5261
#41-5302	#42-5597	#43-5426	#44-5669	#45-5278	#46-5331	#47-5678	#48-5706	#49-5603	#50-5501
#51-5389	#52-5584	#53-5330	#54-5337	#55-5677	#56-5273	#57-5328	#58-5588	#59-5722	#60-5616
#61-5555	#62-5585	#63-5692	#64-5578	#65-5647	#66-5378	#67-5615	#68-5267	#69-5448	#70-5571
#71-5665	#72-5635	#73-5344	#74-5477	#75-5589	#76-5551	#77-5445	#78-5511	#79-5285	#80-5712
#81-5380	#82-5466	#83-5433	#84-5604	#85-5516	#86-5252	#87-5259	#88-5683	#89-5370	#90-5471
#91-5262	#92-5458	#93-5341	#94-5355	#95-5258	#96-5637	#97-5586	#98-5303	#99-5542	#100-5365

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Type 6 #19 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5389	#02-5427	#03-5582	#04-5520	#05-5464	#06-5286	#07-5483	#08-5420	#09-5293	#10-5549
#11-5705	#12-5448	#13-5431	#14-5670	#15-5315	#16-5343	#17-5613	#18-5258	#19-5594	#20-5349
#21-5443	#22-5622	#23-5611	#24-5385	#25-5598	#26-5480	#27-5533	#28-5423	#29-5659	#30-5562
#31-5351	#32-5426	#33-5658	#34-5456	#35-5541	#36-5449	#37-5674	#38-5428	#39-5437	#40-5478
#41-5618	#42-5649	#43-5257	#44-5667	#45-5543	#46-5452	#47-5578	#48-5433	#49-5654	#50-5266
#51-5529	#52-5696	#53-5413	#54-5253	#55-5597	#56-5376	#57-5295	#58-5610	#59-5329	#60-5626
#61-5409	#62-5407	#63-5462	#64-5302	#65-5414	#66-5399	#67-5265	#68-5435	#69-5382	#70-5492
#71-5559	#72-5590	#73-5538	#74-5715	#75-5692	#76-5570	#77-5475	#78-5633	#79-5334	#80-5347
#81-5687	#82-5320	#83-5540	#84-5378	#85-5445	#86-5312	#87-5555	#88-5311	#89-5432	#90-5569
#91-5355	#92-5303	#93-5384	#94-5365	#95-5380	#96-5489	#97-5591	#98-5655	#99-5563	#100-5395

Type 6 #20 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5547	#02-5440	#03-5621	#04-5630	#05-5530	#06-5544	#07-5701	#08-5719	#09-5529	#10-5716
#11-5447	#12-5336	#13-5646	#14-5649	#15-5693	#16-5337	#17-5434	#18-5374	#19-5674	#20-5483
#21-5714	#22-5485	#23-5484	#24-5581	#25-5455	#26-5344	#27-5393	#28-5468	#29-5417	#30-5528
#31-5373	#32-5427	#33-5394	#34-5555	#35-5255	#36-5415	#37-5650	#38-5505	#39-5613	#40-5281
#41-5574	#42-5551	#43-5312	#44-5661	#45-5684	#46-5444	#47-5521	#48-5503	#49-5470	#50-5384
#51-5405	#52-5680	#53-5290	#54-5708	#55-5325	#56-5449	#57-5558	#58-5501	#59-5361	#60-5437
#61-5323	#62-5633	#63-5687	#64-5647	#65-5508	#66-5593	#67-5311	#68-5452	#69-5390	#70-5658
#71-5422	#72-5644	#73-5260	#74-5614	#75-5597	#76-5689	#77-5671	#78-5559	#79-5293	#80-5492
#81-5300	#82-5667	#83-5430	#84-5413	#85-5448	#86-5439	#87-5599	#88-5588	#89-5350	#90-5657
#91-5265	#92-5379	#93-5507	#94-5371	#95-5270	#96-5314	#97-5560	#98-5686	#99-5536	#100-5414

Type 6 #21 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5602	#02-5563	#03-5590	#04-5512	#05-5577	#06-5636	#07-5522	#08-5565	#09-5412	#10-5623
#11-5254	#12-5316	#13-5468	#14-5548	#15-5306	#16-5318	#17-5502	#18-5288	#19-5357	#20-5709
#21-5459	#22-5658	#23-5361	#24-5698	#25-5363	#26-5517	#27-5253	#28-5647	#29-5366	#30-5487
#31-5511	#32-5275	#33-5721	#34-5274	#35-5435	#36-5404	#37-5508	#38-5309	#39-5371	#40-5662
#41-5653	#42-5673	#43-5635	#44-5684	#45-5315	#46-5358	#47-5720	#48-5307	#49-5648	#50-5428
#51-5430	#52-5393	#53-5630	#54-5478	#55-5539	#56-5464	#57-5369	#58-5518	#59-5643	#60-5296
#61-5492	#62-5530	#63-5443	#64-5551	#65-5281	#66-5451	#67-5639	#68-5719	#69-5365	#70-5298
#71-5587	#72-5433	#73-5452	#74-5558	#75-5663	#76-5538	#77-5519	#78-5564	#79-5332	#80-5569
#81-5368	#82-5681	#83-5294	#84-5528	#85-5515	#86-5615	#87-5607	#88-5410	#89-5441	#90-5382
#91-5283	#92-5632	#93-5331	#94-5313	#95-5532	#96-5380	#97-5568	#98-5596	#99-5625	#100-5295

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5514	#02-5261	#03-5535	#04-5580	#05-5355	#06-5650	#07-5501	#08-5652	#09-5447	#10-5599
#11-5698	#12-5637	#13-5494	#14-5298	#15-5674	#16-5562	#17-5507	#18-5384	#19-5631	#20-5372
#21-5272	#22-5606	#23-5260	#24-5425	#25-5629	#26-5289	#27-5455	#28-5281	#29-5676	#30-5251
#31-5706	#32-5467	#33-5636	#34-5326	#35-5283	#36-5717	#37-5659	#38-5347	#39-5690	#40-5483
#41-5670	#42-5567	#43-5409	#44-5370	#45-5387	#46-5282	#47-5364	#48-5695	#49-5597	#50-5433
#51-5689	#52-5503	#53-5273	#54-5632	#55-5250	#56-5360	#57-5449	#58-5610	#59-5295	#60-5621
#61-5496	#62-5716	#63-5419	#64-5582	#65-5697	#66-5641	#67-5569	#68-5573	#69-5287	#70-5665
#71-5266	#72-5661	#73-5418	#74-5508	#75-5493	#76-5257	#77-5341	#78-5311	#79-5329	#80-5543
#81-5267	#82-5613	#83-5708	#84-5623	#85-5330	#86-5310	#87-5586	#88-5424	#89-5694	#90-5417
#91-5530	#92-5309	#93-5448	#94-5375	#95-5274	#96-5395	#97-5487	#98-5557	#99-5344	#100-5681

Type 6 #23 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5602	#02-5679	#03-5559	#04-5416	#05-5304	#06-5699	#07-5455	#08-5694	#09-5528	#10-5607
#11-5687	#12-5590	#13-5389	#14-5585	#15-5681	#16-5652	#17-5487	#18-5448	#19-5574	#20-5557
#21-5688	#22-5672	#23-5618	#24-5661	#25-5397	#26-5717	#27-5451	#28-5379	#29-5447	#30-5512
#31-5539	#32-5666	#33-5452	#34-5355	#35-5276	#36-5257	#37-5639	#38-5442	#39-5470	#40-5560
#41-5505	#42-5565	#43-5412	#44-5409	#45-5255	#46-5413	#47-5531	#48-5556	#49-5458	#50-5358
#51-5494	#52-5718	#53-5655	#54-5310	#55-5623	#56-5362	#57-5632	#58-5707	#59-5253	#60-5331
#61-5406	#62-5425	#63-5300	#64-5382	#65-5575	#66-5625	#67-5480	#68-5533	#69-5336	#70-5377
#71-5302	#72-5498	#73-5620	#74-5391	#75-5553	#76-5645	#77-5547	#78-5714	#79-5342	#80-5267
#81-5673	#82-5522	#83-5294	#84-5378	#85-5460	#86-5467	#87-5719	#88-5424	#89-5408	#90-5712
#91-5281	#92-5680	#93-5703	#94-5549	#95-5499	#96-5488	#97-5258	#98-5374	#99-5466	#100-5490

Type 6 #24 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5403	#02-5332	#03-5267	#04-5341	#05-5314	#06-5407	#07-5346	#08-5498	#09-5584	#10-5530
#11-5497	#12-5585	#13-5525	#14-5647	#15-5594	#16-5383	#17-5717	#18-5619	#19-5511	#20-5583
#21-5522	#22-5690	#23-5617	#24-5261	#25-5517	#26-5629	#27-5429	#28-5333	#29-5284	#30-5286
#31-5253	#32-5492	#33-5307	#34-5384	#35-5701	#36-5344	#37-5554	#38-5262	#39-5421	#40-5400
#41-5367	#42-5274	#43-5440	#44-5630	#45-5456	#46-5496	#47-5363	#48-5587	#49-5680	#50-5631
#51-5605	#52-5375	#53-5330	#54-5521	#55-5502	#56-5641	#57-5415	#58-5550	#59-5493	#60-5432
#61-5282	#62-5589	#63-5459	#64-5406	#65-5634	#66-5524	#67-5682	#68-5549	#69-5350	#70-5540
#71-5618	#72-5438	#73-5601	#74-5512	#75-5648	#76-5390	#77-5447	#78-5586	#79-5426	#80-5576
#81-5252	#82-5547	#83-5302	#84-5345	#85-5593	#86-5595	#87-5638	#88-5660	#89-5716	#90-5575
#91-5420	#92-5300	#93-5563	#94-5431	#95-5331	#96-5504	#97-5552	#98-5640	#99-5436	#100-5278

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5313	#02-5367	#03-5538	#04-5288	#05-5570	#06-5353	#07-5709	#08-5421	#09-5413	#10-5442
#11-5555	#12-5631	#13-5702	#14-5630	#15-5403	#16-5680	#17-5480	#18-5633	#19-5545	#20-5682
#21-5501	#22-5588	#23-5551	#24-5650	#25-5334	#26-5485	#27-5266	#28-5504	#29-5646	#30-5440
#31-5660	#32-5541	#33-5519	#34-5713	#35-5703	#36-5305	#37-5557	#38-5311	#39-5535	#40-5676
#41-5544	#42-5412	#43-5470	#44-5586	#45-5250	#46-5278	#47-5375	#48-5274	#49-5643	#50-5345
#51-5478	#52-5450	#53-5264	#54-5711	#55-5362	#56-5593	#57-5692	#58-5641	#59-5491	#60-5252
#61-5619	#62-5340	#63-5432	#64-5424	#65-5625	#66-5648	#67-5572	#68-5259	#69-5256	#70-5425
#71-5331	#72-5694	#73-5472	#74-5484	#75-5379	#76-5622	#77-5522	#78-5565	#79-5312	#80-5268
#81-5512	#82-5689	#83-5319	#84-5444	#85-5550	#86-5667	#87-5708	#88-5628	#89-5645	#90-5700
#91-5575	#92-5590	#93-5333	#94-5578	#95-5475	#96-5351	#97-5320	#98-5335	#99-5275	#100-5613

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5629	#02-5393	#03-5263	#04-5358	#05-5704	#06-5512	#07-5594	#08-5455	#09-5304	#10-5278
#11-5414	#12-5378	#13-5460	#14-5555	#15-5453	#16-5272	#17-5317	#18-5303	#19-5504	#20-5399
#21-5480	#22-5353	#23-5318	#24-5400	#25-5384	#26-5628	#27-5521	#28-5451	#29-5479	#30-5564
#31-5448	#32-5487	#33-5325	#34-5300	#35-5537	#36-5558	#37-5254	#38-5366	#39-5301	#40-5495
#41-5562	#42-5714	#43-5679	#44-5367	#45-5644	#46-5622	#47-5297	#48-5267	#49-5450	#50-5490
#51-5464	#52-5398	#53-5289	#54-5669	#55-5683	#56-5570	#57-5608	#58-5322	#59-5253	#60-5549
#61-5439	#62-5690	#63-5616	#64-5385	#65-5391	#66-5403	#67-5483	#68-5662	#69-5452	#70-5684
#71-5516	#72-5329	#73-5445	#74-5266	#75-5708	#76-5624	#77-5462	#78-5363	#79-5717	#80-5586
#81-5265	#82-5260	#83-5592	#84-5600	#85-5409	#86-5482	#87-5492	#88-5697	#89-5373	#90-5273
#91-5313	#92-5707	#93-5503	#94-5468	#95-5509	#96-5433	#97-5553	#98-5292	#99-5560	#100-5498

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5589	#02-5487	#03-5553	#04-5625	#05-5423	#06-5574	#07-5337	#08-5325	#09-5257	#10-5624
#11-5523	#12-5376	#13-5392	#14-5592	#15-5608	#16-5583	#17-5430	#18-5473	#19-5386	#20-5711
#21-5393	#22-5305	#23-5381	#24-5283	#25-5455	#26-5405	#27-5566	#28-5677	#29-5655	#30-5380
#31-5674	#32-5276	#33-5550	#34-5253	#35-5362	#36-5580	#37-5582	#38-5530	#39-5642	#40-5610
#41-5297	#42-5266	#43-5414	#44-5434	#45-5377	#46-5326	#47-5694	#48-5372	#49-5543	#50-5452
#51-5355	#52-5533	#53-5356	#54-5520	#55-5419	#56-5268	#57-5258	#58-5384	#59-5395	#60-5602
#61-5497	#62-5630	#63-5496	#64-5573	#65-5668	#66-5469	#67-5351	#68-5345	#69-5289	#70-5692
#71-5327	#72-5328	#73-5597	#74-5302	#75-5330	#76-5577	#77-5347	#78-5444	#79-5256	#80-5310
#81-5412	#82-5511	#83-5634	#84-5476	#85-5626	#86-5389	#87-5464	#88-5661	#89-5551	#90-5421
#91-5378	#92-5571	#93-5524	#94-5600	#95-5679	#96-5259	#97-5493	#98-5388	#99-5671	#100-5342

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5664	#02-5385	#03-5331	#04-5314	#05-5594	#06-5544	#07-5645	#08-5452	#09-5498	#10-5394
#11-5490	#12-5668	#13-5411	#14-5406	#15-5560	#16-5600	#17-5443	#18-5625	#19-5477	#20-5637
#21-5501	#22-5632	#23-5492	#24-5648	#25-5484	#26-5458	#27-5504	#28-5622	#29-5720	#30-5372
#31-5676	#32-5592	#33-5364	#34-5320	#35-5571	#36-5562	#37-5519	#38-5266	#39-5348	#40-5647
#41-5685	#42-5613	#43-5628	#44-5362	#45-5444	#46-5369	#47-5476	#48-5541	#49-5593	#50-5635
#51-5283	#52-5565	#53-5282	#54-5618	#55-5407	#56-5555	#57-5386	#58-5289	#59-5272	#60-5456
#61-5376	#62-5553	#63-5341	#64-5559	#65-5311	#66-5455	#67-5606	#68-5356	#69-5557	#70-5620
#71-5402	#72-5709	#73-5531	#74-5285	#75-5581	#76-5345	#77-5310	#78-5503	#79-5494	#80-5556
#81-5333	#82-5682	#83-5330	#84-5479	#85-5539	#86-5605	#87-5711	#88-5256	#89-5383	#90-5719
#91-5617	#92-5521	#93-5715	#94-5324	#95-5271	#96-5609	#97-5307	#98-5659	#99-5486	#100-5327

Type 6 #29 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5388	#02-5413	#03-5297	#04-5336	#05-5372	#06-5699	#07-5290	#08-5704	#09-5493	#10-5687
#11-5545	#12-5359	#13-5665	#14-5473	#15-5587	#16-5269	#17-5431	#18-5468	#19-5600	#20-5698
#21-5676	#22-5626	#23-5510	#24-5438	#25-5288	#26-5295	#27-5506	#28-5323	#29-5425	#30-5446
#31-5621	#32-5571	#33-5604	#34-5667	#35-5315	#36-5492	#37-5518	#38-5589	#39-5282	#40-5342
#41-5475	#42-5654	#43-5700	#44-5383	#45-5299	#46-5575	#47-5409	#48-5590	#49-5601	#50-5527
#51-5309	#52-5513	#53-5376	#54-5486	#55-5628	#56-5583	#57-5298	#58-5326	#59-5442	#60-5691
#61-5528	#62-5464	#63-5648	#64-5311	#65-5531	#66-5521	#67-5502	#68-5638	#69-5603	#70-5567
#71-5605	#72-5300	#73-5400	#74-5580	#75-5462	#76-5630	#77-5721	#78-5656	#79-5639	#80-5560
#81-5569	#82-5670	#83-5562	#84-5307	#85-5478	#86-5430	#87-5412	#88-5633	#89-5469	#90-5512
#91-5564	#92-5375	#93-5348	#94-5428	#95-5439	#96-5302	#97-5594	#98-5712	#99-5294	#100-5613

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5337	#02-5688	#03-5648	#04-5466	#05-5632	#06-5325	#07-5336	#08-5297	#09-5370	#10-5393
#11-5330	#12-5511	#13-5302	#14-5693	#15-5452	#16-5519	#17-5455	#18-5558	#19-5350	#20-5359
#21-5594	#22-5418	#23-5341	#24-5252	#25-5479	#26-5676	#27-5697	#28-5390	#29-5410	#30-5285
#31-5258	#32-5611	#33-5276	#34-5473	#35-5606	#36-5271	#37-5345	#38-5399	#39-5402	#40-5344
#41-5364	#42-5512	#43-5326	#44-5431	#45-5303	#46-5323	#47-5380	#48-5700	#49-5645	#50-5690
#51-5389	#52-5403	#53-5669	#54-5503	#55-5467	#56-5520	#57-5557	#58-5463	#59-5373	#60-5685
#61-5357	#62-5322	#63-5625	#64-5469	#65-5571	#66-5497	#67-5715	#68-5305	#69-5406	#70-5256
#71-5720	#72-5332	#73-5634	#74-5674	#75-5546	#76-5721	#77-5444	#78-5621	#79-5579	#80-5667
#81-5255	#82-5439	#83-5607	#84-5278	#85-5705	#86-5457	#87-5552	#88-5694	#89-5296	#90-5635
#91-5378	#92-5398	#93-5334	#94-5722	#95-5663	#96-5508	#97-5385	#98-5428	#99-5514	#100-5551

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	82573	83	0	0	548922	631578
2	1	6	94954	90	0	0	536534	631578
3	3	17	140883	78	1105	1686	487670	631578
4	3	20	66537	95	1090	1028	562638	631578
5	1	18	58146	57	0	0	573375	631578
6	2	20	524935	88	1644	0	104823	631578
7	3	11	321993	94	1300	1352	306651	631578
8	2	11	394690	54	1591	0	235189	631578
9	2	11	2024	74	1361	0	628045	631578
10	2	16	514932	81	1317	0	115167	631578
11	2	5	343498	50	1864	0	286116	631578
12	1	19	293192	90	0	0	338296	631578
13	2	10	91862	94	1223	0	538305	631578
14	3	17	130005	70	1247	1642	498474	631578
15	3	13	534364	80	1417	1534	94023	631578
16	3	6	122412	70	1071	1067	506818	631578
17	2	7	217816	50	1809	0	411853	631578
18	2	11	108539	95	1737	0	521112	631578
19	3	17	163398	65	1066	1095	465824	631578

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Type 5 #1 5494.80 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	9	134636	87	944	0	570128	705882
2	1	12	394003	98	0	0	311781	705882
3	1	10	276849	85	0	0	428948	705882
4	3	8	211281	66	1604	960	491839	705882
5	3	5	210278	92	1217	1325	492786	705882
6	2	16	517464	81	1155	0	187101	705882
7	2	12	337163	85	1575	0	366974	705882
8	2	7	696533	92	1051	0	8114	705882
9	1	17	127171	69	0	0	578642	705882
10	1	12	237670	52	0	0	468160	705882
11	2	6	606178	55	1049	0	98545	705882
12	1	14	300880	97	0	0	404905	705882
13	3	18	166119	87	1324	1173	537005	705882
14	3	5	250551	91	1802	1642	451614	705882
15	3	13	518671	68	1816	1244	183947	705882
16	2	7	177823	63	1148	0	526785	705882
17	3	6	265906	64	1070	1578	437136	705882

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Type 5 #2 5510.00 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	19	652684	87	0	0	13895	666666
2	3	10	99407	72	1506	1894	563643	666666
3	3	8	650394	68	1086	1640	13342	666666
4	3	14	370107	87	1133	1461	293704	666666
5	2	9	318886	65	1606	0	346044	666666
6	3	7	291928	56	1046	1125	372399	666666
7	1	20	293804	86	0	0	372776	666666
8	3	6	512592	70	1487	1665	150712	666666
9	1	17	7334	65	0	0	659267	666666
10	1	9	290911	61	0	0	375694	666666
11	2	7	412669	52	1229	0	252664	666666
12	1	15	189790	81	0	0	476795	666666
13	3	12	519213	72	1741	975	144521	666666
14	3	12	485784	51	1662	1488	177579	666666
15	1	15	542472	76	0	0	124118	666666
16	3	5	252980	59	1471	1601	410437	666666
17	2	16	83277	92	1614	0	581591	666666
18	1	6	493008	95	0	0	173563	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	73701	56	0	0	592909	666666
2	1	8	342257	98	0	0	324311	666666
3	3	15	467024	100	1415	1662	196265	666666
4	1	12	311695	77	0	0	354894	666666
5	3	14	378820	53	1098	1572	285017	666666
6	3	6	425533	81	1261	1576	238053	666666
7	1	20	474122	67	0	0	192477	666666
8	2	11	350173	60	1494	0	314879	666666
9	3	12	479096	98	1589	1576	184111	666666
10	1	5	424932	53	0	0	241681	666666
11	2	11	449034	90	1169	0	216283	666666
12	1	12	368113	55	0	0	298498	666666
13	1	18	600388	84	0	0	66194	666666
14	3	18	33184	60	1254	1482	630566	666666
15	1	7	626596	94	0	0	39976	666666
16	3	6	631578	50	1061	1415	32462	666666
17	3	13	51190	83	1000	1622	612605	666666
18	3	6	246242	85	1213	1404	417552	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	18	448075	62	1898	984	254739	705882
2	2	11	13331	91	1505	0	690864	705882
3	3	11	174147	89	1760	1397	528311	705882
4	2	15	495782	55	1493	0	208497	705882
5	2	17	549145	56	1139	0	155486	705882
6	2	8	395408	57	1187	0	309173	705882
7	3	10	36326	58	1647	1026	666709	705882
8	1	20	95222	74	0	0	610586	705882
9	2	13	655474	52	1247	0	49057	705882
10	2	8	521074	50	1788	0	182920	705882
11	2	7	402794	87	1045	0	301869	705882
12	3	18	465090	59	1800	1076	237739	705882
13	1	12	654267	67	0	0	51548	705882
14	2	7	138238	55	1346	0	566188	705882
15	2	15	185893	82	1331	0	518494	705882
16	2	12	87980	80	1185	0	616557	705882
17	2	11	129182	97	1407	0	575099	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	7	291502	59	1292	1815	1038547	1333333
2	2	12	941450	93	1167	0	390530	1333333
3	1	10	737468	68	0	0	595797	1333333
4	3	15	94614	91	1162	1650	1235634	1333333
5	3	20	779543	94	1046	1601	550861	1333333
6	3	16	364726	90	1699	1758	964880	1333333
7	3	19	429106	81	929	968	902087	1333333
8	1	18	1253398	51	0	0	79884	1333333
9	1	13	148146	95	0	0	1185092	1333333

Type 5 #6 5510.00 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	150441	74	1675	0	447736	600000
2	2	9	99921	52	1269	0	498706	600000
3	1	15	529357	59	0	0	70584	600000

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4	1	12	515703	88	0	0	84209	600000
5	3	16	456822	79	1562	1772	139607	600000
6	1	16	153876	100	0	0	446024	600000
7	3	6	377868	94	1525	1490	218835	600000
8	1	14	23832	65	0	0	576103	600000
9	2	16	353529	92	1272	0	245015	600000
10	3	7	453814	92	1543	1047	143320	600000
11	1	5	434912	77	0	0	165011	600000
12	2	19	212879	63	1570	0	385425	600000
13	2	16	269446	63	1736	0	328692	600000
14	2	14	598328	55	1540	0	22	600000
15	3	7	576613	88	1344	1176	20603	600000
16	3	5	105004	66	940	1861	491997	600000
17	2	12	198835	79	1534	0	399473	600000
18	1	5	224707	95	0	0	375198	600000
19	1	8	365749	84	0	0	234167	600000
20	1	20	547924	55	0	0	52021	600000

Type 5 #7 5524.00 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	13	16301	62	1573	1356	1313917	1333333
2	1	17	1012553	55	0	0	320725	1333333
3	3	19	338094	97	1530	1332	992086	1333333
4	3	9	95120	57	1781	1067	1235194	1333333
5	3	15	1197666	78	1412	996	133025	1333333
6	3	18	1219151	97	1783	1320	110788	1333333
7	1	15	952735	84	0	0	380514	1333333
8	1	14	309101	74	0	0	1024158	1333333
9	1	10	594795	56	0	0	738482	1333333

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Type 5 #8 5493.20 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	10	411448	91	0	0	588461	1000000
2	3	6	547685	82	927	1591	449551	1000000
3	3	19	277612	50	1889	1094	719255	1000000
4	3	18	363214	95	1417	1869	633215	1000000
5	3	8	267280	81	1901	1737	728839	1000000
6	3	14	138481	91	1130	1088	859028	1000000
7	1	12	523668	54	0	0	476278	1000000
8	3	10	129323	62	1846	1528	867117	1000000
9	2	8	423792	85	1461	0	574577	1000000
10	3	8	386208	71	1425	1864	610290	1000000
11	3	16	823445	53	1156	1930	173310	1000000
12	3	18	827182	55	1931	1720	169002	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	17	397714	53	1263	955	266575	666666
2	1	17	413660	52	0	0	252954	666666
3	3	16	623207	75	1197	1769	40268	666666
4	2	16	499857	66	1178	0	165499	666666
5	2	16	606022	50	1265	0	59279	666666
6	2	17	96206	77	1659	0	568647	666666
7	3	12	93817	94	1542	1269	569756	666666
8	1	19	509242	61	0	0	157363	666666
9	1	12	489582	96	0	0	176988	666666
10	3	13	297591	61	1903	1116	365873	666666
11	2	14	376484	52	986	0	289092	666666
12	1	5	65077	53	0	0	601536	666666
13	1	9	26244	82	0	0	640340	666666
14	2	14	423461	57	1248	0	241843	666666
15	2	9	551143	90	1018	0	114325	666666
16	2	12	1842	71	1498	0	663184	666666
17	2	18	407894	84	1485	0	257119	666666
18	1	17	192607	75	0	0	473984	666666

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	87914	66	0	0	835096	923076
2	1	7	61187	86	0	0	861803	923076
3	3	14	844297	99	989	1830	75663	923076
4	2	7	204111	69	1476	0	717351	923076
5	1	7	439812	81	0	0	483183	923076
6	1	11	308535	70	0	0	614471	923076
7	1	17	908644	83	0	0	14349	923076
8	1	19	523119	67	0	0	399890	923076
9	1	8	906123	87	0	0	16866	923076
10	1	10	525853	68	0	0	397155	923076
11	2	13	863533	70	1679	0	57724	923076
12	1	7	873176	61	0	0	49839	923076
13	2	17	774145	59	1883	0	146930	923076

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	10	69069	85	972	1329	528375	600000
2	3	17	190586	63	964	1288	406973	600000
3	2	14	449414	97	1004	0	149388	600000
4	1	19	399063	78	0	0	200859	600000
5	3	11	360915	84	1899	1334	235600	600000
6	1	7	68759	88	0	0	531153	600000
7	2	16	165081	66	1450	0	433337	600000
8	3	20	85132	65	1389	1548	511736	600000
9	3	14	132112	86	1682	1500	464448	600000
10	2	11	229550	74	1447	0	368855	600000
11	3	18	45092	66	968	1911	551831	600000
12	3	20	544836	76	1441	1528	51967	600000
13	3	19	211651	100	1310	1188	385551	600000
14	2	6	312841	66	1199	0	285828	600000
15	1	17	129023	98	0	0	470879	600000
16	3	15	354598	69	1194	1648	242353	600000
17	1	11	419977	68	0	0	179955	600000
18	1	8	565499	89	0	0	34412	600000
19	3	15	513548	83	1075	1726	83402	600000
20	3	17	585459	84	1010	1045	12234	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	17	835549	85	0	0	364366	1200000
2	1	18	197003	58	0	0	1002939	1200000
3	1	9	1064324	64	0	0	135612	1200000
4	1	15	605407	74	0	0	594519	1200000
5	3	14	192243	52	1181	1332	1005088	1200000
6	2	20	1139187	95	1046	0	59577	1200000
7	2	14	159764	58	1504	0	1038616	1200000
8	3	20	4429	70	1593	1530	1192238	1200000
9	1	10	934090	80	0	0	265830	1200000
10	3	10	449618	69	1202	1421	747552	1200000

Type 5 #13 5510.00 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	726941	55	0	0	606337	1333333
2	3	6	977885	91	1006	1819	352350	1333333
3	3	11	971468	61	945	1494	359243	1333333
4	1	19	697145	57	0	0	636131	1333333
5	3	16	1159697	96	1795	1885	169668	1333333
6	2	8	918613	67	1460	0	413126	1333333
7	2	9	626117	79	1910	0	705148	1333333
8	2	20	1122454	79	1510	0	209211	1333333
9	2	9	517177	85	1127	0	814859	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	15	340995	63	1186	1058	256572	600000
2	3	9	337500	58	1337	1099	259890	600000
3	3	17	27052	60	1811	1323	569634	600000
4	1	6	10652	82	0	0	589266	600000
5	1	13	95579	61	0	0	504360	600000
6	1	11	128377	84	0	0	471539	600000
7	2	14	498109	84	1845	0	99878	600000
8	1	9	340875	79	0	0	259046	600000
9	1	7	433845	86	0	0	166069	600000
10	1	5	69774	68	0	0	530158	600000
11	2	16	133642	53	1254	0	464998	600000
12	3	18	254818	88	1667	1089	342162	600000
13	3	8	30579	99	1073	1661	566390	600000
14	3	20	413168	74	1872	1298	183440	600000
15	1	12	127220	55	0	0	472725	600000
16	3	9	304472	99	910	1762	292559	600000
17	1	14	426397	98	0	0	173505	600000
18	3	17	46814	60	1785	1036	550185	600000
19	3	13	327685	57	1549	1783	268812	600000
20	2	6	30014	84	1793	0	568025	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	11	241313	69	0	0	958618	1200000
2	3	18	199910	86	1776	1374	996682	1200000
3	2	19	672044	60	1235	0	526601	1200000
4	1	16	865601	57	0	0	334342	1200000
5	1	9	944406	93	0	0	255501	1200000
6	1	18	446731	77	0	0	753192	1200000
7	2	14	1179455	80	1813	0	18572	1200000
8	2	19	363169	94	1142	0	835501	1200000
9	3	5	740679	73	943	1162	456997	1200000
10	3	10	1183142	80	1607	1464	13547	1200000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	7	322105	69	1853	0	675904	1000000
2	3	9	334068	80	1576	1795	662321	1000000
3	2	18	580939	63	1211	0	417724	1000000
4	3	10	437569	52	1272	1694	559309	1000000
5	1	6	612739	84	0	0	387177	1000000
6	3	13	825842	52	1139	1132	171731	1000000
7	2	6	828420	63	1457	0	169997	1000000
8	2	8	25707	78	1570	0	972567	1000000
9	1	16	557911	80	0	0	442009	1000000
10	3	12	637591	89	919	1518	359705	1000000
11	1	14	88482	83	0	0	911435	1000000
12	1	17	709904	74	0	0	290022	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	12	760239	87	1604	0	737983	1500000
2	1	16	1130965	50	0	0	368985	1500000
3	3	12	1078604	60	1086	1616	418514	1500000
4	2	20	970946	84	1470	0	527416	1500000
5	3	13	965612	79	1505	1466	531180	1500000
6	3	5	1088936	84	1338	1261	408213	1500000
7	3	6	1351837	58	1230	1529	145230	1500000
8	1	20	58347	74	0	0	1441579	1500000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	7	25680	70	0	0	680132	705882
2	3	16	180470	94	1322	1435	522373	705882
3	1	20	145119	57	0	0	560706	705882
4	3	18	517124	57	1304	1280	186003	705882
5	1	12	465106	70	0	0	240706	705882
6	3	11	524581	78	1725	1701	177641	705882
7	1	18	616732	85	0	0	89065	705882
8	1	11	429662	59	0	0	276161	705882
9	3	9	330795	91	915	1726	372173	705882
10	3	7	532817	51	1032	1656	170224	705882
11	2	14	266790	56	1247	0	437733	705882
12	3	12	304350	96	966	1325	398953	705882
13	3	17	206204	82	1101	1285	497046	705882
14	1	16	523008	97	0	0	182777	705882
15	1	13	302427	82	0	0	403373	705882
16	1	5	622309	80	0	0	83493	705882
17	3	10	282370	71	1024	950	421325	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	12	254638	78	0	0	345284	600000
2	1	13	183613	97	0	0	416290	600000
3	2	10	171962	70	964	0	426934	600000
4	2	6	8258	87	1065	0	590503	600000
5	1	12	53526	54	0	0	546420	600000
6	3	9	67155	52	1854	1549	529286	600000
7	1	17	369147	54	0	0	230799	600000
8	2	9	350855	61	1681	0	247342	600000
9	2	18	196009	71	1637	0	402212	600000
10	1	20	333259	50	0	0	266691	600000
11	3	8	48611	74	1269	1122	548776	600000
12	1	12	593375	65	0	0	6560	600000
13	3	7	258972	72	1291	1249	338272	600000
14	1	14	452836	64	0	0	147100	600000
15	2	6	289962	52	1938	0	307996	600000
16	2	8	94362	80	1305	0	504173	600000
17	3	6	76844	93	1612	1089	520176	600000
18	3	19	42776	83	1638	1528	553809	600000
19	3	6	36240	65	1080	1277	561208	600000
20	2	5	246228	63	1794	0	351852	600000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	10	659001	83	1147	1775	537828	1200000
2	2	19	59735	91	1220	0	1138863	1200000
3	3	12	647008	67	1114	1125	550552	1200000
4	2	19	697664	70	1074	0	501122	1200000
5	1	19	407926	91	0	0	791983	1200000
6	1	16	133282	76	0	0	1066642	1200000
7	1	12	1077968	54	0	0	121978	1200000
8	3	17	403193	76	1588	1731	793260	1200000
9	1	7	538507	91	0	0	661402	1200000
10	1	17	1059702	62	0	0	140236	1200000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	11	285081	87	0	0	346410	631578
2	2	10	333930	52	1316	0	296228	631578
3	1	8	607938	76	0	0	23564	631578
4	1	7	610976	91	0	0	20511	631578
5	2	15	261300	72	1594	0	368540	631578
6	3	6	273091	92	1565	1247	355399	631578
7	3	15	408527	79	1459	1341	220014	631578
8	2	16	578830	69	1562	0	51048	631578
9	3	7	181647	74	1174	1285	447250	631578
10	1	16	211108	63	0	0	420407	631578
11	1	18	225629	64	0	0	405885	631578
12	1	19	541031	60	0	0	90487	631578
13	2	18	557561	69	1648	0	72231	631578
14	2	14	520433	98	1882	0	109067	631578
15	1	11	283196	86	0	0	348296	631578
16	2	14	326326	73	1100	0	304006	631578
17	1	13	617991	76	0	0	13511	631578
18	2	6	181535	82	1501	0	448378	631578
19	3	8	327413	59	1377	1446	301165	631578

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	7	717514	52	0	0	482434	1200000
2	2	16	315400	64	1245	0	883227	1200000
3	3	19	489046	100	1718	1846	707090	1200000
4	3	16	34053	52	1671	1287	1162833	1200000
5	2	6	1121574	74	1711	0	76567	1200000
6	3	17	247073	91	1543	1786	949325	1200000
7	3	6	688170	64	1343	1413	508882	1200000
8	3	17	522871	94	1135	1622	674090	1200000
9	2	17	487098	60	1282	0	711500	1200000
10	2	16	218231	57	1725	0	979930	1200000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	5	821676	79	1734	1614	508072	1333333
2	3	15	1309131	76	1001	1704	21269	1333333
3	2	5	638410	93	1184	0	693553	1333333
4	3	13	54172	93	1706	1596	1275580	1333333
5	2	7	534417	79	1250	0	797508	1333333
6	2	7	975648	75	1350	0	356185	1333333
7	1	18	568912	62	0	0	764359	1333333
8	3	9	113992	59	1795	1661	1215708	1333333
9	2	8	645990	94	1135	0	686020	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	19	864617	83	0	0	58376	923076
2	2	7	582101	67	1465	0	339376	923076
3	1	9	486480	76	0	0	436520	923076
4	1	20	327624	56	0	0	595396	923076
5	1	14	155137	70	0	0	767869	923076
6	3	14	72564	86	1499	1617	847138	923076
7	2	13	868347	84	1282	0	53279	923076
8	3	8	448860	100	1735	1101	471080	923076
9	1	6	278136	90	0	0	644850	923076
10	3	15	536195	77	1894	1250	383506	923076
11	3	13	802373	71	1896	1765	116829	923076
12	1	20	297846	65	0	0	625165	923076
13	2	9	784073	97	1455	0	137354	923076

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	12	400474	79	1451	1834	929337	1333333
2	3	7	1152866	94	1496	1428	177261	1333333
3	1	19	818596	59	0	0	514678	1333333
4	2	15	28544	75	1189	0	1303450	1333333
5	2	20	1233194	55	1706	0	98323	1333333
6	3	7	717144	94	1090	1448	613369	1333333
7	2	15	699989	86	1008	0	632164	1333333
8	3	15	1092816	84	1592	1570	237103	1333333
9	1	10	323291	67	0	0	1009975	1333333

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	13	632612	87	1678	0	71418	705882
2	2	12	334333	53	1420	0	370023	705882
3	3	11	673914	100	1762	1631	28275	705882
4	1	11	246779	100	0	0	459003	705882
5	2	6	581284	92	1488	0	122926	705882
6	1	10	408151	80	0	0	297651	705882
7	3	11	346805	81	1603	1052	356179	705882
8	2	17	608418	82	1559	0	95741	705882
9	2	14	18515	60	990	0	686257	705882
10	3	18	138566	62	1862	1800	563468	705882
11	2	19	382258	98	1145	0	322283	705882
12	2	20	702515	99	1796	0	1373	705882
13	3	14	212683	95	1761	1284	489869	705882
14	1	10	226833	68	0	0	478981	705882
15	1	13	502013	67	0	0	203802	705882
16	1	5	390775	61	0	0	315046	705882
17	1	17	313295	88	0	0	392499	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	11	627295	62	1729	0	76734	705882
2	3	15	608104	88	1750	1658	94106	705882
3	3	5	268054	66	1129	1581	434920	705882
4	3	14	18707	72	1469	1855	683635	705882
5	2	19	430885	59	1262	0	273617	705882
6	2	7	180725	90	1134	0	523843	705882
7	1	14	665074	98	0	0	40710	705882
8	2	11	457298	69	1515	0	246931	705882
9	2	15	695484	80	1694	0	8544	705882
10	1	19	536461	92	0	0	169329	705882
11	3	18	157515	66	1109	1672	545388	705882
12	1	20	444552	81	0	0	261249	705882
13	1	5	434283	63	0	0	271536	705882
14	2	7	416624	84	978	0	288112	705882
15	3	14	627220	94	933	912	76535	705882
16	2	16	666310	71	1337	0	38093	705882
17	1	13	26872	89	0	0	678921	705882

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	20	903821	70	1140	1310	93519	1000000
2	3	17	392211	71	1375	1319	604882	1000000
3	3	6	250166	52	1784	1097	746797	1000000
4	1	8	300306	95	0	0	699599	1000000
5	3	8	200308	64	1730	1257	796513	1000000
6	1	10	753455	76	0	0	246469	1000000
7	1	16	278267	64	0	0	721669	1000000
8	1	8	798146	93	0	0	201761	1000000
9	3	8	100164	57	1503	1444	896718	1000000
10	2	10	958252	84	1026	0	40554	1000000
11	2	7	594736	65	1045	0	404089	1000000
12	2	20	583957	86	1501	0	414370	1000000

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Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	275946	63	1574	0	428236	705882
2	3	18	28188	65	1611	1232	674656	705882
3	2	6	201714	97	963	0	503011	705882
4	3	10	632610	57	1594	1828	69679	705882
5	2	12	123064	93	1761	0	580871	705882
6	1	12	624940	86	0	0	80856	705882
7	2	9	684979	60	1677	0	19106	705882
8	2	16	262083	94	1659	0	441952	705882
9	2	15	633323	72	1406	0	71009	705882
10	1	13	190925	52	0	0	514905	705882
11	3	8	361715	92	1843	1726	340322	705882
12	3	7	103611	61	1477	1460	599151	705882
13	1	11	293494	61	0	0	412327	705882
14	1	10	61749	83	0	0	644050	705882
15	3	11	267981	96	1496	1182	434935	705882
16	2	10	443994	95	1456	0	260242	705882
17	1	12	370943	81	0	0	334858	705882

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Type 6 #1 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5279	#02-5431	#03-5382	#04-5462	#05-5354	#06-5376	#07-5369	#08-5572	#09-5331	#10-5359
#11-5356	#12-5445	#13-5349	#14-5368	#15-5586	#16-5518	#17-5587	#18-5471	#19-5253	#20-5434
#21-5558	#22-5561	#23-5457	#24-5273	#25-5632	#26-5657	#27-5551	#28-5680	#29-5502	#30-5554
#31-5582	#32-5416	#33-5265	#34-5683	#35-5350	#36-5302	#37-5639	#38-5512	#39-5364	#40-5375
#41-5421	#42-5275	#43-5710	#44-5371	#45-5396	#46-5650	#47-5281	#48-5450	#49-5329	#50-5718
#51-5496	#52-5569	#53-5597	#54-5546	#55-5255	#56-5468	#57-5436	#58-5270	#59-5579	#60-5615
#61-5492	#62-5677	#63-5263	#64-5628	#65-5418	#66-5534	#67-5547	#68-5614	#69-5309	#70-5387
#71-5535	#72-5626	#73-5324	#74-5511	#75-5649	#76-5708	#77-5422	#78-5335	#79-5571	#80-5393
#81-5386	#82-5344	#83-5695	#84-5420	#85-5325	#86-5343	#87-5250	#88-5495	#89-5604	#90-5606
#91-5271	#92-5641	#93-5506	#94-5284	#95-5607	#96-5509	#97-5459	#98-5260	#99-5430	#100-5394

Type 6 #2 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5650	#02-5368	#03-5450	#04-5666	#05-5406	#06-5304	#07-5355	#08-5595	#09-5491	#10-5323
#11-5563	#12-5377	#13-5607	#14-5520	#15-5309	#16-5617	#17-5364	#18-5376	#19-5271	#20-5442
#21-5379	#22-5604	#23-5311	#24-5317	#25-5640	#26-5526	#27-5453	#28-5312	#29-5658	#30-5560
#31-5515	#32-5275	#33-5400	#34-5699	#35-5524	#36-5553	#37-5264	#38-5290	#39-5448	#40-5501
#41-5511	#42-5505	#43-5514	#44-5327	#45-5401	#46-5336	#47-5567	#48-5621	#49-5382	#50-5408
#51-5676	#52-5489	#53-5388	#54-5599	#55-5490	#56-5502	#57-5677	#58-5293	#59-5662	#60-5365
#61-5488	#62-5298	#63-5351	#64-5456	#65-5545	#66-5509	#67-5313	#68-5349	#69-5548	#70-5592
#71-5522	#72-5714	#73-5375	#74-5366	#75-5587	#76-5340	#77-5480	#78-5427	#79-5356	#80-5324
#81-5605	#82-5460	#83-5386	#84-5679	#85-5499	#86-5512	#87-5495	#88-5457	#89-5574	#90-5390
#91-5279	#92-5278	#93-5669	#94-5516	#95-5665	#96-5504	#97-5521	#98-5296	#99-5585	#100-5259

Type 6 #3 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5653	#02-5389	#03-5590	#04-5609	#05-5704	#06-5377	#07-5561	#08-5431	#09-5571	#10-5310
#11-5666	#12-5277	#13-5576	#14-5334	#15-5373	#16-5359	#17-5575	#18-5548	#19-5303	#20-5459
#21-5268	#22-5684	#23-5497	#24-5685	#25-5483	#26-5430	#27-5646	#28-5683	#29-5381	#30-5496
#31-5314	#32-5676	#33-5321	#34-5521	#35-5319	#36-5520	#37-5385	#38-5659	#39-5276	#40-5252
#41-5505	#42-5689	#43-5338	#44-5251	#45-5343	#46-5432	#47-5541	#48-5394	#49-5671	#50-5472
#51-5532	#52-5525	#53-5635	#54-5649	#55-5471	#56-5711	#57-5509	#58-5260	#59-5651	#60-5654
#61-5419	#62-5687	#63-5624	#64-5263	#65-5577	#66-5289	#67-5305	#68-5413	#69-5369	#70-5265
#71-5429	#72-5597	#73-5482	#74-5337	#75-5393	#76-5354	#77-5416	#78-5262	#79-5633	#80-5513
#81-5291	#82-5615	#83-5427	#84-5395	#85-5299	#86-5438	#87-5672	#88-5492	#89-5717	#90-5579
#91-5284	#92-5643	#93-5288	#94-5443	#95-5418	#96-5355	#97-5616	#98-5309	#99-5619	#100-5535

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Type 6 #4 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5302	#02-5713	#03-5584	#04-5568	#05-5404	#06-5638	#07-5271	#08-5454	#09-5424	#10-5583
#11-5373	#12-5399	#13-5619	#14-5255	#15-5699	#16-5421	#17-5664	#18-5273	#19-5575	#20-5497
#21-5678	#22-5443	#23-5390	#24-5311	#25-5371	#26-5573	#27-5526	#28-5419	#29-5397	#30-5613
#31-5616	#32-5343	#33-5310	#34-5579	#35-5354	#36-5338	#37-5665	#38-5263	#39-5439	#40-5588
#41-5295	#42-5539	#43-5460	#44-5610	#45-5335	#46-5716	#47-5596	#48-5401	#49-5288	#50-5349
#51-5519	#52-5689	#53-5593	#54-5506	#55-5517	#56-5423	#57-5653	#58-5254	#59-5436	#60-5484
#61-5507	#62-5670	#63-5369	#64-5316	#65-5576	#66-5598	#67-5634	#68-5488	#69-5284	#70-5654
#71-5485	#72-5487	#73-5534	#74-5265	#75-5525	#76-5462	#77-5578	#78-5718	#79-5515	#80-5614
#81-5324	#82-5617	#83-5398	#84-5565	#85-5511	#86-5536	#87-5282	#88-5659	#89-5691	#90-5650
#91-5552	#92-5722	#93-5491	#94-5529	#95-5585	#96-5655	#97-5413	#98-5281	#99-5660	#100-5368

Type 6 #5 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5713	#02-5635	#03-5271	#04-5654	#05-5532	#06-5405	#07-5479	#08-5555	#09-5501	#10-5705
#11-5486	#12-5644	#13-5702	#14-5720	#15-5611	#16-5368	#17-5543	#18-5641	#19-5546	#20-5521
#21-5609	#22-5438	#23-5528	#24-5695	#25-5298	#26-5383	#27-5575	#28-5684	#29-5687	#30-5366
#31-5629	#32-5392	#33-5596	#34-5488	#35-5514	#36-5352	#37-5377	#38-5509	#39-5461	#40-5344
#41-5301	#42-5266	#43-5255	#44-5610	#45-5607	#46-5669	#47-5294	#48-5595	#49-5263	#50-5459
#51-5388	#52-5483	#53-5525	#54-5357	#55-5300	#56-5605	#57-5398	#58-5520	#59-5259	#60-5590
#61-5268	#62-5369	#63-5264	#64-5559	#65-5373	#66-5578	#67-5440	#68-5287	#69-5310	#70-5387
#71-5511	#72-5690	#73-5413	#74-5500	#75-5630	#76-5640	#77-5250	#78-5290	#79-5673	#80-5632
#81-5490	#82-5634	#83-5321	#84-5381	#85-5463	#86-5472	#87-5703	#88-5678	#89-5665	#90-5335
#91-5435	#92-5723	#93-5545	#94-5646	#95-5692	#96-5474	#97-5422	#98-5328	#99-5694	#100-5570

Type 6 #6 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5335	#02-5441	#03-5623	#04-5649	#05-5605	#06-5259	#07-5550	#08-5319	#09-5462	#10-5499
#11-5650	#12-5302	#13-5716	#14-5365	#15-5693	#16-5535	#17-5333	#18-5369	#19-5428	#20-5676
#21-5513	#22-5329	#23-5542	#24-5452	#25-5334	#26-5719	#27-5282	#28-5610	#29-5448	#30-5459
#31-5412	#32-5664	#33-5658	#34-5377	#35-5280	#36-5279	#37-5310	#38-5326	#39-5609	#40-5653
#41-5398	#42-5346	#43-5372	#44-5493	#45-5654	#46-5577	#47-5436	#48-5663	#49-5339	#50-5683
#51-5515	#52-5306	#53-5255	#54-5421	#55-5565	#56-5701	#57-5665	#58-5595	#59-5253	#60-5337
#61-5710	#62-5431	#63-5712	#64-5662	#65-5456	#66-5303	#67-5309	#68-5352	#69-5317	#70-5584
#71-5656	#72-5446	#73-5566	#74-5315	#75-5429	#76-5423	#77-5509	#78-5453	#79-5399	#80-5472
#81-5478	#82-5381	#83-5633	#84-5439	#85-5424	#86-5349	#87-5669	#88-5308	#89-5395	#90-5386
#91-5374	#92-5590	#93-5457	#94-5285	#95-5624	#96-5413	#97-5368	#98-5447	#99-5324	#100-5427

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Type 6 #7 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5341	#02-5723	#03-5545	#04-5522	#05-5491	#06-5335	#07-5608	#08-5561	#09-5622	#10-5677
#11-5589	#12-5530	#13-5547	#14-5609	#15-5252	#16-5373	#17-5526	#18-5511	#19-5436	#20-5667
#21-5441	#22-5567	#23-5563	#24-5649	#25-5302	#26-5334	#27-5554	#28-5710	#29-5353	#30-5281
#31-5297	#32-5679	#33-5541	#34-5440	#35-5604	#36-5552	#37-5427	#38-5697	#39-5376	#40-5550
#41-5477	#42-5520	#43-5250	#44-5693	#45-5635	#46-5420	#47-5264	#48-5411	#49-5720	#50-5646
#51-5537	#52-5715	#53-5399	#54-5531	#55-5703	#56-5683	#57-5283	#58-5523	#59-5304	#60-5576
#61-5518	#62-5542	#63-5256	#64-5255	#65-5424	#66-5670	#67-5724	#68-5310	#69-5367	#70-5689
#71-5296	#72-5680	#73-5392	#74-5638	#75-5539	#76-5549	#77-5357	#78-5360	#79-5485	#80-5688
#81-5633	#82-5625	#83-5594	#84-5585	#85-5663	#86-5713	#87-5321	#88-5698	#89-5599	#90-5433
#91-5366	#92-5628	#93-5271	#94-5259	#95-5711	#96-5300	#97-5538	#98-5654	#99-5656	#100-5370

Type 6 #8 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5611	#02-5616	#03-5609	#04-5489	#05-5277	#06-5410	#07-5535	#08-5306	#09-5613	#10-5589
#11-5490	#12-5354	#13-5555	#14-5335	#15-5261	#16-5714	#17-5393	#18-5256	#19-5422	#20-5379
#21-5564	#22-5488	#23-5617	#24-5530	#25-5562	#26-5307	#27-5268	#28-5671	#29-5283	#30-5360
#31-5316	#32-5694	#33-5474	#34-5698	#35-5296	#36-5353	#37-5556	#38-5522	#39-5313	#40-5376
#41-5478	#42-5289	#43-5505	#44-5629	#45-5406	#46-5689	#47-5450	#48-5527	#49-5665	#50-5560
#51-5483	#52-5715	#53-5297	#54-5378	#55-5717	#56-5684	#57-5440	#58-5517	#59-5579	#60-5424
#61-5384	#62-5331	#63-5362	#64-5569	#65-5632	#66-5407	#67-5447	#68-5459	#69-5359	#70-5253
#71-5448	#72-5361	#73-5625	#74-5405	#75-5342	#76-5542	#77-5394	#78-5343	#79-5472	#80-5481
#81-5461	#82-5650	#83-5642	#84-5596	#85-5418	#86-5521	#87-5266	#88-5624	#89-5536	#90-5495
#91-5324	#92-5577	#93-5606	#94-5620	#95-5508	#96-5415	#97-5351	#98-5374	#99-5712	#100-5687

Type 6 #9 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5655	#02-5605	#03-5309	#04-5284	#05-5260	#06-5699	#07-5691	#08-5486	#09-5256	#10-5668
#11-5648	#12-5572	#13-5436	#14-5651	#15-5521	#16-5535	#17-5690	#18-5290	#19-5562	#20-5712
#21-5637	#22-5280	#23-5379	#24-5330	#25-5489	#26-5661	#27-5498	#28-5559	#29-5306	#30-5336
#31-5496	#32-5688	#33-5480	#34-5536	#35-5447	#36-5408	#37-5546	#38-5299	#39-5387	#40-5529
#41-5388	#42-5571	#43-5477	#44-5391	#45-5679	#46-5349	#47-5697	#48-5450	#49-5311	#50-5250
#51-5501	#52-5267	#53-5575	#54-5678	#55-5287	#56-5442	#57-5675	#58-5538	#59-5561	#60-5325
#61-5473	#62-5664	#63-5723	#64-5493	#65-5607	#66-5266	#67-5662	#68-5298	#69-5357	#70-5616
#71-5532	#72-5578	#73-5348	#74-5707	#75-5399	#76-5587	#77-5581	#78-5318	#79-5525	#80-5695
#81-5629	#82-5606	#83-5494	#84-5636	#85-5509	#86-5582	#87-5461	#88-5579	#89-5574	#90-5259
#91-5401	#92-5642	#93-5265	#94-5308	#95-5698	#96-5681	#97-5428	#98-5520	#99-5312	#100-5452

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Type 6 #10 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5634	#02-5683	#03-5372	#04-5349	#05-5397	#06-5305	#07-5292	#08-5314	#09-5344	#10-5469
#11-5286	#12-5554	#13-5694	#14-5385	#15-5366	#16-5724	#17-5695	#18-5481	#19-5329	#20-5562
#21-5503	#22-5523	#23-5426	#24-5430	#25-5692	#26-5341	#27-5613	#28-5624	#29-5614	#30-5254
#31-5433	#32-5708	#33-5310	#34-5671	#35-5484	#36-5394	#37-5489	#38-5454	#39-5539	#40-5396
#41-5485	#42-5354	#43-5698	#44-5572	#45-5606	#46-5296	#47-5647	#48-5582	#49-5682	#50-5458
#51-5288	#52-5707	#53-5615	#54-5381	#55-5641	#56-5574	#57-5337	#58-5676	#59-5444	#60-5579
#61-5281	#62-5370	#63-5302	#64-5633	#65-5439	#66-5456	#67-5277	#68-5515	#69-5415	#70-5268
#71-5662	#72-5549	#73-5645	#74-5418	#75-5666	#76-5406	#77-5691	#78-5450	#79-5342	#80-5653
#81-5279	#82-5635	#83-5471	#84-5521	#85-5588	#86-5290	#87-5499	#88-5452	#89-5553	#90-5387
#91-5700	#92-5352	#93-5252	#94-5260	#95-5442	#96-5363	#97-5703	#98-5274	#99-5318	#100-5392

Type 6 #11 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5417	#02-5507	#03-5395	#04-5502	#05-5423	#06-5315	#07-5644	#08-5684	#09-5704	#10-5409
#11-5696	#12-5358	#13-5659	#14-5636	#15-5651	#16-5444	#17-5702	#18-5412	#19-5607	#20-5376
#21-5721	#22-5508	#23-5685	#24-5305	#25-5564	#26-5403	#27-5680	#28-5258	#29-5617	#30-5540
#31-5300	#32-5611	#33-5402	#34-5378	#35-5674	#36-5330	#37-5550	#38-5512	#39-5326	#40-5601
#41-5533	#42-5593	#43-5407	#44-5298	#45-5253	#46-5719	#47-5318	#48-5349	#49-5516	#50-5255
#51-5385	#52-5541	#53-5391	#54-5667	#55-5396	#56-5633	#57-5547	#58-5339	#59-5663	#60-5269
#61-5359	#62-5317	#63-5414	#64-5334	#65-5530	#66-5687	#67-5571	#68-5619	#69-5439	#70-5336
#71-5256	#72-5568	#73-5377	#74-5350	#75-5301	#76-5569	#77-5335	#78-5581	#79-5466	#80-5405
#81-5484	#82-5470	#83-5460	#84-5707	#85-5290	#86-5574	#87-5306	#88-5491	#89-5622	#90-5525
#91-5718	#92-5664	#93-5289	#94-5387	#95-5670	#96-5361	#97-5455	#98-5348	#99-5268	#100-5532

Type 6 #12 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5636	#02-5287	#03-5344	#04-5658	#05-5503	#06-5419	#07-5431	#08-5258	#09-5599	#10-5589
#11-5469	#12-5548	#13-5646	#14-5313	#15-5408	#16-5590	#17-5279	#18-5489	#19-5670	#20-5577
#21-5357	#22-5696	#23-5382	#24-5530	#25-5443	#26-5521	#27-5500	#28-5459	#29-5335	#30-5361
#31-5688	#32-5482	#33-5596	#34-5423	#35-5479	#36-5373	#37-5713	#38-5453	#39-5709	#40-5315
#41-5304	#42-5544	#43-5689	#44-5465	#45-5606	#46-5677	#47-5330	#48-5426	#49-5620	#50-5403
#51-5416	#52-5425	#53-5664	#54-5629	#55-5538	#56-5360	#57-5309	#58-5622	#59-5655	#60-5524
#61-5569	#62-5504	#63-5584	#64-5414	#65-5441	#66-5710	#67-5631	#68-5467	#69-5372	#70-5630
#71-5328	#72-5703	#73-5639	#74-5379	#75-5578	#76-5439	#77-5683	#78-5522	#79-5307	#80-5656
#81-5518	#82-5666	#83-5262	#84-5653	#85-5555	#86-5435	#87-5470	#88-5437	#89-5354	#90-5301
#91-5415	#92-5691	#93-5694	#94-5519	#95-5369	#96-5660	#97-5302	#98-5284	#99-5551	#100-5552

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5501	#02-5330	#03-5707	#04-5357	#05-5395	#06-5716	#07-5315	#08-5398	#09-5312	#10-5356
#11-5509	#12-5442	#13-5419	#14-5618	#15-5571	#16-5636	#17-5318	#18-5662	#19-5409	#20-5528
#21-5523	#22-5479	#23-5652	#24-5474	#25-5581	#26-5308	#27-5319	#28-5273	#29-5588	#30-5254
#31-5622	#32-5691	#33-5363	#34-5486	#35-5573	#36-5572	#37-5306	#38-5289	#39-5478	#40-5459
#41-5288	#42-5292	#43-5669	#44-5630	#45-5499	#46-5525	#47-5626	#48-5522	#49-5590	#50-5364
#51-5599	#52-5278	#53-5272	#54-5403	#55-5483	#56-5500	#57-5710	#58-5658	#59-5720	#60-5375
#61-5448	#62-5351	#63-5612	#64-5475	#65-5305	#66-5381	#67-5723	#68-5314	#69-5261	#70-5655
#71-5485	#72-5436	#73-5708	#74-5568	#75-5332	#76-5609	#77-5406	#78-5521	#79-5724	#80-5614
#81-5667	#82-5334	#83-5464	#84-5339	#85-5531	#86-5304	#87-5545	#88-5637	#89-5569	#90-5567
#91-5268	#92-5469	#93-5494	#94-5524	#95-5684	#96-5578	#97-5467	#98-5668	#99-5680	#100-5518

Type 6 #14 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5560	#02-5420	#03-5639	#04-5418	#05-5351	#06-5502	#07-5449	#08-5375	#09-5461	#10-5588
#11-5532	#12-5696	#13-5642	#14-5554	#15-5700	#16-5455	#17-5568	#18-5360	#19-5579	#20-5572
#21-5591	#22-5390	#23-5550	#24-5308	#25-5636	#26-5722	#27-5290	#28-5395	#29-5397	#30-5329
#31-5712	#32-5541	#33-5628	#34-5724	#35-5424	#36-5362	#37-5678	#38-5292	#39-5264	#40-5511
#41-5369	#42-5355	#43-5404	#44-5465	#45-5497	#46-5577	#47-5694	#48-5709	#49-5372	#50-5623
#51-5557	#52-5350	#53-5670	#54-5693	#55-5279	#56-5339	#57-5685	#58-5590	#59-5451	#60-5335
#61-5304	#62-5314	#63-5509	#64-5545	#65-5405	#66-5263	#67-5525	#68-5343	#69-5615	#70-5318
#71-5564	#72-5310	#73-5472	#74-5284	#75-5567	#76-5617	#77-5309	#78-5277	#79-5305	#80-5272
#81-5498	#82-5611	#83-5595	#84-5659	#85-5334	#86-5252	#87-5717	#88-5426	#89-5538	#90-5291
#91-5620	#92-5645	#93-5342	#94-5563	#95-5433	#96-5258	#97-5489	#98-5609	#99-5471	#100-5719

Type 6 #15 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5668	#02-5517	#03-5318	#04-5531	#05-5423	#06-5280	#07-5282	#08-5540	#09-5261	#10-5658
#11-5535	#12-5329	#13-5585	#14-5441	#15-5340	#16-5622	#17-5616	#18-5275	#19-5609	#20-5407
#21-5718	#22-5500	#23-5646	#24-5525	#25-5471	#26-5612	#27-5597	#28-5717	#29-5490	#30-5257
#31-5350	#32-5710	#33-5438	#34-5699	#35-5390	#36-5460	#37-5649	#38-5620	#39-5364	#40-5395
#41-5476	#42-5608	#43-5712	#44-5532	#45-5484	#46-5529	#47-5664	#48-5360	#49-5485	#50-5724
#51-5313	#52-5251	#53-5418	#54-5595	#55-5310	#56-5289	#57-5300	#58-5253	#59-5557	#60-5549
#61-5615	#62-5610	#63-5605	#64-5698	#65-5721	#66-5636	#67-5464	#68-5375	#69-5492	#70-5659
#71-5711	#72-5332	#73-5604	#74-5303	#75-5379	#76-5385	#77-5589	#78-5374	#79-5697	#80-5381
#81-5560	#82-5554	#83-5426	#84-5404	#85-5707	#86-5593	#87-5644	#88-5667	#89-5308	#90-5386
#91-5601	#92-5574	#93-5510	#94-5663	#95-5483	#96-5527	#97-5660	#98-5524	#99-5323	#100-5452

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5528	#02-5711	#03-5645	#04-5593	#05-5692	#06-5563	#07-5491	#08-5637	#09-5328	#10-5265
#11-5567	#12-5410	#13-5331	#14-5476	#15-5382	#16-5316	#17-5261	#18-5505	#19-5260	#20-5367
#21-5413	#22-5662	#23-5719	#24-5717	#25-5508	#26-5450	#27-5435	#28-5464	#29-5419	#30-5653
#31-5582	#32-5486	#33-5351	#34-5434	#35-5256	#36-5436	#37-5394	#38-5352	#39-5257	#40-5589
#41-5293	#42-5544	#43-5440	#44-5492	#45-5284	#46-5531	#47-5417	#48-5515	#49-5405	#50-5513
#51-5680	#52-5289	#53-5591	#54-5716	#55-5652	#56-5335	#57-5677	#58-5362	#59-5305	#60-5422
#61-5633	#62-5336	#63-5710	#64-5649	#65-5705	#66-5291	#67-5375	#68-5535	#69-5724	#70-5318
#71-5590	#72-5406	#73-5323	#74-5676	#75-5423	#76-5317	#77-5498	#78-5416	#79-5629	#80-5296
#81-5628	#82-5497	#83-5311	#84-5568	#85-5264	#86-5578	#87-5651	#88-5484	#89-5281	#90-5297
#91-5559	#92-5681	#93-5558	#94-5516	#95-5511	#96-5607	#97-5337	#98-5647	#99-5665	#100-5608

Type 6 #17 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5518	#02-5290	#03-5478	#04-5267	#05-5429	#06-5671	#07-5401	#08-5376	#09-5254	#10-5564
#11-5642	#12-5368	#13-5644	#14-5448	#15-5361	#16-5682	#17-5323	#18-5559	#19-5692	#20-5571
#21-5367	#22-5720	#23-5589	#24-5525	#25-5711	#26-5423	#27-5473	#28-5414	#29-5362	#30-5410
#31-5395	#32-5590	#33-5428	#34-5300	#35-5699	#36-5349	#37-5633	#38-5304	#39-5335	#40-5620
#41-5433	#42-5676	#43-5641	#44-5398	#45-5592	#46-5519	#47-5294	#48-5649	#49-5442	#50-5503
#51-5338	#52-5697	#53-5286	#54-5400	#55-5614	#56-5467	#57-5498	#58-5652	#59-5686	#60-5616
#61-5403	#62-5496	#63-5502	#64-5465	#65-5386	#66-5582	#67-5415	#68-5504	#69-5321	#70-5388
#71-5603	#72-5672	#73-5369	#74-5628	#75-5489	#76-5645	#77-5632	#78-5306	#79-5618	#80-5391
#81-5624	#82-5655	#83-5460	#84-5416	#85-5587	#86-5561	#87-5693	#88-5472	#89-5309	#90-5688
#91-5621	#92-5371	#93-5317	#94-5277	#95-5723	#96-5625	#97-5623	#98-5710	#99-5666	#100-5340

Type 6 #18 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5323	#02-5594	#03-5473	#04-5446	#05-5696	#06-5496	#07-5439	#08-5609	#09-5324	#10-5499
#11-5456	#12-5372	#13-5723	#14-5642	#15-5636	#16-5353	#17-5641	#18-5356	#19-5639	#20-5527
#21-5480	#22-5718	#23-5507	#24-5521	#25-5422	#26-5617	#27-5633	#28-5441	#29-5717	#30-5493
#31-5488	#32-5519	#33-5326	#34-5513	#35-5691	#36-5469	#37-5275	#38-5338	#39-5680	#40-5261
#41-5302	#42-5597	#43-5426	#44-5669	#45-5278	#46-5331	#47-5678	#48-5706	#49-5603	#50-5501
#51-5389	#52-5584	#53-5330	#54-5337	#55-5677	#56-5273	#57-5328	#58-5588	#59-5722	#60-5616
#61-5555	#62-5585	#63-5692	#64-5578	#65-5647	#66-5378	#67-5615	#68-5267	#69-5448	#70-5571
#71-5665	#72-5635	#73-5344	#74-5477	#75-5589	#76-5551	#77-5445	#78-5511	#79-5285	#80-5712
#81-5380	#82-5466	#83-5433	#84-5604	#85-5516	#86-5252	#87-5259	#88-5683	#89-5370	#90-5471
#91-5262	#92-5458	#93-5341	#94-5355	#95-5258	#96-5637	#97-5586	#98-5303	#99-5542	#100-5365

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Type 6 #19 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5389	#02-5427	#03-5582	#04-5520	#05-5464	#06-5286	#07-5483	#08-5420	#09-5293	#10-5549
#11-5705	#12-5448	#13-5431	#14-5670	#15-5315	#16-5343	#17-5613	#18-5258	#19-5594	#20-5349
#21-5443	#22-5622	#23-5611	#24-5385	#25-5598	#26-5480	#27-5533	#28-5423	#29-5659	#30-5562
#31-5351	#32-5426	#33-5658	#34-5456	#35-5541	#36-5449	#37-5674	#38-5428	#39-5437	#40-5478
#41-5618	#42-5649	#43-5257	#44-5667	#45-5543	#46-5452	#47-5578	#48-5433	#49-5654	#50-5266
#51-5529	#52-5696	#53-5413	#54-5253	#55-5597	#56-5376	#57-5295	#58-5610	#59-5329	#60-5626
#61-5409	#62-5407	#63-5462	#64-5302	#65-5414	#66-5399	#67-5265	#68-5435	#69-5382	#70-5492
#71-5559	#72-5590	#73-5538	#74-5715	#75-5692	#76-5570	#77-5475	#78-5633	#79-5334	#80-5347
#81-5687	#82-5320	#83-5540	#84-5378	#85-5445	#86-5312	#87-5555	#88-5311	#89-5432	#90-5569
#91-5355	#92-5303	#93-5384	#94-5365	#95-5380	#96-5489	#97-5591	#98-5655	#99-5563	#100-5395

Type 6 #20 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5547	#02-5440	#03-5621	#04-5630	#05-5530	#06-5544	#07-5701	#08-5719	#09-5529	#10-5716
#11-5447	#12-5336	#13-5646	#14-5649	#15-5693	#16-5337	#17-5434	#18-5374	#19-5674	#20-5483
#21-5714	#22-5485	#23-5484	#24-5581	#25-5455	#26-5344	#27-5393	#28-5468	#29-5417	#30-5528
#31-5373	#32-5427	#33-5394	#34-5555	#35-5255	#36-5415	#37-5650	#38-5505	#39-5613	#40-5281
#41-5574	#42-5551	#43-5312	#44-5661	#45-5684	#46-5444	#47-5521	#48-5503	#49-5470	#50-5384
#51-5405	#52-5680	#53-5290	#54-5708	#55-5325	#56-5449	#57-5558	#58-5501	#59-5361	#60-5437
#61-5323	#62-5633	#63-5687	#64-5647	#65-5508	#66-5593	#67-5311	#68-5452	#69-5390	#70-5658
#71-5422	#72-5644	#73-5260	#74-5614	#75-5597	#76-5689	#77-5671	#78-5559	#79-5293	#80-5492
#81-5300	#82-5667	#83-5430	#84-5413	#85-5448	#86-5439	#87-5599	#88-5588	#89-5350	#90-5657
#91-5265	#92-5379	#93-5507	#94-5371	#95-5270	#96-5314	#97-5560	#98-5686	#99-5536	#100-5414

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5602	#02-5563	#03-5590	#04-5512	#05-5577	#06-5636	#07-5522	#08-5565	#09-5412	#10-5623
#11-5254	#12-5316	#13-5468	#14-5548	#15-5306	#16-5318	#17-5502	#18-5288	#19-5357	#20-5709
#21-5459	#22-5658	#23-5361	#24-5698	#25-5363	#26-5517	#27-5253	#28-5647	#29-5366	#30-5487
#31-5511	#32-5275	#33-5721	#34-5274	#35-5435	#36-5404	#37-5508	#38-5309	#39-5371	#40-5662
#41-5653	#42-5673	#43-5635	#44-5684	#45-5315	#46-5358	#47-5720	#48-5307	#49-5648	#50-5428
#51-5430	#52-5393	#53-5630	#54-5478	#55-5539	#56-5464	#57-5369	#58-5518	#59-5643	#60-5296
#61-5492	#62-5530	#63-5443	#64-5551	#65-5281	#66-5451	#67-5639	#68-5719	#69-5365	#70-5298
#71-5587	#72-5433	#73-5452	#74-5558	#75-5663	#76-5538	#77-5519	#78-5564	#79-5332	#80-5569
#81-5368	#82-5681	#83-5294	#84-5528	#85-5515	#86-5615	#87-5607	#88-5410	#89-5441	#90-5382
#91-5283	#92-5632	#93-5331	#94-5313	#95-5532	#96-5380	#97-5568	#98-5596	#99-5625	#100-5295

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5514	#02-5261	#03-5535	#04-5580	#05-5355	#06-5650	#07-5501	#08-5652	#09-5447	#10-5599
#11-5698	#12-5637	#13-5494	#14-5298	#15-5674	#16-5562	#17-5507	#18-5384	#19-5631	#20-5372
#21-5272	#22-5606	#23-5260	#24-5425	#25-5629	#26-5289	#27-5455	#28-5281	#29-5676	#30-5251
#31-5706	#32-5467	#33-5636	#34-5326	#35-5283	#36-5717	#37-5659	#38-5347	#39-5690	#40-5483
#41-5670	#42-5567	#43-5409	#44-5370	#45-5387	#46-5282	#47-5364	#48-5695	#49-5597	#50-5433
#51-5689	#52-5503	#53-5273	#54-5632	#55-5250	#56-5360	#57-5449	#58-5610	#59-5295	#60-5621
#61-5496	#62-5716	#63-5419	#64-5582	#65-5697	#66-5641	#67-5569	#68-5573	#69-5287	#70-5665
#71-5266	#72-5661	#73-5418	#74-5508	#75-5493	#76-5257	#77-5341	#78-5311	#79-5329	#80-5543
#81-5267	#82-5613	#83-5708	#84-5623	#85-5330	#86-5310	#87-5586	#88-5424	#89-5694	#90-5417
#91-5530	#92-5309	#93-5448	#94-5375	#95-5274	#96-5395	#97-5487	#98-5557	#99-5344	#100-5681

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5602	#02-5679	#03-5559	#04-5416	#05-5304	#06-5699	#07-5455	#08-5694	#09-5528	#10-5607
#11-5687	#12-5590	#13-5389	#14-5585	#15-5681	#16-5652	#17-5487	#18-5448	#19-5574	#20-5557
#21-5688	#22-5672	#23-5618	#24-5661	#25-5397	#26-5717	#27-5451	#28-5379	#29-5447	#30-5512
#31-5539	#32-5666	#33-5452	#34-5355	#35-5276	#36-5257	#37-5639	#38-5442	#39-5470	#40-5560
#41-5505	#42-5565	#43-5412	#44-5409	#45-5255	#46-5413	#47-5531	#48-5556	#49-5458	#50-5358
#51-5494	#52-5718	#53-5655	#54-5310	#55-5623	#56-5362	#57-5632	#58-5707	#59-5253	#60-5331
#61-5406	#62-5425	#63-5300	#64-5382	#65-5575	#66-5625	#67-5480	#68-5533	#69-5336	#70-5377
#71-5302	#72-5498	#73-5620	#74-5391	#75-5553	#76-5645	#77-5547	#78-5714	#79-5342	#80-5267
#81-5673	#82-5522	#83-5294	#84-5378	#85-5460	#86-5467	#87-5719	#88-5424	#89-5408	#90-5712
#91-5281	#92-5680	#93-5703	#94-5549	#95-5499	#96-5488	#97-5258	#98-5374	#99-5466	#100-5490

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5403	#02-5332	#03-5267	#04-5341	#05-5314	#06-5407	#07-5346	#08-5498	#09-5584	#10-5530
#11-5497	#12-5585	#13-5525	#14-5647	#15-5594	#16-5383	#17-5717	#18-5619	#19-5511	#20-5583
#21-5522	#22-5690	#23-5617	#24-5261	#25-5517	#26-5629	#27-5429	#28-5333	#29-5284	#30-5286
#31-5253	#32-5492	#33-5307	#34-5384	#35-5701	#36-5344	#37-5554	#38-5262	#39-5421	#40-5400
#41-5367	#42-5274	#43-5440	#44-5630	#45-5456	#46-5496	#47-5363	#48-5587	#49-5680	#50-5631
#51-5605	#52-5375	#53-5330	#54-5521	#55-5502	#56-5641	#57-5415	#58-5550	#59-5493	#60-5432
#61-5282	#62-5589	#63-5459	#64-5406	#65-5634	#66-5524	#67-5682	#68-5549	#69-5350	#70-5540
#71-5618	#72-5438	#73-5601	#74-5512	#75-5648	#76-5390	#77-5447	#78-5586	#79-5426	#80-5576
#81-5252	#82-5547	#83-5302	#84-5345	#85-5593	#86-5595	#87-5638	#88-5660	#89-5716	#90-5575
#91-5420	#92-5300	#93-5563	#94-5431	#95-5331	#96-5504	#97-5552	#98-5640	#99-5436	#100-5278

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5313	#02-5367	#03-5538	#04-5288	#05-5570	#06-5353	#07-5709	#08-5421	#09-5413	#10-5442
#11-5555	#12-5631	#13-5702	#14-5630	#15-5403	#16-5680	#17-5480	#18-5633	#19-5545	#20-5682
#21-5501	#22-5588	#23-5551	#24-5650	#25-5334	#26-5485	#27-5266	#28-5504	#29-5646	#30-5440
#31-5660	#32-5541	#33-5519	#34-5713	#35-5703	#36-5305	#37-5557	#38-5311	#39-5535	#40-5676
#41-5544	#42-5412	#43-5470	#44-5586	#45-5250	#46-5278	#47-5375	#48-5274	#49-5643	#50-5345
#51-5478	#52-5450	#53-5264	#54-5711	#55-5362	#56-5593	#57-5692	#58-5641	#59-5491	#60-5252
#61-5619	#62-5340	#63-5432	#64-5424	#65-5625	#66-5648	#67-5572	#68-5259	#69-5256	#70-5425
#71-5331	#72-5694	#73-5472	#74-5484	#75-5379	#76-5622	#77-5522	#78-5565	#79-5312	#80-5268
#81-5512	#82-5689	#83-5319	#84-5444	#85-5550	#86-5667	#87-5708	#88-5628	#89-5645	#90-5700
#91-5575	#92-5590	#93-5333	#94-5578	#95-5475	#96-5351	#97-5320	#98-5335	#99-5275	#100-5613

Type 6 #26 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5629	#02-5393	#03-5263	#04-5358	#05-5704	#06-5512	#07-5594	#08-5455	#09-5304	#10-5278
#11-5414	#12-5378	#13-5460	#14-5555	#15-5453	#16-5272	#17-5317	#18-5303	#19-5504	#20-5399
#21-5480	#22-5353	#23-5318	#24-5400	#25-5384	#26-5628	#27-5521	#28-5451	#29-5479	#30-5564
#31-5448	#32-5487	#33-5325	#34-5300	#35-5537	#36-5558	#37-5254	#38-5366	#39-5301	#40-5495
#41-5562	#42-5714	#43-5679	#44-5367	#45-5644	#46-5622	#47-5297	#48-5267	#49-5450	#50-5490
#51-5464	#52-5398	#53-5289	#54-5669	#55-5683	#56-5570	#57-5608	#58-5322	#59-5253	#60-5549
#61-5439	#62-5690	#63-5616	#64-5385	#65-5391	#66-5403	#67-5483	#68-5662	#69-5452	#70-5684
#71-5516	#72-5329	#73-5445	#74-5266	#75-5708	#76-5624	#77-5462	#78-5363	#79-5717	#80-5586
#81-5265	#82-5260	#83-5592	#84-5600	#85-5409	#86-5482	#87-5492	#88-5697	#89-5373	#90-5273
#91-5313	#92-5707	#93-5503	#94-5468	#95-5509	#96-5433	#97-5553	#98-5292	#99-5560	#100-5498

Type 6 #27 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5589	#02-5487	#03-5553	#04-5625	#05-5423	#06-5574	#07-5337	#08-5325	#09-5257	#10-5624
#11-5523	#12-5376	#13-5392	#14-5592	#15-5608	#16-5583	#17-5430	#18-5473	#19-5386	#20-5711
#21-5393	#22-5305	#23-5381	#24-5283	#25-5455	#26-5405	#27-5566	#28-5677	#29-5655	#30-5380
#31-5674	#32-5276	#33-5550	#34-5253	#35-5362	#36-5580	#37-5582	#38-5530	#39-5642	#40-5610
#41-5297	#42-5266	#43-5414	#44-5434	#45-5377	#46-5326	#47-5694	#48-5372	#49-5543	#50-5452
#51-5355	#52-5533	#53-5356	#54-5520	#55-5419	#56-5268	#57-5258	#58-5384	#59-5395	#60-5602
#61-5497	#62-5630	#63-5496	#64-5573	#65-5668	#66-5469	#67-5351	#68-5345	#69-5289	#70-5692
#71-5327	#72-5328	#73-5597	#74-5302	#75-5330	#76-5577	#77-5347	#78-5444	#79-5256	#80-5310
#81-5412	#82-5511	#83-5634	#84-5476	#85-5626	#86-5389	#87-5464	#88-5661	#89-5551	#90-5421
#91-5378	#92-5571	#93-5524	#94-5600	#95-5679	#96-5259	#97-5493	#98-5388	#99-5671	#100-5342

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This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5664	#02-5385	#03-5331	#04-5314	#05-5594	#06-5544	#07-5645	#08-5452	#09-5498	#10-5394
#11-5490	#12-5668	#13-5411	#14-5406	#15-5560	#16-5600	#17-5443	#18-5625	#19-5477	#20-5637
#21-5501	#22-5632	#23-5492	#24-5648	#25-5484	#26-5458	#27-5504	#28-5622	#29-5720	#30-5372
#31-5676	#32-5592	#33-5364	#34-5320	#35-5571	#36-5562	#37-5519	#38-5266	#39-5348	#40-5647
#41-5685	#42-5613	#43-5628	#44-5362	#45-5444	#46-5369	#47-5476	#48-5541	#49-5593	#50-5635
#51-5283	#52-5565	#53-5282	#54-5618	#55-5407	#56-5555	#57-5386	#58-5289	#59-5272	#60-5456
#61-5376	#62-5553	#63-5341	#64-5559	#65-5311	#66-5455	#67-5606	#68-5356	#69-5557	#70-5620
#71-5402	#72-5709	#73-5531	#74-5285	#75-5581	#76-5345	#77-5310	#78-5503	#79-5494	#80-5556
#81-5333	#82-5682	#83-5330	#84-5479	#85-5539	#86-5605	#87-5711	#88-5256	#89-5383	#90-5719
#91-5617	#92-5521	#93-5715	#94-5324	#95-5271	#96-5609	#97-5307	#98-5659	#99-5486	#100-5327

Type 6 #29 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5388	#02-5413	#03-5297	#04-5336	#05-5372	#06-5699	#07-5290	#08-5704	#09-5493	#10-5687
#11-5545	#12-5359	#13-5665	#14-5473	#15-5587	#16-5269	#17-5431	#18-5468	#19-5600	#20-5698
#21-5676	#22-5626	#23-5510	#24-5438	#25-5288	#26-5295	#27-5506	#28-5323	#29-5425	#30-5446
#31-5621	#32-5571	#33-5604	#34-5667	#35-5315	#36-5492	#37-5518	#38-5589	#39-5282	#40-5342
#41-5475	#42-5654	#43-5700	#44-5383	#45-5299	#46-5575	#47-5409	#48-5590	#49-5601	#50-5527
#51-5309	#52-5513	#53-5376	#54-5486	#55-5628	#56-5583	#57-5298	#58-5326	#59-5442	#60-5691
#61-5528	#62-5464	#63-5648	#64-5311	#65-5531	#66-5521	#67-5502	#68-5638	#69-5603	#70-5567
#71-5605	#72-5300	#73-5400	#74-5580	#75-5462	#76-5630	#77-5721	#78-5656	#79-5639	#80-5560
#81-5569	#82-5670	#83-5562	#84-5307	#85-5478	#86-5430	#87-5412	#88-5633	#89-5469	#90-5512
#91-5564	#92-5375	#93-5348	#94-5428	#95-5439	#96-5302	#97-5594	#98-5712	#99-5294	#100-5613

Type 6 #30 [Back to Summary]

This table contains a list of 100 hop frequencies, randomly selected from 5250-5724MHz in 1MHz steps

#01-5337	#02-5688	#03-5648	#04-5466	#05-5632	#06-5325	#07-5336	#08-5297	#09-5370	#10-5393
#11-5330	#12-5511	#13-5302	#14-5693	#15-5452	#16-5519	#17-5455	#18-5558	#19-5350	#20-5359
#21-5594	#22-5418	#23-5341	#24-5252	#25-5479	#26-5676	#27-5697	#28-5390	#29-5410	#30-5285
#31-5258	#32-5611	#33-5276	#34-5473	#35-5606	#36-5271	#37-5345	#38-5399	#39-5402	#40-5344
#41-5364	#42-5512	#43-5326	#44-5431	#45-5303	#46-5323	#47-5380	#48-5700	#49-5645	#50-5690
#51-5389	#52-5403	#53-5669	#54-5503	#55-5467	#56-5520	#57-5557	#58-5463	#59-5373	#60-5685
#61-5357	#62-5322	#63-5625	#64-5469	#65-5571	#66-5497	#67-5715	#68-5305	#69-5406	#70-5256
#71-5720	#72-5332	#73-5634	#74-5674	#75-5546	#76-5721	#77-5444	#78-5621	#79-5579	#80-5667
#81-5255	#82-5439	#83-5607	#84-5278	#85-5705	#86-5457	#87-5552	#88-5694	#89-5296	#90-5635
#91-5378	#92-5398	#93-5334	#94-5722	#95-5663	#96-5508	#97-5385	#98-5428	#99-5514	#100-5551

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